

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
2				*****
3	*			
4	*			Zvector E6 instruction tests for VRI-i encoded:
5	*			
6	*			E658 VCVD - VECTOR CONVERT TO DECIMAL (32)
7	*			E65A VCVDG - VECTOR CONVERT TO DECIMAL (64)
8	*			
9	*			James Wekel June 2024
10				*****
11				
12				*****
13	*			
14	*			basic instruction tests
15	*			
16				*****
17	*			This program tests proper functioning of the z/arch E6 VRI-i vector
18	*			convert to decimal. Exceptions are not tested.
19	*			
20	*			PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
21	*			obvious coding errors. None of the tests are thorough. They are
22	*			NOT designed to test all aspects of any of the instructions.
23	*			
24				*****
25	*			
26	*	*	*	*Testcase zvector-e6-13-converttodecimal: VECTOR E6 VRI-i instruction
27	*	*	*	
28	*	*	*	Zvector E6 tests for VRI-i encoded instruction:
29	*	*	*	
30	*	*	*	E658 VCVD - VECTOR CONVERT TO DECIMAL (32)
31	*	*	*	E65A VCVDG - VECTOR CONVERT TO DECIMAL (64)
32	*	*	*	
33	*	*	*	# -----
34	*	*	*	# This tests only the basic function of the instruction.
35	*	*	*	# Exceptions are NOT tested.
36	*	*	*	# -----
37	*	*	*	
38	*	mainsize	2	
39	*	numcpu	1	
40	*	sysclear		
41	*	archl vl		z/Arch
42	*			
43	*	diag8cmd	enable	# (needed for messages to Hercules console)
44	*	loadcore	"\$(testpath)/zvector-e6-13-converttodecimal.core"	0x0
45	*	diag8cmd	disable	# (reset back to default)
46	*			
47	*	*	Done	
48	*			
49				*****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				51 **** 52 * FCHECK Macro - Is a Facility Bit set? 53 * 54 * If the facility bit is NOT set, an message is issued and 55 * the test is skipped. 56 * 57 * Fcheck uses R0, R1 and R2 58 * 59 * eg. FCHECK 134, 'vector-packed-decimal' 60 **** 61 MACRO 62 FCHECK &BITNO, &NOTSETMSG 63 . * &BITNO : facility bit number to check 64 . * &NOTSETMSG : 'facility name' 65 LCLA &FBBYTE Facility bit in Byte 66 LCLA &FBBIT Facility bit within Byte 67 68 LCLA &L(8) 69 &L(1) SetA 128, 64, 32, 16, 8, 4, 2, 1 bit positions within byte 70 71 &FBBYTE SETA &BITNO/8 72 &FBBIT SETA &L((&BITNO-(&FBBYTE*8))+1) 73 . * MN0TE 0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT' 74 75 B X&SYSNDX 76 * 77 * Fcheck data area 78 SKT&SYSNDX DC C' skipping tests: 79 DC C&NOTSETMSG 80 DC C' facility (bit &BITNO) is not installed.' 81 SKL&SYSNDX EQU *- SKT&SYSNDX 82 * facility bits 83 DS FD gap 84 FB&SYSNDX DS 4FD gap 85 DS FD gap 86 * 87 X&SYSNDX EQU * 88 LA R0, ((X&SYSNDX- FB&SYSNDX)/8)-1 89 STFLE FB&SYSNDX get facility bits 90 91 XGR R0, R0 92 IC R0, FB&SYSNDX+&FBBYTE get fbit byte 93 N R0, =F' &FBBIT' is bit set? 94 BNZ XC&SYSNDX 95 * 96 * facility bit not set, issue message and exit 97 * 98 LA R0, SKL&SYSNDX message length 99 LA R1, SKT&SYSNDX message address 100 BAL R2, MSG 101 102 B EOJ 103 XC&SYSNDX EQU * 104 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				126 **** 127 * The actual "ZVE6TST" program itself... 128 **** 129 * 130 * Architecture Mode: z/Arch 131 * Register Usage: 132 * 133 * R0 (work) 134 * R1-4 (work) 135 * R5 Testing control table - current test base 136 * R6-R7 (work) 137 * R8 First base register 138 * R9 Second base register 139 * R10 Third base register 140 * R11 E6TEST call return 141 * R12 E6TESTS register 142 * R13 (work) 143 * R14 Subroutine call 144 * R15 Secondary Subroutine call or work 145 * 146 ****
00000200		00000200		148 USING BEGIN, R8 FIRST Base Register
00000200		00001200		149 USING BEGIN+4096, R9 SECOND Base Register
00000200		00002200		150 USING BEGIN+8192, R10 THIRD Base Register
00000200	0580			151 152 BEGIN BALR R8, 0 Initialize FIRST base register
00000202	0680			153 BCTR R8, 0 Initialize FIRST base register
00000204	0680			154 BCTR R8, 0 Initialize FIRST base register
00000206	4190 8800		00000800	155 156 LA R9, 2048(, R8) Initialize SECOND base register
0000020A	4190 9800		00000800	157 LA R9, 2048(, R9) Initialize SECOND base register
0000020E	41A0 9800		00000800	158 159 LA R10, 2048(, R9) Initialize THIRD base register
00000212	41A0 A800		00000800	160 LA R10, 2048(, R10) Initialize THIRD base register
00000216	B600 834C		0000054C	161 162 STCTL R0, R0, CTLR0 Store CRO to enable AFP
0000021A	9604 834D		0000054D	163 OI CTLR0+1, X' 04' Turn on AFP bit
0000021E	9602 834D		0000054D	164 OI CTLR0+1, X' 02' Turn on Vector bit
00000222	B700 834C		0000054C	165 LCTL R0, R0, CTLR0 Reload updated CRO
				166 167 ****
				168 * Is Vector packed-decimal facility installed (bit 134) 169 ****
				170 171 FCHECK 134, 'vector-packed-decimal'
00000226	47F0 80B0		000002B0	172+ B X0001 Fcheck data area 173+* skip message
0000022A	40404040 40404040			174+* 175+SKT0001 DC C' Skipping tests: '
00000244	A58583A3 96996097			176+ DC C' vector-packed-decimal'
00000259	40868183 899389A3	00000054	00000001	177+ DC C' facility (bit 134) is not installed. 178+SKL0001 EQU -* SKT0001
00000280	00000000 00000000			179+* facility bits 00000288 00000000 00000000 180+ DS FD gap 181+FB0001 DS 4FD

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000002A8	00000000 00000000			182+ 183+*	DS	FD	gap
000002B0	4100 0004	000002B0	00000001	184+X0001	EQU *		
000002B4	B2B0 8088		00000004	185+	LA	R0, ((X0001-FB0001)/8)-1	
000002B8	B982 0000		00000288	186+	STFLE	FB0001	get facility bits
000002BC	4300 8098			187+	XGR	RO, RO	
000002C0	5400 8354		00000298	188+	IC	RO, FB0001+16	get fbit byte
000002C4	4770 80D8		00000554	189+	N	RO, =F' 2'	is bit set?
			000002D8	190+	BNZ	XC0001	
				191+*			
				192+*	facility bit not set, issue message and exit		
				193+*			
000002C8	4100 0054		00000054	194+	LA	RO, SKL0001	message length
000002CC	4110 802A		0000022A	195+	LA	R1, SKT0001	message address
000002D0	4520 8268		00000468	196+	BAL	R2, MSG	
000002D4	47F0 8330		00000530	197+	B	EOJ	
		000002D8	00000001	198+XC0001	EQU *		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				200 ****	*****	*****	*****
				201 *	Do tests in the E6TESTS table		
				202 *****	*****	*****	*****
000002D8	58C0 8358		00000558	204 L R12, =A(E6TESTS)	get table of test addresses		
				205			
000002DC	5850 C000	000002DC	00000001	206 NEXTE6 EQU *	get test address		
000002E0	1255		00000000	207 L R5, 0(0, R12)	have a test?		
000002E2	4780 8222		00000422	208 LTR R5, R5			
				209 BZ ENDTEST	done?		
000002E6	B982 0000			210			
				211 XGR R0, R0	no cc error		
000002EA		00000000		212			
				213 USING E6TEST, R5			
000002EA	58B0 5000		00000000	214			
000002EE	05BB			215 L R11, TSUB	get address of test routine		
000002F0	E310 500A 0076		0000000A	216 BALR R11, R11	do test		
000002F6	8910 0004		00000004	217			
000002FA	4410 8116		00000316	218 LB R1, CCMASK	(failure CC mask)		
				219 SLL R1, 4	(shift to BC instr CC position)		
				220 EX R1, TESTCC	fail if...		
		000002FE	00000001	221			
000002FE	E310 5018 0014	00000018		222 TESTREST EQU *			
00000304	D50F 8F10 1000	00001110	00000000	223 LGF R1, READDR	get address of expected result		
0000030A	4770 81AA		000003AA	224 CLC V10OUTPUT, 0(R1)	valid?		
				225 BNE FAILMSG	no, issue failed message		
0000030E	41C0 C004		00000004	226			
00000312	47F0 80DC		000002DC	227 LA R12, 4(0, R12)	next test address		
00000316	4700 811A		0000031A	228 B NEXTE6			
				229			
				230 TESTCC BC 0, CCMMSG	(fail if unexpected condition code)		
				231			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				233 ****	*****
				234 * cc was not as expected	*****
				235 *****	*****
0000031A	E310 0001 0082	0000031A	00000001	236 CCMMSG EQU *	
00000320	E310 5008 0076		00000001	237 XG R1, R1	
00000326	5410 835C		00000008	238 LB R1, M4	m3 has CS bit
0000032A	4780 80FE		0000055C	239 N R1, =F' 1'	get CS (CC set) bit
			000002FE	240 BZ TESTREST	ignore if not set
				241 *	
				242 * extract CC extracted PSW	
				243 *	
0000032E	5810 8EE8		000010E8	244 L R1, CCPSW	
00000332	8810 000C		0000000C	245 SRL R1, 12	
00000336	5410 8360		00000560	246 N R1, =XL4' 3'	
0000033A	4210 8EF0		000010F0	247 STC R1, CCFOUND	save cc
				248 *	
				249 * FILL IN MESSAGE	
				250 *	
0000033E	4820 5004		00000004	251 LH R2, TNUM	get test number and convert
00000342	4E20 8ED5		000010D5	252 CVD R2, DECNUM	
00000346	D211 8EBF 8EA9	000010BF	000010A9	253 MVC PRT3, EDIT	
0000034C	DE11 8EBF 8ED5	000010BF	000010D5	254 ED PRT3, DECNUM	
00000352	D202 8E64 8ECC	00001064	000010CC	255 MVC CCPRTNUM(3), PRT3+13	fill in message with test #
00000358	D207 8E81 500B	00001081	0000000B	256 MVC CCPRTNAME, OPNAME	fill in message with instruction
0000035E	B982 0022		257		
00000362	4320 5009		00000009	258 XGR R2, R2	get CC as U8
00000366	4E20 8ED5		000010D5	259 IC R2, CC	
0000036A	D211 8EBF 8EA9	000010BF	000010A9	260 CVD R2, DECNUM	and convert
00000370	DE11 8EBF 8ED5	000010BF	000010D5	261 MVC PRT3, EDIT	
00000376	D200 8E97 8ECE	00001097	000010CE	262 ED PRT3, DECNUM	
			263 MVC CCPRTEXP(1), PRT3+15	fill in message with CC field	
0000037C	B982 0022		264		
00000380	4320 8EF0		265	XGR R2, R2	get CCFOUND as U8
00000384	4E20 8ED5	000010F0	266	IC R2, CCFOUND	
00000388	D211 8EBF 8EA9	000010D5	267	CVD R2, DECNUM	and convert
0000038E	DE11 8EBF 8ED5	000010BF	268	MVC PRT3, EDIT	
00000394	D200 8EA7 8ECE	000010D5	269	ED PRT3, DECNUM	
		000010A7	270	MVC CCPRTGOT(1), PRT3+15	fill in message with ccfound
0000039A	4100 0055		271		
0000039E	4110 8E54	00000055	272	LA R0, CCPRTLNG	message length
000003A2	45F0 8230	00001054	273	LA R1, CCPRTLINE	messagfe address
		00000430	274	BAL R15, RPERROR	
000003A6	47F0 8212	00000412	275		
			276		
			277	B FAILCONT	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				279 ****	*****	*****	*****
				280 * result not as expected:	*****	*****	*****
				281 * issue message with test number, instruction under test	*****	*****	*****
				282 * and instruction 12	*****	*****	*****
				283 ****	*****	*****	*****
000003AA	4820 5004	000003AA	00000001	284 FAILMSG EQU *	LH R2, TNUM	R2, DECNUM	get test number and convert
000003AE	4E20 8ED5		00000004	285 CVD	ED PRT3, EDIT	PRT3, DECNUM	
000003B2	D211 8EBF 8EA9	000010BF	000010A9	287 MVC	MVC	PRT3, DECNUM	
000003B8	DE11 8EBF 8ED5	000010BF	000010D5	288 ED	ED	PRT3+13	
000003BE	D202 8E18 8ECC	00001018	000010CC	289 MVC	MVC	PRTNUM(3), PRT3+13	fill in message with test #
000003C4	D207 8E33 500B	00001033	0000000B	290			
				291	MVC	PRTNAME, OPNAME	fill in message with instruction
				292			
000003CA	B982 0022			293 XGR	R2, R2	R2, I3	get i3 as U8
000003CE	4320 5007		00000007	294 IC	IC	CVD	and convert
000003D2	4E20 8ED5		000010D5	295 CVD	R2, DECNUM	R2, DECNUM	
000003D6	D211 8EBF 8EA9	000010BF	000010A9	296 MVC	MVC	PRT3, EDIT	
000003DC	DE11 8EBF 8ED5	000010BF	000010D5	297 ED	ED	PRT3, DECNUM	
000003E2	D202 8E44 8ECC	00001044	000010CC	298 MVC	MVC	PRTI3(3), PRT3+13	fill in message with i3 field
000003E8	B982 0022			299			
000003EC	4320 5008		00000008	300 XGR	R2, R2	R2, M4	get m4 as U8
				301 IC	IC	CVD	and convert
000003F0	4E20 8ED5		000010D5	302 CVD	R2, DECNUM	R2, DECNUM	
000003F4	D211 8EBF 8EA9	000010BF	000010A9	303 MVC	MVC	PRT3, EDIT	
000003FA	DE11 8EBF 8ED5	000010BF	000010D5	304 ED	ED	PRT3, DECNUM	
00000400	D202 8E51 8ECD	00001051	000010CD	305 MVC	MVC	PRTM4(3), PRT3+14	fill in message with m4 field
00000406	4100 004C		0000004C	306 307 LA	LA	R0, PRTLNG	message length
0000040A	4110 8E08		00001008	308 LA	LA	R1, PRTLINE	message address
0000040E	45F0 8230		00000430	309 BAL	BAL	R15, RPERROR	
				310			
				311 ****	*****	*****	*****
				312 * continue after a failed test	*****	*****	*****
				313 ****	*****	*****	*****
00000412	5800 835C	00000412	00000001	314 FAILCONT EQU *	L R0, =F' 1'	R0, FAILED	set GLOBAL failed test indicator
00000416	5000 8E00		0000055C	315 ST	ST	ST	
			00001000	316			
0000041A	41C0 C004		00000004	317			
0000041E	47F0 80DC		000002DC	318 LA	LA	R12, 4(0, R12)	next test address
				319 B	B	NEXTE6	
				320			
				321 ****	*****	*****	*****
				322 * end of testing; set ending psw	*****	*****	*****
				323 ****	*****	*****	*****
00000422	5810 8E00	00000422	00000001	324 ENDTEST EQU *	L R1, FAILED	R1, R1	did a test fail?
00000426	1211		00001000	325 LTR	LTR	EOJ	No, exit
00000428	4780 8330		00000530	326 BZ	BZ	FAILTEST	Yes, exit with BAD PSW
0000042C	47F0 8348		00000548	327 B	B		
				328			
				329			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				331 ****	*****	*****
				332 * RPTERROR	Report instruction test in error	
				333 *	R0 = MESSGAE LENGTH	
				334 *	R1 = ADDRESS OF MESSAGE	
				335 ****	*****	*****
00000430	50F0 8250		00000450	337 RPTERROR ST	R15, RPTSAVE	Save return address
00000434	5050 8254		00000454	338 ST	R5, RPTSVR5	Save R5
				339 *		
				340 *	Use Hercules Diagnose for Message to console	
				341 *		
00000438	9002 8258		00000458	342 STM	R0, R2, RPTDWSAV	save regs used by MSG
0000043C	4520 8268		00000468	343 BAL	R2, MSG	call Hercules console MSG display
00000440	9802 8258		00000458	344 LM	R0, R2, RPTDWSAV	restore regs
00000444	5850 8254		00000454	346 L	R5, RPTSVR5	Restore R5
00000448	58F0 8250		00000450	347 L	R15, RPTSAVE	Restore return address
0000044C	07FF			348 BR	R15	Return to caller
00000450	00000000			350 RPTSAVE DC	F' 0'	R15 save area
00000454	00000000			351 RPTSVR5 DC	F' 0'	R5 save area
00000458	00000000 00000000			353 RPTDWSAV DC	2D' 0'	R0-R2 save area for MSG call

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				355 **** 356 * Issue HERCULES MESSAGE pointed to by R1, length in R0 357 * R2 = return address 358 **** 359			
00000468	4900 8364		00000564	360 MSG CH R0, =H' 0' 361 BNHR R2		Do we even HAVE a message? No, ignore	
0000046C	07D2			362			
0000046E	9002 82A4		000004A4	363 STM R0, R2, MSGSAVE 364		Save registers	
00000472	4900 8366		00000566	365 CH R0, =AL2(L' MSGMSG) 366 BNH MSGOK 367 LA R0, L' MSGMSG 368		Message length within limits? Yes, continue No, set to maximum	
00000476	47D0 827E		0000047E				
0000047A	4100 005F		0000005F				
0000047E	1820		000004B0	369 MSGOK LR R2, R0 370 BCTR R2, 0 371 EX R2, MSGMVC 372		Copy length to work register Minus-1 for execute Copy message to O/P buffer	
00000480	0620			373 LA R2, 1+L' MSGCMD(, R2) 374 LA R1, MSGCMD 375		Calculate true command length Point to true command	
00000482	4420 82B0						
00000486	4120 200A		0000000A	376 DC X' 83' , X' 12' , X' 0008' 377 BZ MSGRET 378		Issue Hercules Diagnose X' 008' Return if successful	
0000048A	4110 82B6		000004B6				
0000048E	83120008		0000049E	379 LTR R2, R2 380 BZ MSGRET 381		Is Diag8 Ry (R2) 0? an error occurred but continue	
00000492	4780 829E			382 DC H' 0' 383		CRASH for debugging purposes	
00000496	1222		0000049E				
00000498	4780 829E			384 MSGRET LM R0, R2, MSGSAVE 385 MVC R2		Restore registers Return to caller	
0000049C	0000						
0000049E	9802 82A4		000004A4				
000004A2	07F2						
000004A4	00000000 00000000	000004BF	00000000	387 MSGSAVE DC 3F' 0' 388 MSGMVC MVC MSGMSG(0), 0(R1)		Registers save area Executed instruction	
000004B0	D200 82BF 1000						
000004B6	D4E2C7D5 D6C8405C			390 MSGCMD DC C' MSGNOH * ' 391 MSGMSG DC CL95' '' 392		*** HERCULES MESSAGE COMMAND *** The message text to be displayed	
000004BF	40404040 40404040						

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				394 ****	*****
				395 *	Normal completion or Abnormal termination PSWs
				396 ****	*****
00000520	00020001 80000000			398 EOJPSW DC OD' 0' , X' 0002000180000000' , AD(0)	
00000530	B2B2 8320	00000520	400 EOJ LPSWE EOJPSW		Normal completion
00000538	00020001 80000000			402 FAILPSW DC OD' 0' , X' 0002000180000000' , AD(X' BAD')	
00000548	B2B2 8338	00000538	404 FAILTEST LPSWE FAILPSW		Abnormal termination
				406 ****	*****
				407 *	Working Storage
				408 ****	*****
0000054C	00000000		410 CTLR0 DS F		CR0
00000550	00000000		411 DS F		
00000554			413 LTORG ,		Literals pool
00000554	00000002		414 =F' 2'		
00000558	00003560		415 =A(E6TESTS)		
0000055C	00000001		416 =F' 1'		
00000560	00000003		417 =XL4' 3'		
00000564	0000		418 =H' 0'		
00000566	005F		419 =AL2(L' MSGMSG)		
			420		
			421 *	some constants	
			422		
	00000400	00000001	423 K EQU 1024		One KB
	00001000	00000001	424 PAGE EQU (4*K)		Size of one page
	00010000	00000001	425 K64 EQU (64*K)		64 KB
	00100000	00000001	426 MB EQU (K*K)		1 MB
			427		
			428		
	AABBCCDD	00000001	429 REG2PATT EQU X' AABBCCDD'		Polluted Register pattern
	000000DD	00000001	430 REG2LOW EQU X' DD'		(last byte above)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				432 *=====
				433 *
				434 * NOTE: start data on an address that is easy to display
				435 * within Hercules
				436 *
				437 *=====
				438
00000568		00000568	00001000	439 ORG ZVE6TST+X'1000'
00001000	00000000			440 FAILED DC F'0'
00001004	00000000			441 TESTING DC F'0'
				some test failed? current test number
				443 *****
				444 * TEST failed : result messgae
				445 *****
				446 *
				447 * failed message and associated editting
				448 *
00001008	40404040 40404040			449 PRTLINE DC C' Test # '
00001018	A7A7A7			450 PRTNUM DC C' xxx'
0000101B	40868189 93858440			451 DC C' failed for instruction '
00001033	A7A7A7A7 A7A7A7A7			452 PRTNAME DC CL8' xxxxxxxx'
0000103B	40A689A3 884089F3			453 DC C' with i3='
00001044	A7A7A76B			454 PRTI3 DC C' xxx, '
00001048	40A689A3 884094F4			455 DC C' with m4='
00001051	A7A7			456 PRTM4 DC C' xx'
00001053	4B	0000004C	00000001	457 DC C' . '
				458 PRTLNG EQU *-PRTLINE
				460 *****
				461 * TEST failed : CC message
				462 *****
				463 *
				464 * failed message and associated editting
				465 *
00001054	40404040 40404040			466 CCPRTLINE DC C' Test # '
00001064	A7A7A7			467 CCPRTNUM DC C' xxx'
00001067	40A69996 95874083			468 DC C' wrong cc for instruction '
00001081	A7A7A7A7 A7A7A7A7			469 CCPRTNAME DC CL8' xxxxxxxx'
00001089	4085A797 8583A385			470 DC C' expected: cc='
00001097	A7			471 CCPRTEXP DC C' x'
00001098	6B			472 DC C' , '
00001099	40998583 8589A585			473 DC C' received: cc='
000010A7	A7	00000055	00000001	474 CCPRTGOT DC C' x'
000010A8	4B			475 DC C' . '
				476 CCPRTLNG EQU *-CCPRTLINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				510 **** 511 * E6TEST DSECT 512 ****
00000000	00000000			514 E6TEST DSECT ,
00000004	0000			515 TSUB DC A(0) pointer to test 516 TNUM DC H'00' Test Number
00000006	00			517 DC XL1'00'
00000007	00			518 I3 DC HL1'00' i3
00000008	00			519 M4 DC HL1'00' m4
00000009	00			520 CC DC HL1'00' cc
0000000A	00			521 CCMASK DC HL1'00' not expected CC mask 522
0000000B	40404040 40404040			523 OPNAME DC CL8' ' E6 name 524
00000014	00000000			525 RELEN DC A(0) RESULT LENGTH 00000018 00000000 526 READDR DC A(0) expected result address 527 528 **
				529 * test routine will be here (from VRR_K macro) 530 * followed by 531 * 16-byte EXPECTED RESULT 532 * 8-byte byte source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
534				*****
535	*			Macros to help build test tables
536	*			-
537	*			VRR_K Macro to help build test tables
538				*****
539				MACRO
540				VRR_K &INST, &I3, &M4, &CC
541	.	*		&INST - instruction under test
542	.	*		&I3
543	.	*		&M4
544	.	*		&CC - expected CC
545	.	*		
546		LCLA	&XCC(4)	&CC has mask values for FAILED condition codes
547	&XCC(1)	SETA	7	CC != 0
548	&XCC(2)	SETA	11	CC != 1
549	&XCC(3)	SETA	13	CC != 2
550	&XCC(4)	SETA	14	CC != 3
551				
552		GBLA	&TNUM	
553	&TNUM	SETA	&TNUM+1	
554				
555		DS	OFD	
556		USING	*, R5	base for test data and test routine
557				
558	T&TNUM	DC	A(X&TNUM)	address of test routine
559		DC	H' &TNUM	test number
560		DC	XL1' 00'	
561		DC	HL1' &I3'	i3
562		DC	HL1' &M4'	m4
563		DC	HL1' &CC'	cc
564		DC	HL1' &XCC(&CC+1)'	cc failed mask
565				
566		DC	CL8' &INST'	instruction name
567				
568		DC	A(16)	result length
569	REA&TNUM	DC	A(RE&TNUM)	result address
570	.	*		
571	*			INSTRUCTION UNDER TEST ROUTINE
572	X&TNUM	DS	OF	
573		VL	V1, V1FUDGE	pollute V1
574		LG	R2, RE&TNUM+16	get R2 source
575				
576		&INST	V1, R2, &I3, &M4	test instruction
577				
578		VST	V1, V1OUTPUT	save
579		EPSW	R2, R0	extract psw
580		ST	R2, CCPSW	to save CC
581				
582		BR	R11	return
583				
584	RE&TNUM	DC	OF	
585		DROP	R5	
586				
587		MEND		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
589				*****
590	*			PTTABLE Macro to generate table of pointers to individual tests
591				*****
592				
593				MACRO
594				PTTABLE
595				GBLA &TNUM
596				LCLA &CUR
597	&CUR			SETA 1
598	. *			
599	TTABLE	DS	OF	
600	. LOOP	ANOP		
601	. *			
602		DC	A(T&CUR)	address of test
603	. *			
604	&CUR	SETA	&CUR+1	
605		AIF	(&CUR LE &TNUM).LOOP	
606	* .			
607		DC	A(0)	END OF TABLE
608		DC	A(0)	
609	. *			
610				MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				612 **** 613 * E6 VRR_K tests 614 ****
00001198	00000000 0000370F		615 ZVE6TST CSECT , 616 DS OF	
			618 PRINT DATA	
			619 * 620 * E658 VCVD - VECTOR CONVERT TO DECIMAL (32) 621 * E65A VCVDG - VECTOR CONVERT TO DECIMAL (64) 622 *	
			623 * VRR_K instr, i3, m4, cc 624 * followed by 625 * v1 - expected result (16 bytes) 626 * R2 - 8 byte binary source 627	
			628 *- 629 * VCVD - VECTOR CONVERT TO DECIMAL (32) 630 *	
			631 * VCVD simple m4= 1 (LB=0, P1=0 , CS=1) 632 * m4= 3 (LB=0, P1=1 , CS=1) 633 * m4= 9 (LB=1, P1=0 , CS=1) 634 * m4= 11 (LB=1, P1=1 , CS=1) 635 *	
			636 * i3= 137 (IOM=1, RDC= 9) 637 * i3= 159 (IOM=1, RDC=31) 638 *	
			639 * VCVD m4= 1 (LB=0, P1=0 , CS=1) 640 * i3= 159 (IOM=1, RDC=31) 641	
			642 VRR_K VCVD, 159, 1, 0	
00001198			643+ DS OFD	
00001198		00001198	644+ USING *, R5	base for test data and test routine
00001198	000011B4		645+T1 DC A(X1)	address of test routine
0000119C	0001		646+ DC H' 1'	test number
0000119E	00		647+ DC XL1' 00'	
0000119F	9F		648+ DC HL1' 159'	i3
000011A0	01		649+ DC HL1' 1'	m4
000011A1	00		650+ DC HL1' 0'	cc
000011A2	07		651+ DC HL1' 7'	cc failed mask
000011A3	E5C3E5C4 40404040		652+ DC CL8' VCVD'	instruction name
000011AC	00000010		653+ DC A(16)	result length
000011B0	000011D8		654+REA1 DC A(REA1)	result address
			655+*	INSTRUCTION UNDER TEST ROUTINE
000011B4			656+X1 DS OF	
000011B4	E710 8F48 0006	00001148	657+ VL V1, V1FUDGE	pollute V1
000011BA	E320 5050 0004	000011E8	658+ LG R2, RE1+16	get R2 source
000011C0	E612 0019 F058		659+ VCVD V1, R2, 159, 1	test instruction
000011C6	E710 8F10 000E	00001110	660+ VST V1, V1OUTPUT	save
000011CC	B98D 0020		661+ EPSW R2, R0	extract psw
000011D0	5020 8EE8	000010E8	662+ ST R2, CCPSW	to save CC
000011D4	07FB		663+ BR R11	return
000011D8			664+REA1 DC OF	
000011D8			665+ DROP R5	
000011D8	00000000 00000000		666 DC XL16' 00000000000000000000000000000000C'	V1 result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000011E0	00000000 0000000C			667 DC FD' 0'		R2 source
000011E8	00000000 00000000			668 669 670+ VRR_K VCVD, 159, 1, 0 DS OFD		
000011F0		000011F0		671+ USING *, R5 672+T2 DC A(X2) 673+ DC H' 2'	base for test data and test routine address of test routine test number	
000011F0	0000120C			674+ DC XL1' 00' 675+ DC HL1' 159' 676+ DC HL1' 1' 677+ DC HL1' 0' 678+ DC HL1' 7'	i3 m4 cc cc failed mask instruction name	
000011F4	0002			679+ DC CL8' VCVD'	instruction name	
000011F6	00			680+ DC A(16)	result length	
000011F7	9F			681+REA2 DC A(RE2)	result address	
000011F8	01			682+*	INSTRUCTION UNDER TEST ROUTINE	
000011F9	00					
000011FA	07					
000011FB	E5C3E5C4 40404040					
00001204	00000010					
00001208	00001230					
0000120C				683+X2 DS OF		
0000120C	E710 8F48 0006	00001148		684+ VL V1, V1FUDGE	pollute V1	
00001212	E320 9040 0004	00001240		685+ LG R2, RE2+16	get R2 source	
00001218	E612 0019 F058			686+ VCVD V1, R2, 159, 1	test instruction	
0000121E	E710 8F10 000E	00001110		687+ VST V1, V1OUTPUT	save	
00001224	B98D 0020			688+ EPSW R2, R0	extract psw	
00001228	5020 8EE8	000010E8		689+ ST R2, CCPSW	to save CC	
0000122C	07FB			690+ BR R11	return	
00001230				691+RE2 DC OF		
00001230				692+ DROP R5		
00001230	00000000 00000000			693 DC XL16' 00000000000000000000000000000001C'	V1 result	
00001238	00000000 0000001C					
00001240	00000000 00000001			694 DC FD' 1'	R2 source	
00001240				695		
00001248				696 VRR_K VCVD, 159, 1, 0		
00001248		00001248		697+ DS OFD		
00001248	00001264			698+ USING *, R5 699+T3 DC A(X3)	base for test data and test routine address of test routine test number	
0000124C	0003			700+ DC H' 3'		
0000124E	00			701+ DC XL1' 00'		
0000124F	9F			702+ DC HL1' 159'	i3	
00001250	01			703+ DC HL1' 1'	m4	
00001251	00			704+ DC HL1' 0'	cc	
00001252	07			705+ DC HL1' 7'	cc failed mask	
00001253	E5C3E5C4 40404040			706+ DC CL8' VCVD'	instruction name	
0000125C	00000010			707+ DC A(16)	result length	
00001260	00001288			708+REA3 DC A(RE3)	result address	
00001260				709+*	INSTRUCTION UNDER TEST ROUTINE	
00001264				710+X3 DS OF		
00001264	E710 8F48 0006	00001148		711+ VL V1, V1FUDGE	pollute V1	
0000126A	E320 5050 0004	00001298		712+ LG R2, RE3+16	get R2 source	
00001270	E612 0019 F058			713+ VCVD V1, R2, 159, 1	test instruction	
00001276	E710 8F10 000E	00001110		714+ VST V1, V1OUTPUT	save	
0000127C	B98D 0020			715+ EPSW R2, R0	extract psw	
00001280	5020 8EE8	000010E8		716+ ST R2, CCPSW	to save CC	
00001284	07FB			717+ BR R11	return	
00001288				718+RE3 DC OF		
00001288				719+ DROP R5		
00001288	00000000 00000000			720 DC XL16' 00000000000000000000000000000001D'	V1 result	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001290	00000000 0000001D			721 DC FD' -1'		R2 source
00001298	FFFFFFF FFFFFFFF			722		
				723 VRR_K VCVD, 159, 1, 0		INT_MAX
000012A0				724+ DS OFD		
000012A0	000012BC	000012A0		725+ USING *, R5	base for test data and test routine	
000012A0	0004			726+T4 DC A(X4)	address of test routine	
000012A4	0004			727+ DC H'4'	test number	
000012A6	00			728+ DC XL1' 00'		
000012A7	9F			729+ DC HL1' 159'	i3	
000012A8	01			730+ DC HL1' 1'	m4	
000012A9	00			731+ DC HL1' 0'	cc	
000012AA	07			732+ DC HL1' 7'	cc failed mask	
000012AB	E5C3E5C4 40404040			733+ DC CL8' VCVD'	instruction name	
000012B4	00000010			734+ DC A(16)	result length	
000012B8	000012E0			735+REA4 DC A(RE4)	result address	
				736+*	INSTRUCTION UNDER TEST ROUTINE	
000012BC				737+X4 DS OF		
000012BC	E710 8F48 0006	00001148		738+ VL V1, V1FUDGE	pollute V1	
000012C2	E320 5050 0004	000012F0		739+ LG R2, RE4+16	get R2 source	
000012C8	E612 0019 F058			740+ VCVD V1, R2, 159, 1	test instruction	
000012CE	E710 8F10 000E	00001110		741+ VST V1, V1OUTPUT	save	
000012D4	B98D 0020			742+ EPSW R2, R0	extract psw	
000012D8	5020 8EE8	000010E8		743+ ST R2, CCPSW	to save CC	
000012DC	07FB			744+ BR R11	return	
000012E0				745+REA4 DC OF		
000012E0				746+ DROP R5		
000012E0	00000000 00000000			747 DC XL16' 000000000000000000000000000000002147483647C'	V1 result	
000012E8	00000214 7483647C					
000012F0	00000000 7FFFFFFF			748 DC FD' 2147483647'	R2 source	
				749		
				750 VRR_K VCVD, 159, 1, 0	INT_MIN	
000012F8				751+ DS OFD		
000012F8	00001314	000012F8		752+ USING *, R5	base for test data and test routine	
000012F8	0005			753+T5 DC A(X5)	address of test routine	
000012FC	0005			754+ DC H'5'	test number	
000012FE	00			755+ DC XL1' 00'		
000012FF	9F			756+ DC HL1' 159'	i3	
00001300	01			757+ DC HL1' 1'	m4	
00001301	00			758+ DC HL1' 0'	cc	
00001302	07			759+ DC HL1' 7'	cc failed mask	
00001303	E5C3E5C4 40404040			760+ DC CL8' VCVD'	instruction name	
0000130C	00000010			761+ DC A(16)	result length	
00001310	00001338			762+REA5 DC A(RE5)	result address	
				763+*	INSTRUCTION UNDER TEST ROUTINE	
00001314				764+X5 DS OF		
00001314	E710 8F48 0006	00001148		765+ VL V1, V1FUDGE	pollute V1	
0000131A	E320 5050 0004	00001348		766+ LG R2, RE5+16	get R2 source	
00001320	E612 0019 F058			767+ VCVD V1, R2, 159, 1	test instruction	
00001326	E710 8F10 000E	00001110		768+ VST V1, V1OUTPUT	save	
0000132C	B98D 0020			769+ EPSW R2, R0	extract psw	
00001330	5020 8EE8	000010E8		770+ ST R2, CCPSW	to save CC	
00001334	07FB			771+ BR R11	return	
00001338				772+REA5 DC OF		
00001338				773+ DROP R5		
00001338	00000000 00000000			774 DC XL16' 000000000000000000000000000000002147483648D'	V1 result	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001340	00000214 7483648D			775 DC FD' - 2147483648'		R2 source
00001348	FFFFFFFFFF 80000000			776 777 * VCVD 778 * m4= 1 (LB=0, P1=0 , CS=1) i3= 137 (IOM=1, RDC= 9)		
00001350				779 780 VRR_K VCVD, 137, 1, 0 781+ DS OFD		
00001350	0000136C	00001350		782+ USING *, R5 783+T6 DC A(X6)	base for test data and test routine	
00001350	0006			784+ DC H' 6'	address of test routine	
00001356	00			785+ DC XL1' 00'	test number	
00001357	89			786+ DC HL1' 137'	i3	
00001358	01			787+ DC HL1' 1'	m4	
00001359	00			788+ DC HL1' 0'	cc	
0000135A	07			789+ DC HL1' 7'	cc failed mask	
0000135B	E5C3E5C4 40404040			790+ DC CL8' VCVD'	instruction name	
00001364	00000010			791+ DC A(16)	result length	
00001368	00001390			792+REA6 DC A(RE6)	result address	
				793+*	INSTRUCTION UNDER TEST ROUTINE	
0000136C				794+X6 DS OF		
0000136C	E710 8F48 0006	00001148		795+ VL V1, V1FUDGE	pollute V1	
00001372	E320 5050 0004	000013A0		796+ LG R2, RE6+16	get R2 source	
00001378	E612 0018 9058			797+ VCVD V1, R2, 137, 1	test instruction	
0000137E	E710 8F10 000E	00001110		798+ VST V1, V1OUTPUT	save	
00001384	B98D 0020			799+ EPSW R2, R0	extract psw	
00001388	5020 8EE8	000010E8		800+ ST R2, CCPSW	to save CC	
0000138C	07FB			801+ BR R11	return	
00001390				802+RE6 DC OF		
00001390	00000000 00000000			803+ DROP R5		
00001398	00000000 0000000C			804 DC XL16' 00000000000000000000000000000000C'	V1 result	
000013A0	00000000 00000000			805 DC FD' 0'	R2 source	
000013A8				806		
000013A8	000013C4	000013A8		807 VRR_K VCVD, 137, 1, 0 808+ DS OFD		
000013A8	0007			809+ USING *, R5 810+T7 DC A(X7)	base for test data and test routine	
000013AC	00			811+ DC H' 7'	address of test routine	
000013AE	89			812+ DC XL1' 00'	test number	
000013AF	01			813+ DC HL1' 137'	i3	
000013B0	00			814+ DC HL1' 1'	m4	
000013B1	07			815+ DC HL1' 0'	cc	
000013B2	E5C3E5C4 40404040			816+ DC HL1' 7'	cc failed mask	
000013B3	00000010			817+ DC CL8' VCVD'	instruction name	
000013BC	000013E8			818+ DC A(16)	result length	
000013C0				819+REA7 DC A(RE7)	result address	
				820+*	INSTRUCTION UNDER TEST ROUTINE	
000013C4				821+X7 DS OF		
000013C4	E710 8F48 0006	00001148		822+ VL V1, V1FUDGE	pollute V1	
000013CA	E320 5050 0004	000013F8		823+ LG R2, RE7+16	get R2 source	
000013D0	E612 0018 9058			824+ VCVD V1, R2, 137, 1	test instruction	
000013D6	E710 8F10 000E	00001110		825+ VST V1, V1OUTPUT	save	
000013DC	B98D 0020			826+ EPSW R2, R0	extract psw	
000013E0	5020 8EE8	000010E8		827+ ST R2, CCPSW	to save CC	
000013E4	07FB			828+ BR R11	return	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000013E8				829+RE7	DC	OF
000013E8				830+	DROP	R5
000013E8	00000000 00000000			831	DC	XL16' 000000000000000000000000000000001C'
000013F0	00000000 0000001C					V1 result
000013F8	00000000 00000001			832	DC	FD' 1'
				833		
				834	VRR_K	VCVD, 137, 1, 0
				835+	DS	OFD
00001400		00001400		836+	USING	*, R5
00001400	0000141C			837+T8	DC	A(X8)
00001404	0008			838+	DC	H' 8'
00001406	00			839+	DC	XL1' 00'
00001407	89			840+	DC	HL1' 137'
00001408	01			841+	DC	HL1' 1'
00001409	00			842+	DC	HL1' 0'
0000140A	07			843+	DC	HL1' 7'
0000140B	E5C3E5C4 40404040			844+	DC	CL8' VCVD'
00001414	00000010			845+	DC	A(16)
00001418	00001440			846+REA8	DC	A(RE8)
				847+*		
0000141C				848+X8	DS	OF
0000141C	E710 8F48 0006		00001148	849+	VL	V1, V1FUDGE
00001422	E320 5050 0004		00001450	850+	LG	R2, RE8+16
00001428	E612 0018 9058			851+	VCVD	V1, R2, 137, 1
0000142E	E710 8F10 000E		00001110	852+	VST	V1, V1OUTPUT
00001434	B98D 0020			853+	EPSW	R2, R0
00001438	5020 8EE8		000010E8	854+	ST	R2, CCPSW
0000143C	07FB			855+	BR	R11
00001440				856+REA8	DC	OF
				857+	DROP	R5
00001440	00000000 00000000			858	DC	XL16' 000000000000000000000000000000001D'
00001448	00000000 0000001D					V1 result
00001450	FFFFFF FFFFFFFF			859	DC	FD' - 1'
				860		
				861	VRR_K	VCVD, 137, 1, 3
				862+	DS	OFD
00001458	00001474	00001458		863+	USING	*, R5
00001458	0009			864+T9	DC	A(X9)
0000145C	00			865+	DC	H' 9'
0000145E	89			866+	DC	XL1' 00'
0000145F	01			867+	DC	HL1' 137'
00001460	03			868+	DC	HL1' 1'
00001461	0E			869+	DC	HL1' 3'
00001462	E5C3E5C4 40404040			870+	DC	HL1' 14'
00001463	00000010			871+	DC	CL8' VCVD'
0000146C	00000010			872+	DC	A(16)
00001470	00001498			873+REA9	DC	A(RE9)
				874+*		
00001474				875+X9	DS	OF
00001474	E710 8F48 0006		00001148	876+	VL	V1, V1FUDGE
0000147A	E320 5050 0004		000014A8	877+	LG	R2, RE9+16
00001480	E612 0018 9058			878+	VCVD	V1, R2, 137, 1
00001486	E710 8F10 000E		00001110	879+	VST	V1, V1OUTPUT
0000148C	B98D 0020			880+	EPSW	R2, R0
00001490	5020 8EE8		000010E8	881+	ST	R2, CCPSW
00001494	07FB			882+	BR	R11

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001498				883+RE9	DC	OF
00001498				884+	DROP	R5
00001498	00000000 00000000			885	DC	XL16' 00000000000000000000000000000000147483647C'
000014A0	00000014 7483647C					V1 result
000014A8	00000000 7FFFFFFF			886	DC	FD' 2147483647'
				887		
				888	VRR_K	VCVD, 137, 1, 3
000014B0		000014B0		889+	DS	OFD
000014B0	000014CC			890+	USING	* , R5
000014B0	000A			891+T10	DC	A(X10)
000014B4	00			892+	DC	H' 10'
000014B6	89			893+	DC	XL1' 00'
000014B7	01			894+	DC	HL1' 137'
000014B8	03			895+	DC	HL1' 1'
000014B9	0E			896+	DC	HL1' 3'
000014BA	E5C3E5C4 40404040			897+	DC	HL1' 14'
000014BB	00000010			898+	DC	CL8' VCVD'
000014C4	000014F0			899+	DC	A(16)
000014C8	000014F0			900+REA10	DC	A(RE10)
				901+*		
000014CC				902+X10	DS	OF
000014CC	E710 8F48 0006	00001148		903+	VL	V1, V1FUDGE
000014D2	E320 5050 0004	00001500		904+	LG	R2, RE10+16
000014D8	E612 0018 9058			905+	VCVD	V1, R2, 137, 1
000014DE	E710 8F10 000E	00001110		906+	VST	V1, V1OUTPUT
000014E4	B98D 0020			907+	EPSW	R2, R0
000014E8	5020 8EE8	000010E8		908+	ST	R2, CCPSW
000014EC	07FB			909+	BR	R11
000014F0				910+RE10	DC	OF
000014F0				911+	DROP	R5
000014F0	00000000 00000000			912	DC	XL16' 00000000000000000000000000000000147483648D'
000014F8	00000014 7483648D					V1 result
00001500	FFFFFFFFFF 80000000			913	DC	FD' - 2147483648'
				914		
				915 *		
				916 * VCVD		m4= 3 (LB=0, P1=1 , CS=1)
				917 *		i3= 159 (IOM=1, RDC=31)
				918		
00001508		00001508		919	VRR_K	VCVD, 159, 3, 0
00001508	00001524			920+	DS	OFD
00001508	000B			921+	USING	* , R5
0000150C	00			922+T11	DC	A(X11)
0000150E	9F			923+	DC	H' 11'
0000150F	03			924+	DC	XL1' 00'
00001510	00			925+	DC	HL1' 159'
00001511	07			926+	DC	HL1' 3'
00001512	E5C3E5C4 40404040			927+	DC	HL1' 0'
00001513	00000010			928+	DC	HL1' 7'
0000151C	00001548			929+	DC	CL8' VCVD'
00001520	00001548			930+	DC	A(16)
				931+REA11	DC	A(RE11)
				932+*		
00001524	E710 8F48 0006	00001148		933+X11	DS	OF
0000152A	E320 5050 0004	00001558		934+	VL	V1, V1FUDGE
00001530	E612 0039 F058			935+	LG	R2, RE11+16
				936+	VCVD	V1, R2, 159, 3

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001536	E710 8F10 000E		00001110	937+ 938+	VST EPSW	V1, V1OUTPUT R2, R0	save extract psw
0000153C	B98D 0020			939+ 940+	ST BR	R2, CCPSW R11	to save CC
00001540	5020 8EE8		000010E8	941+RE11	DC	OF	return
00001544	07FB			942+ 943	DROP DC	R5 XL16' 00000000000000000000000000000000F'	V1 result
00001548				944 945	DC	FD' 0'	R2 source
00001548	00000000 00000000			946	VRR_K	VCVD, 159, 3, 0	
00001550	00000000 0000000F			947+ 948+	DS USING	OFD *, R5	base for test data and test routine
00001558	00000000 00000000			949+T12	DC	A(X12)	address of test routine
00001560		00001560		950+ 951+	DC	H' 12' XL1' 00'	test number
00001564	000C			952+ 953+	DC	HL1' 159' HL1' 3'	i3
00001566	00			954+ 955+	DC	HL1' 0' HL1' 7'	m4 cc cc failed mask
00001567	9F			956+	DC	CL8' VCVD'	instruction name
00001568	03			957+ 958+REA12	DC	A(16) A(REA12)	result length result address
00001569	00			959+*			INSTRUCTION UNDER TEST ROUTINE
0000156A	07			960+X12	DS	OF	
0000156B	E5C3E5C4 40404040			961+ 962+	VL LG	V1, V1FUDGE R2, RE12+16	pollute V1 get R2 source
00001574	00000010			963+	VCVD	V1, R2, 159, 3	test instruction
00001578	000015A0		00001110	964+	VST	V1, V1OUTPUT	save
0000157C				965+	EPSW	R2, R0	extract psw
0000157C	E710 8F48 0006		00001148	966+ 967+	ST BR	R2, CCPSW R11	to save CC return
00001582	E320 5050 0004		000015B0	968+REA12	DC	OF	
00001588	E612 0039 F058			969+	DROP	R5	
0000158E	E710 8F10 000E			970	DC	XL16' 00000000000000000000000000000001F'	V1 result
00001594	B98D 0020			971 972	DC	FD' 1'	R2 source
00001598	5020 8EE8		000010E8	973	VRR_K	VCVD, 159, 3, 0	
0000159C	07FB			974+ 975+	DS USING	OFD *, R5	base for test data and test routine
000015A0		000015B8		976+T13	DC	A(X13)	address of test routine
000015A0	000D			977+ 978+	DC	H' 13' XL1' 00'	test number
000015BC	00			979+ 980+	DC	HL1' 159' HL1' 3'	i3
000015BF	9F			981+ 982+	DC	HL1' 0' HL1' 7'	m4 cc cc failed mask
000015C0	03			983+ 984+	DC	CL8' VCVD' A(16)	instruction name result length
000015C1	00			985+REA13	DC	A(REA13)	result address
000015C2	07			986+*			INSTRUCTION UNDER TEST ROUTINE
000015C3	E5C3E5C4 40404040			987+X13	DS	OF	
000015CC	00000010		00001148	988+ 989+	VL LG	V1, V1FUDGE R2, RE13+16	pollute V1 get R2 source
000015D0	000015F8		00001608	990+	VCVD	V1, R2, 159, 3	test instruction

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000015E6	E710 8F10 000E		00001110	991+ 992+	VST EPSW	V1, V1OUTPUT R2, R0	save extract psw
000015EC	B98D 0020		000010E8	993+ 994+ 995+RE13	ST BR DC	R2, CCPSW R11 OF	to save CC return
000015F0	5020 8EE8			996+	DROP	R5	
000015F4	07FB			997	DC	XL16' 00000000000000000000000000000001F'	V1 result
000015F8				998 999	DC	FD' - 1'	R2 source
00001600	00000000 00000000			1000	VRR_K	VCVD, 159, 3, 0	INT_MAX
00001600	00000000 0000001F			1001+	DS	OFD	
00001608	FFFFFFFFFF FFFFFFFF			1002+ 1003+T14	USING	*, R5 A(X14)	base for test data and test routine address of test routine
00001610		00001610		1004+	DC	H' 14'	test number
00001614	000E			1005+	DC	XL1' 00'	
00001616	00			1006+	DC	HL1' 159'	i3
00001617	9F			1007+	DC	HL1' 3'	m4
00001618	03			1008+	DC	HL1' 0'	cc
00001619	00			1009+	DC	HL1' 7'	cc failed mask
0000161A	07			1010+	DC	CL8' VCVD'	instruction name
0000161B	E5C3E5C4 40404040			1011+	DC	A(16)	result length
00001624	00000010			1012+RE14	DC	A(RE14)	result address
00001628	00001650			1013+*			INSTRUCTION UNDER TEST ROUTINE
0000162C				1014+X14	DS	OF	
0000162C	E710 8F48 0006		00001148	1015+	VL	V1, V1FUDGE	pollute V1
00001632	E320 5050 0004		00001660	1016+	LG	R2, RE14+16	get R2 source
00001638	E612 0039 F058			1017+	VCVD	V1, R2, 159, 3	test instruction
0000163E	E710 8F10 000E		00001110	1018+	VST	V1, V1OUTPUT	save
00001644	B98D 0020			1019+	EPSW	R2, R0	extract psw
00001648	5020 8EE8		000010E8	1020+ 1021+	ST BR	R2, CCPSW R11	to save CC return
0000164C	07FB			1022+RE14	DC	OF	
00001650				1023+	DROP	R5	
00001650	00000000 00000000			1024	DC	XL16' 00000000000000002147483647F'	V1 result
00001658	00000214 7483647F			1025	DC	FD' 2147483647'	R2 source
00001660	00000000 7FFFFFFF			1026			
00001668		00001668		1027	VRR_K	VCVD, 159, 3, 0	INT_MIN
00001668				1028+	DS	OFD	
00001668	00001684			1029+	USING	*, R5	base for test data and test routine
0000166C	000F			1030+T15	DC	A(X15)	address of test routine
0000166E	00			1031+	DC	H' 15'	test number
0000166F	9F			1032+	DC	XL1' 00'	
00001670	03			1033+	DC	HL1' 159'	i3
00001671	00			1034+	DC	HL1' 3'	m4
00001672	07			1035+	DC	HL1' 0'	cc
00001673	E5C3E5C4 40404040			1036+	DC	HL1' 7'	cc failed mask
0000167C	00000010			1037+	DC	CL8' VCVD'	instruction name
00001680	000016A8			1038+	DC	A(16)	result length
00001680				1039+RE15	DC	A(RE15)	result address
00001684				1040+*			INSTRUCTION UNDER TEST ROUTINE
00001684	E710 8F48 0006		00001148	1041+X15	DS	OF	
0000168A	E320 5050 0004		000016B8	1042+	VL	V1, V1FUDGE	pollute V1
00001690	E612 0039 F058			1043+	LG	R2, RE15+16	get R2 source
00001690				1044+	VCVD	V1, R2, 159, 3	test instruction

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001696	E710 8F10 000E		00001110	1045+ 1046+	VST EPSW	V1, V1OUTPUT R2, R0	save extract psw
0000169C	B98D 0020			000010E8	1047+ 1048+ 1049+RE15	ST BR DC	R2, CCPSW R11 OF
000016A0	5020 8EE8				1050+	DROP	R5
000016A4	07FB				1051	DC	XL16' 0000000000000000000000002147483648F' V1 result
000016A8					1052	DC	FD' -2147483648'
000016A8	00000000 00000000				1053		R2 source
000016B0	00000214 7483648F				1054 * VCVD	m4= 3 (LB=0, P1=1 , CS=1)	
000016B8	FFFFFFF 80000000				1055 *	i 3= 137 (IOM=1, RDC= 9)	
					1056		
					1057	VRR_K VCVD, 137, 3, 0	
000016C0					1058+	DS OFD	
000016C0		000016C0			1059+	USING *, R5	base for test data and test routine
000016C0	000016DC				1060+T16	DC A(X16)	address of test routine
000016C4	0010				1061+	DC H' 16'	test number
000016C6	00				1062+	DC XL1' 00'	
000016C7	89				1063+	DC HL1' 137'	i 3
000016C8	03				1064+	DC HL1' 3'	m4
000016C9	00				1065+	DC HL1' 0'	cc
000016CA	07				1066+	DC HL1' 7'	cc failed mask
000016CB	E5C3E5C4 40404040				1067+	DC CL8' VCVD'	instruction name
000016D4	00000010				1068+	DC A(16)	result length
000016D8	00001700				1069+REA16	DC A(RE16)	result address
					1070+*		INSTRUCTION UNDER TEST ROUTINE
000016DC					1071+X16	DS OF	
000016DC	E710 8F48 0006		00001148	1072+	VL	V1, V1FUDGE	pollute V1
000016E2	E320 5050 0004		00001710	1073+	LG	R2, RE16+16	get R2 source
000016E8	E612 0038 9058			1074+	VCVD	V1, R2, 137, 3	test instruction
000016EE	E710 8F10 000E		00001110	1075+	VST	V1, V1OUTPUT	save
000016F4	B98D 0020			1076+	EPSW	R2, R0	extract psw
000016F8	5020 8EE8		000010E8	1077+	ST	R2, CCPSW	to save CC
000016FC	07FB			1078+	BR	R11	return
00001700					1079+RE16	DC OF	
00001700					1080+	DROP	R5
00001700	00000000 00000000				1081	DC XL16' 00000000000000000000000000000000F'	V1 result
00001708	00000000 0000000F						
00001710	00000000 00000000				1082	DC FD' 0'	R2 source
					1083		
					1084	VRR_K VCVD, 137, 3, 0	
00001718					1085+	DS OFD	
00001718	00001734		00001718	1086+	USING *, R5		base for test data and test routine
00001718	0011				1087+T17	DC A(X17)	address of test routine
0000171C	00				1088+	DC H' 17'	test number
0000171E	89				1089+	DC XL1' 00'	
0000171F	03				1090+	DC HL1' 137'	i 3
00001720	00				1091+	DC HL1' 3'	m4
00001721	07				1092+	DC HL1' 0'	cc
00001722	E5C3E5C4 40404040				1093+	DC HL1' 7'	cc failed mask
00001723	00000010				1094+	DC CL8' VCVD'	instruction name
0000172C	00001758				1095+	DC A(16)	result length
00001730					1096+REA17	DC A(RE17)	result address
00001734					1097+*		INSTRUCTION UNDER TEST ROUTINE
					1098+X17	DS OF	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001734	E710 8F48 0006		00001148	1099+	VL	V1, V1FUDGE	
0000173A	E320 5050 0004		00001768	1100+	LG	R2, RE17+16	pollute V1 get R2 source
00001740	E612 0038 9058			1101+	VCVD	V1, R2, 137, 3	test instruction
00001746	E710 8F10 000E		00001110	1102+	VST	V1, V1OUTPUT	save
0000174C	B98D 0020			1103+	EPSW	R2, R0	extract psw
00001750	5020 8EE8		000010E8	1104+	ST	R2, CCPSW	to save CC
00001754	07FB			1105+	BR	R11	return
00001758				1106+RE17	DC	OF	
00001758				1107+	DROP	R5	
00001758	00000000 00000000			1108	DC	XL16' 000000000000000000000000000000001F'	V1 result
00001760	00000000 0000001F						
00001768	00000000 00000001			1109	DC	FD' 1'	R2 source
				1110			
				1111	VRR_K	VCVD, 137, 3, 0	
00001770				1112+	DS	OFD	
00001770		00001770		1113+	USING	*, R5	base for test data and test routine
00001770	0000178C			1114+T18	DC	A(X18)	address of test routine
00001774	0012			1115+	DC	H' 18'	test number
00001776	00			1116+	DC	XL1' 00'	
00001777	89			1117+	DC	HL1' 137'	i 3
00001778	03			1118+	DC	HL1' 3'	m4
00001779	00			1119+	DC	HL1' 0'	cc
0000177A	07			1120+	DC	HL1' 7'	cc failed mask
0000177B	E5C3E5C4 40404040			1121+	DC	CL8' VCVD'	instruction name
00001784	00000010			1122+	DC	A(16)	result length
00001788	000017B0			1123+REA18	DC	A(RE18)	result address
				1124+*			INSTRUCTION UNDER TEST ROUTINE
0000178C				1125+X18	DS	OF	
0000178C	E710 8F48 0006		00001148	1126+	VL	V1, V1FUDGE	pollute V1
00001792	E320 5050 0004		000017C0	1127+	LG	R2, RE18+16	get R2 source
00001798	E612 0038 9058			1128+	VCVD	V1, R2, 137, 3	test instruction
0000179E	E710 8F10 000E		00001110	1129+	VST	V1, V1OUTPUT	save
000017A4	B98D 0020			1130+	EPSW	R2, R0	extract psw
000017A8	5020 8EE8		000010E8	1131+	ST	R2, CCPSW	to save CC
000017AC	07FB			1132+	BR	R11	return
000017B0				1133+RE18	DC	OF	
000017B0				1134+	DROP	R5	
000017B0	00000000 00000000			1135	DC	XL16' 000000000000000000000000000000001F'	V1 result
000017B8	00000000 0000001F						
000017C0	FFFFFF FFFFFFFF			1136	DC	FD' - 1'	R2 source
				1137			
				1138	VRR_K	VCVD, 137, 3, 3	INT_MAX
000017C8				1139+	DS	OFD	
000017C8		000017C8		1140+	USING	*, R5	base for test data and test routine
000017C8	000017E4			1141+T19	DC	A(X19)	address of test routine
000017CC	0013			1142+	DC	H' 19'	test number
000017CE	00			1143+	DC	XL1' 00'	
000017CF	89			1144+	DC	HL1' 137'	i 3
000017D0	03			1145+	DC	HL1' 3'	m4
000017D1	03			1146+	DC	HL1' 3'	cc
000017D2	0E			1147+	DC	HL1' 14'	cc failed mask
000017D3	E5C3E5C4 40404040			1148+	DC	CL8' VCVD'	instruction name
000017DC	00000010			1149+	DC	A(16)	result length
000017E0	00001808			1150+REA19	DC	A(RE19)	result address
				1151+*			INSTRUCTION UNDER TEST ROUTINE
000017E4				1152+X19	DS	OF	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000017E4	E710 8F48 0006		00001148	1153+ VL	V1, V1FUDGE	pollute V1	
000017EA	E320 5050 0004		00001818	1154+ LG	R2, RE19+16	get R2 source	
000017F0	E612 0038 9058			1155+ VCVD	V1, R2, 137, 3	test instruction	
000017F6	E710 8F10 000E		00001110	1156+ VST	V1, V1OUTPUT	save	
000017FC	B98D 0020			1157+ EPSW	R2, R0	extract psw	
00001800	5020 8EE8		000010E8	1158+ ST	R2, CCPSW	to save CC	
00001804	07FB			1159+ BR	R11	return	
00001808				1160+RE19 DC	OF		
00001808				1161+ DROP	R5		
00001808	00000000 00000000			1162 DC	XL16' 00000000000000000000000000000000147483647F'	V1 result	
00001810	00000014 7483647F						
00001818	00000000 7FFFFFFF			1163 DC	FD' 2147483647'	R2 source	
				1164			
				1165 VRR_K	VCVD, 137, 3, 3	INT_MIN	
00001820				1166+ DS	OFD		
00001820		00001820		1167+ USING	* , R5	base for test data and test routine	
00001820	0000183C			1168+T20 DC	A(X20)	address of test routine	
00001824	0014			1169+ DC	H' 20'	test number	
00001826	00			1170+ DC	XL1' 00'		
00001827	89			1171+ DC	HL1' 137'	i3	
00001828	03			1172+ DC	HL1' 3'	m4	
00001829	03			1173+ DC	HL1' 3'	cc	
0000182A	OE			1174+ DC	HL1' 14'	cc failed mask	
0000182B	E5C3E5C4 40404040			1175+ DC	CL8' VCVD'	instruction name	
00001834	00000010			1176+ DC	A(16)	result length	
00001838	00001860			1177+REA20 DC	A(RE20)	result address	
				1178+*		INSTRUCTION UNDER TEST ROUTINE	
0000183C				1179+X20 DS	OF		
0000183C	E710 8F48 0006		00001148	1180+ VL	V1, V1FUDGE	pollute V1	
00001842	E320 5050 0004		00001870	1181+ LG	R2, RE20+16	get R2 source	
00001848	E612 0038 9058			1182+ VCVD	V1, R2, 137, 3	test instruction	
0000184E	E710 8F10 000E		00001110	1183+ VST	V1, V1OUTPUT	save	
00001854	B98D 0020			1184+ EPSW	R2, R0	extract psw	
00001858	5020 8EE8		000010E8	1185+ ST	R2, CCPSW	to save CC	
0000185C	07FB			1186+ BR	R11	return	
00001860				1187+RE20 DC	OF		
00001860				1188+ DROP	R5		
00001860	00000000 00000000			1189 DC	XL16' 00000000000000000000000000000000147483648F'	V1 result	
00001868	00000014 7483648F						
00001870	FFFFFFFFFF 80000000			1190 DC	FD' - 2147483648'		
				1191			
				1192 *-----			
				1193 * VCVD	m4= 9 (LB=1, P1=0 , CS=1)		
				1194 *	i3= 159 (IOM=1, RDC=31)		
				1195			
00001878				1196 VRR_K	VCVD, 159, 9, 0		
00001878		00001878		1197+ DS	OFD		
00001878	00001894			1198+ USING	* , R5	base for test data and test routine	
00001878	0015			1199+T21 DC	A(X21)	address of test routine	
0000187C	0015			1200+ DC	H' 21'	test number	
0000187E	00			1201+ DC	XL1' 00'		
0000187F	9F			1202+ DC	HL1' 159'	i3	
00001880	09			1203+ DC	HL1' 9'	m4	
00001881	00			1204+ DC	HL1' 0'	cc	
00001882	07			1205+ DC	HL1' 7'	cc failed mask	
00001883	E5C3E5C4 40404040			1206+ DC	CL8' VCVD'	instruction name	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
0000188C	00000010			1207+ DC A(16)	result length	
00001890	000018B8			1208+REA21 DC A(REA21)	result address	
00001894				1209+*	INSTRUCTION UNDER TEST ROUTINE	
00001894	E710 8F48 0006	00001148	000018C8	1210+X21 DS OF	pollute V1	
0000189A	E320 5050 0004	00001148	00001110	1211+ VL V1, V1FUDGE	get R2 source	
000018A0	E612 0099 F058	00001148	00001110	1212+ LG R2, RE21+16	test instruction	
000018A6	E710 8F10 000E	00001148	00001110	1213+ VCVD V1, R2, 159, 9	save	
000018AC	B98D 0020	00001148	00001110	1214+ VST V1, V1OUTPUT	extract psw	
000018B0	5020 8EE8	000010E8	00001148	1215+ EPSW R2, R0	to save CC	
000018B4	07FB	000010E8	00001148	1216+ ST R2, CCPSW	return	
000018B8				1217+ BR R11		
000018B8				1218+RE21 DC OF		
000018B8				1219+ DROP R5		
000018B8	00000000 00000000			1220 DC XL16' 00000000000000000000000000000000C'	V1 result	
000018C0	00000000 0000000C			1221 DC FD' 0'		
000018C8	00000000 00000000			1222 DC	R2 source	
000018D0		000018D0		1223 VRR_K VCVD, 159, 9, 0		
000018D0		000018D0		1224+ DS OFD	base for test data and test routine	
000018D0	000018EC			1225+ USING *, R5	address of test routine	
000018D4	0016			1226+T22 DC A(X22)	test number	
000018D6	00			1227+ DC H' 22'		
000018D7	9F			1228+ DC XL1' 00'		
000018D8	09			1229+ DC HL1' 159'	i3	
000018D9	00			1230+ DC HL1' 9'	m4	
000018DA	07			1231+ DC HL1' 0'	cc	
000018DB	E5C3E5C4 40404040			1232+ DC HL1' 7'	cc failed mask	
000018E4	00000010			1233+ DC CL8' VCVD'	instruction name	
000018E8	00001910			1234+ DC A(16)	result length	
000018EC				1235+REA22 DC A(REA22)	result address	
000018EC	E710 8F48 0006	00001148	00001920	1236+* 1237+X22 DS OF	INSTRUCTION UNDER TEST ROUTINE	
000018F2	E320 5050 0004	00001148	00001920	1238+ VL V1, V1FUDGE	pollute V1	
000018F8	E612 0099 F058	00001148	00001920	1239+ LG R2, RE22+16	get R2 source	
000018FE	E710 8F10 000E	00001148	00001920	1240+ VCVD V1, R2, 159, 9	test instruction	
00001904	B98D 0020	00001148	00001920	1241+ VST V1, V1OUTPUT	save	
00001908	5020 8EE8	000010E8	00001920	1242+ EPSW R2, R0	extract psw	
0000190C	07FB	000010E8	00001920	1243+ ST R2, CCPSW	to save CC	
00001910				1244+ BR R11	return	
00001910				1245+RE22 DC OF		
00001910				1246+ DROP R5		
00001910	00000000 00000000			1247 DC XL16' 00000000000000000000000000000001C'	V1 result	
00001918	00000000 0000001C			1248 DC FD' 1'		
00001920	00000000 00000001			1249 DC	R2 source	
00001928		00001928		1250 VRR_K VCVD, 159, 9, 0	UINT_MAX	
00001928	00001944	00001928	00001928	1251+ DS OFD	base for test data and test routine	
0000192C	0017	00001944	00001928	1252+ USING *, R5	address of test routine	
0000192E	00	00001944	00001928	1253+T23 DC A(X23)	test number	
0000192F	9F	00001944	00001928	1254+ DC H' 23'		
00001930	09	00001944	00001928	1255+ DC XL1' 00'		
00001931	00	00001944	00001928	1256+ DC HL1' 159'	i3	
00001932	07	00001944	00001928	1257+ DC HL1' 9'	m4	
00001933	E5C3E5C4 40404040	00001944	00001928	1258+ DC HL1' 0'	cc	
				1259+ DC HL1' 7'	cc failed mask	
				1260+ DC CL8' VCVD'	instruction name	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
0000193C	00000010			1261+ DC A(16)	result length	
00001940	00001968			1262+REA23 DC A(REA23)	result address	
				1263+*	INSTRUCTION UNDER TEST ROUTINE	
00001944				1264+X23 DS OF		
00001944	E710 8F48 0006	00001148	00001978	1265+ VL V1, V1FUDGE	pollute V1	
0000194A	E320 5050 0004			1266+ LG R2, RE23+16	get R2 source	
00001950	E612 0099 F058			1267+ VCVD V1, R2, 159, 9	test instruction	
00001956	E710 8F10 000E	00001110		1268+ VST V1, V1OUTPUT	save	
0000195C	B98D 0020			1269+ EPSW R2, R0	extract psw	
00001960	5020 8EE8	000010E8		1270+ ST R2, CCPSW	to save CC	
00001964	07FB			1271+ BR R11	return	
00001968				1272+REA23 DC OF		
00001968				1273+ DROP R5		
00001968	00000000 00000000			1274 DC XL16' 0000000000000000000000004294967295C'	V1 result	
00001970	00000429 4967295C					
00001978	FFFFFFFFFF FFFFFFFF			1275 DC FD' -1'	R2 source	
				1276		
				1277 VRR_K VCVD, 159, 9, 0	INT_MAX	
00001980		00001980		1278+ DS OFD		
00001980				1279+ USING *, R5	base for test data and test routine	
00001980	0000199C			1280+T24 DC A(X24)	address of test routine	
00001984	0018			1281+ DC H' 24'	test number	
00001986	00			1282+ DC XL1' 00'		
00001987	9F			1283+ DC HL1' 159'	i3	
00001988	09			1284+ DC HL1' 9'	m4	
00001989	00			1285+ DC HL1' 0'	cc	
0000198A	07			1286+ DC HL1' 7'	cc failed mask	
0000198B	E5C3E5C4 40404040			1287+ DC CL8' VCVD'	instruction name	
00001994	00000010			1288+ DC A(16)	result length	
00001998	000019C0			1289+REA24 DC A(REA24)	result address	
				1290+*	INSTRUCTION UNDER TEST ROUTINE	
0000199C				1291+X24 DS OF		
0000199C	E710 8F48 0006	00001148	000019D0	1292+ VL V1, V1FUDGE	pollute V1	
000019A2	E320 5050 0004			1293+ LG R2, RE24+16	get R2 source	
000019A8	E612 0099 F058			1294+ VCVD V1, R2, 159, 9	test instruction	
000019AE	E710 8F10 000E	00001110		1295+ VST V1, V1OUTPUT	save	
000019B4	B98D 0020			1296+ EPSW R2, R0	extract psw	
000019B8	5020 8EE8	000010E8		1297+ ST R2, CCPSW	to save CC	
000019BC	07FB			1298+ BR R11	return	
000019C0				1299+REA24 DC OF		
000019C0				1300+ DROP R5		
000019C0	00000000 00000000			1301 DC XL16' 0000000000000000000000002147483647C'	V1 result	
000019C8	00000214 7483647C					
000019D0	00000000 7FFFFFFF			1302 DC FD' 2147483647'	R2 source	
				1303		
				1304 VRR_K VCVD, 159, 9, 0	INT_MIN	
000019D8		000019D8		1305+ DS OFD		
000019D8				1306+ USING *, R5	base for test data and test routine	
000019D8	000019F4			1307+T25 DC A(X25)	address of test routine	
000019DC	0019			1308+ DC H' 25'	test number	
000019DE	00			1309+ DC XL1' 00'		
000019DF	9F			1310+ DC HL1' 159'	i3	
000019E0	09			1311+ DC HL1' 9'	m4	
000019E1	00			1312+ DC HL1' 0'	cc	
000019E2	07			1313+ DC HL1' 7'	cc failed mask	
000019E3	E5C3E5C4 40404040			1314+ DC CL8' VCVD'	instruction name	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001A91	00			1369+	DC	HL1' 0'
00001A92	07			1370+	DC	HL1' 7'
00001A93	E5C3E5C4 40404040			1371+	DC	CL8' VCVD'
00001A9C	00000010			1372+	DC	A(16)
00001AA0	00001AC8			1373+REA27	DC	A(RE27)
				1374+*		
00001AA4				1375+X27	DS	OF
00001AA4	E710 8F48 0006	00001148	1376+	VL	V1, V1FUDGE	pollute V1
00001AAA	E320 5050 0004	00001AD8	1377+	LG	R2, RE27+16	get R2 source
00001AB0	E612 0098 9058		1378+	VCVD	V1, R2, 137, 9	test instruction
00001AB6	E710 8F10 000E	00001110	1379+	VST	V1, V1OUTPUT	save
00001ABC	B98D 0020		1380+	EPSW	R2, R0	extract psw
00001AC0	5020 8EE8	000010E8	1381+	ST	R2, CCPSW	to save CC
00001AC4	07FB		1382+	BR	R11	return
00001AC8			1383+RE27	DC	OF	
00001AC8			1384+	DROP	R5	
00001AC8	00000000 00000000		1385	DC	XL16' 000000000000000000000000000000001C'	V1 result
00001AD0	00000000 0000001C		1386	DC	FD' 1'	
00001AD8	00000000 00000001		1387			R2 source
			1388	VRR_K	VCVD, 137, 9, 3	UINT_MAX
00001AE0			1389+	DS	OFD	
00001AE0		00001AE0	1390+	USING	*, R5	base for test data and test routine
00001AE0	00001AFC		1391+T28	DC	A(X28)	address of test routine
00001AE4	001C		1392+	DC	H' 28'	test number
00001AE6	00		1393+	DC	XL1' 00'	
00001AE7	89		1394+	DC	HL1' 137'	i 3
00001AE8	09		1395+	DC	HL1' 9'	m4
00001AE9	03		1396+	DC	HL1' 3'	cc
00001AEA	OE		1397+	DC	HL1' 14'	cc failed mask
00001AEB	E5C3E5C4 40404040		1398+	DC	CL8' VCVD'	instruction name
00001AF4	00000010		1399+	DC	A(16)	result length
00001AF8	00001B20		1400+REA28	DC	A(RE28)	result address
			1401+*			INSTRUCTION UNDER TEST ROUTINE
00001AFC			1402+X28	DS	OF	
00001AFC	E710 8F48 0006	00001148	1403+	VL	V1, V1FUDGE	pollute V1
00001B02	E320 5050 0004	00001B30	1404+	LG	R2, RE28+16	get R2 source
00001B08	E612 0098 9058		1405+	VCVD	V1, R2, 137, 9	test instruction
00001B0E	E710 8F10 000E	00001110	1406+	VST	V1, V1OUTPUT	save
00001B14	B98D 0020		1407+	EPSW	R2, R0	extract psw
00001B18	5020 8EE8	000010E8	1408+	ST	R2, CCPSW	to save CC
00001B1C	07FB		1409+	BR	R11	return
00001B20			1410+RE28	DC	OF	
00001B20			1411+	DROP	R5	
00001B20	00000000 00000000		1412	DC	XL16' 00000000000000000000000000000000294967295C'	V1 result
00001B28	00000029 4967295C		1413	DC	FD' - 1'	
00001B30	FFFFFFFFFF FFFFFFFF					R2 source
			1414			
00001B38			1415	VRR_K	VCVD, 137, 9, 3	INT_MAX
00001B38			1416+	DS	OFD	
00001B38	00001B54	00001B38	1417+	USING	*, R5	base for test data and test routine
00001B38	001D		1418+T29	DC	A(X29)	address of test routine
00001B3C	001D		1419+	DC	H' 29'	test number
00001B3E	00		1420+	DC	XL1' 00'	
00001B3F	89		1421+	DC	HL1' 137'	i 3
00001B40	09		1422+	DC	HL1' 9'	m4

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001B41	03			1423+ DC HL1' 3'	cc	
00001B42	0E			1424+ DC HL1' 14'	cc failed mask	
00001B43	E5C3E5C4 40404040			1425+ DC CL8' VCVD'	instruction name	
00001B4C	00000010			1426+ DC A(16)	result length	
00001B50	00001B78			1427+REA29 DC A(RE29)	result address	
00001B54				1428+*	INSTRUCTION UNDER TEST ROUTINE	
00001B54	E710 8F48 0006	00001148	1430+ VL V1, V1FUDGE		pollute V1	
00001B5A	E320 5050 0004	00001B88	1431+ LG R2, RE29+16		get R2 source	
00001B60	E612 0098 9058		1432+ VCVD V1, R2, 137, 9		test instruction	
00001B66	E710 8F10 000E	00001110	1433+ VST V1, V1OUTPUT		save	
00001B6C	B98D 0020		1434+ EPSW R2, R0		extract psw	
00001B70	5020 8EE8	000010E8	1435+ ST R2, CCPSW		to save CC	
00001B74	07FB		1436+ BR R11		return	
00001B78			1437+REA29 DC OF			
00001B78			1438+ DROP R5			
00001B78	00000000 00000000		1439 DC XL16' 000000000000000000000000147483647C'	V1 result		
00001B80	00000014 7483647C					
00001B88	00000000 7FFFFFFF		1440 DC FD' 2147483647'	R2 source		
			1441			
00001B90		00001B90	1442 VRR_K VCVD, 137, 9, 3		INT_MIN	
00001B90			1443+ DS OFD			
00001B90			1444+ USING *, R5		base for test data and test routine	
00001B90	00001BAC		1445+T30 DC A(X30)		address of test routine	
00001B94	001E		1446+ DC H' 30'		test number	
00001B96	00		1447+ DC XL1' 00'			
00001B97	89		1448+ DC HL1' 137'	i3		
00001B98	09		1449+ DC HL1' 9'	m4		
00001B99	03		1450+ DC HL1' 3'	cc		
00001B9A	0E		1451+ DC HL1' 14'	cc failed mask		
00001B9B	E5C3E5C4 40404040		1452+ DC CL8' VCVD'	instruction name		
00001BA4	00000010		1453+ DC A(16)	result length		
00001BA8	00001BD0		1454+REA30 DC A(RE30)	result address		
00001BAC			1455+*	INSTRUCTION UNDER TEST ROUTINE		
00001BAC			1456+X30 DS OF			
00001BAC	E710 8F48 0006	00001148	1457+ VL V1, V1FUDGE	pollute V1		
00001BB2	E320 5050 0004	00001BE0	1458+ LG R2, RE30+16	get R2 source		
00001BB8	E612 0098 9058		1459+ VCVD V1, R2, 137, 9	test instruction		
00001BBE	E710 8F10 000E	00001110	1460+ VST V1, V1OUTPUT	save		
00001BC4	B98D 0020		1461+ EPSW R2, R0	extract psw		
00001BC8	5020 8EE8	000010E8	1462+ ST R2, CCPSW	to save CC		
00001BCC	07FB		1463+ BR R11	return		
00001BD0			1464+REA30 DC OF			
00001BD0			1465+ DROP R5			
00001BD0	00000000 00000000		1466 DC XL16' 000000000000000000000000147483648C'	V1 result		
00001BD8	00000014 7483648C					
00001BE0	FFFFFFFFFF 80000000		1467 DC FD' - 2147483648'			
			1468			
			1469 *-----			
			1470 * VCVD	m4= 11 (LB=1, P1=1 , CS=1)		
			1471 *-----	i3= 159 (IOM=1, RDC=31)		
			1472			
00001BE8		00001BE8	1473 VRR_K VCVD, 159, 11, 0			
00001BE8			1474+ DS OFD			
00001BE8	00001C04		1475+ USING *, R5		base for test data and test routine	
			1476+T31 DC A(X31)		address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001BEC	001F			1477+ DC H' 31'	test number	
00001BEE	00			1478+ DC XL1' 00'		
00001BEF	9F			1479+ DC HL1' 159'	i3	
00001BF0	0B			1480+ DC HL1' 11'	m4	
00001BF1	00			1481+ DC HL1' 0'	cc	
00001BF2	07			1482+ DC HL1' 7'	cc failed mask	
00001BF3	E5C3E5C4 40404040			1483+ DC CL8' VCVD'	instruction name	
00001BFC	00000010			1484+ DC A(16)	result length	
00001C00	00001C28			1485+REA31 DC A(RE31)	result address	
				1486+*	INSTRUCTION UNDER TEST ROUTINE	
00001C04				1487+X31 DS OF		
00001C04	E710 8F48 0006	00001148		1488+ VL V1, V1FUDGE	pollute V1	
00001C0A	E320 5050 0004	00001C38		1489+ LG R2, RE31+16	get R2 source	
00001C10	E612 00B9 F058			1490+ VCVD V1, R2, 159, 11	test instruction	
00001C16	E710 8F10 000E	00001110		1491+ VST V1, V1OUTPUT	save	
00001C1C	B98D 0020			1492+ EPSW R2, R0	extract psw	
00001C20	5020 8EE8	000010E8		1493+ ST R2, CCPSW	to save CC	
00001C24	07FB			1494+ BR R11	return	
00001C28				1495+RE31 DC OF		
00001C28				1496+ DROP R5		
00001C28	00000000 00000000			1497 DC XL16' 00000000000000000000000000000000F'	V1 result	
00001C30	00000000 0000000F					
00001C38	00000000 00000000			1498 DC FD' 0'	R2 source	
				1499		
00001C40		00001C40		1500 VRR_K VCVD, 159, 11, 0		
00001C40				1501+ DS OFD		
00001C40	00001C5C			1502+ USING *, R5	base for test data and test routine	
00001C44	0020			1503+T32 DC A(X32)	address of test routine	
				1504+ DC H' 32'	test number	
00001C46	00			1505+ DC XL1' 00'		
00001C47	9F			1506+ DC HL1' 159'	i3	
00001C48	0B			1507+ DC HL1' 11'	m4	
00001C49	00			1508+ DC HL1' 0'	cc	
00001C4A	07			1509+ DC HL1' 7'	cc failed mask	
00001C4B	E5C3E5C4 40404040			1510+ DC CL8' VCVD'	instruction name	
00001C54	00000010			1511+ DC A(16)	result length	
00001C58	00001C80			1512+REA32 DC A(RE32)	result address	
				1513+*	INSTRUCTION UNDER TEST ROUTINE	
00001C5C				1514+X32 DS OF		
00001C5C	E710 8F48 0006	00001148		1515+ VL V1, V1FUDGE	pollute V1	
00001C62	E320 5050 0004	00001C90		1516+ LG R2, RE32+16	get R2 source	
00001C68	E612 00B9 F058			1517+ VCVD V1, R2, 159, 11	test instruction	
00001C6E	E710 8F10 000E	00001110		1518+ VST V1, V1OUTPUT	save	
00001C74	B98D 0020			1519+ EPSW R2, R0	extract psw	
00001C78	5020 8EE8	000010E8		1520+ ST R2, CCPSW	to save CC	
00001C7C	07FB			1521+ BR R11	return	
00001C80				1522+RE32 DC OF		
00001C80	00000000 00000000			1523+ DROP R5		
00001C80	00000000 0000001F			1524 DC XL16' 00000000000000000000000000000001F'	V1 result	
00001C90	00000000 00000001			1525 DC FD' 1'	R2 source	
				1526		
00001C98		00001C98		1527 VRR_K VCVD, 159, 11, 0	UINT_MAX	
00001C98				1528+ DS OFD		
00001C98	00001CB4			1529+ USING *, R5	base for test data and test routine	
				1530+T33 DC A(X33)	address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001C9C	0021			1531+ DC H' 33'	test number	
00001C9E	00			1532+ DC XL1' 00'		
00001C9F	9F			1533+ DC HL1' 159'	i3	
00001CA0	0B			1534+ DC HL1' 11'	m4	
00001CA1	00			1535+ DC HL1' 0'	cc	
00001CA2	07			1536+ DC HL1' 7'	cc failed mask	
00001CA3	E5C3E5C4 40404040			1537+ DC CL8' VCVD'	instruction name	
00001CAC	00000010			1538+ DC A(16)	result length	
00001CB0	00001CD8			1539+REA33 DC A(RE33)	result address	
				1540+*	INSTRUCTION UNDER TEST ROUTINE	
00001CB4				1541+X33 DS OF		
00001CB4	E710 8F48 0006	00001148		1542+ VL V1, V1FUDGE	pollute V1	
00001CBA	E320 5050 0004	00001CE8		1543+ LG R2, RE33+16	get R2 source	
00001CC0	E612 00B9 F058			1544+ VCVD V1, R2, 159, 11	test instruction	
00001CC6	E710 8F10 000E	00001110		1545+ VST V1, V1OUTPUT	save	
00001CCC	B98D 0020			1546+ EPSW R2, R0	extract psw	
00001CDO	5020 8EE8	000010E8		1547+ ST R2, CCPSW	to save CC	
00001CD4	07FB			1548+ BR R11	return	
00001CD8				1549+RE33 DC OF		
00001CD8				1550+ DROP R5		
00001CD8	00000000 00000000			1551 DC XL16' 0000000000000000000000004294967295F'	V1 result	
00001CE0	00000429 4967295F			1552 DC FD' - 1'	R2 source	
00001CE8	FFFFFFF FFFFFFFF			1553	INT_MAX	
00001CF0		00001CF0		1554 VRR_K VCVD, 159, 11, 0		
00001CF0				1555+ DS OFD		
00001CF0	00001DOC			1556+ USING *, R5	base for test data and test routine	
00001CF4	0022			1557+T34 DC A(X34)	address of test routine	
00001CF6	00			1558+ DC H' 34'	test number	
00001CF7	9F			1559+ DC XL1' 00'		
00001CF8	0B			1560+ DC HL1' 159'	i3	
00001CF9	00			1561+ DC HL1' 11'	m4	
00001CFA	07			1562+ DC HL1' 0'	cc	
00001CFB	E5C3E5C4 40404040			1563+ DC HL1' 7'	cc failed mask	
00001D04	00000010			1564+ DC CL8' VCVD'	instruction name	
00001D08	00001D30			1565+ DC A(16)	result length	
				1566+REA34 DC A(RE34)	result address	
				1567+*	INSTRUCTION UNDER TEST ROUTINE	
00001DOC				1568+X34 DS OF		
00001DOC	E710 8F48 0006	00001148		1569+ VL V1, V1FUDGE	pollute V1	
00001D12	E320 5050 0004	00001D40		1570+ LG R2, RE34+16	get R2 source	
00001D18	E612 00B9 F058			1571+ VCVD V1, R2, 159, 11	test instruction	
00001D1E	E710 8F10 000E	00001110		1572+ VST V1, V1OUTPUT	save	
00001D24	B98D 0020			1573+ EPSW R2, R0	extract psw	
00001D28	5020 8EE8	000010E8		1574+ ST R2, CCPSW	to save CC	
00001D2C	07FB			1575+ BR R11	return	
00001D30				1576+RE34 DC OF		
00001D30	00000000 00000000			1577+ DROP R5		
00001D30	00000214 7483647F			1578 DC XL16' 0000000000000000000000002147483647F'	V1 result	
00001D38				1579 DC FD' 2147483647'	R2 source	
00001D40	00000000 7FFFFFFF			1580	INT_MIN	
00001D48		00001D48		1581 VRR_K VCVD, 159, 11, 0		
00001D48				1582+ DS OFD		
00001D48	00001D64			1583+ USING *, R5	base for test data and test routine	
				1584+T35 DC A(X35)	address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001DF8				1639+ DS OFD		
00001DF8		00001DF8		1640+ USING *, R5	base for test data and test routine	
00001DF8	00001E14			1641+T37 DC A(X37)	address of test routine	
00001DFC	0025			1642+ DC H'37'	test number	
00001DFE	00			1643+ DC XL1'00'		
00001DFF	89			1644+ DC HL1'137'	i3	
00001E00	OB			1645+ DC HL1'11'	m4	
00001E01	00			1646+ DC HL1'0'	cc	
00001E02	07			1647+ DC HL1'7'	cc failed mask	
00001E03	E5C3E5C4 40404040			1648+ DC CL8'VCVD'	instruction name	
00001E0C	00000010			1649+ DC A(16)	result length	
00001E10	00001E38			1650+REA37 DC A(RE37)	result address	
				1651+*	INSTRUCTION UNDER TEST ROUTINE	
00001E14				1652+X37 DS OF		
00001E14	E710 8F48 0006	00001148	1653+ VL V1, V1FUDGE		pollute V1	
00001E1A	E320 5050 0004	00001E48	1654+ LG R2, RE37+16		get R2 source	
00001E20	E612 00B8 9058		1655+ VCVD V1, R2, 137, 11		test instruction	
00001E26	E710 8F10 000E	00001110	1656+ VST V1, V1OUTPUT		save	
00001E2C	B98D 0020		1657+ EPSW R2, R0		extract psw	
00001E30	5020 8EE8	000010E8	1658+ ST R2, CCPSW		to save CC	
00001E34	07FB		1659+ BR R11		return	
00001E38			1660+RE37 DC OF			
00001E38			1661+ DROP R5			
00001E38	00000000 00000000		1662 DC	XL16' 00000000000000000000000000000001F'	V1 result	
00001E40	00000000 0000001F		1663 DC	FD'1'	R2 source	
00001E48	00000000 00000001		1664			
			1665 VRR_K VCVD, 137, 11, 3		UINT_MAX	
			1666+ DS OFD			
00001E50		00001E50	1667+ USING *, R5		base for test data and test routine	
00001E50	00001E6C		1668+T38 DC A(X38)		address of test routine	
00001E54	0026		1669+ DC H'38'		test number	
00001E56	00		1670+ DC XL1'00'			
00001E57	89		1671+ DC HL1'137'		i3	
00001E58	OB		1672+ DC HL1'11'		m4	
00001E59	03		1673+ DC HL1'3'		cc	
00001E5A	0E		1674+ DC HL1'14'		cc failed mask	
00001E5B	E5C3E5C4 40404040		1675+ DC CL8'VCVD'		instruction name	
00001E64	00000010		1676+ DC A(16)		result length	
00001E68	00001E90		1677+REA38 DC A(RE38)		result address	
			1678+*	INSTRUCTION UNDER TEST ROUTINE		
00001E6C			1679+X38 DS OF			
00001E6C	E710 8F48 0006	00001148	1680+ VL V1, V1FUDGE		pollute V1	
00001E72	E320 5050 0004	00001EA0	1681+ LG R2, RE38+16		get R2 source	
00001E78	E612 00B8 9058		1682+ VCVD V1, R2, 137, 11		test instruction	
00001E7E	E710 8F10 000E	00001110	1683+ VST V1, V1OUTPUT		save	
00001E84	B98D 0020		1684+ EPSW R2, R0		extract psw	
00001E88	5020 8EE8	000010E8	1685+ ST R2, CCPSW		to save CC	
00001E8C	07FB		1686+ BR R11		return	
00001E90			1687+RE38 DC OF			
00001E90	00000000 00000000		1688+ DROP R5			
00001E98	00000029 4967295F		1689 DC	XL16' 0000000000000000000000000000000294967295F'	V1 result	
00001EA0	FFFFFFFFFF FFFFFFFF		1690 DC	FD'-1'	R2 source	
			1691			
			1692 VRR_K VCVD, 137, 11, 3		INT_MAX	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001EA8				1693+ DS OFD		
00001EA8		00001EA8		1694+ USING *, R5	base for test data and test routine	
00001EA8	00001EC4			1695+T39 DC A(X39)	address of test routine	
00001EAC	0027			1696+ DC H'39'	test number	
00001EAE	00			1697+ DC XL1'00'		
00001EAF	89			1698+ DC HL1'137'	i3	
00001EB0	OB			1699+ DC HL1'11'	m4	
00001EB1	03			1700+ DC HL1'3'	cc	
00001EB2	OE			1701+ DC HL1'14'	cc failed mask	
00001EB3	E5C3E5C4 40404040			1702+ DC CL8'VCVD'	instruction name	
00001EBC	00000010			1703+ DC A(16)	result length	
00001EC0	00001EE8			1704+REA39 DC A(REA39)	result address	
				1705+*	INSTRUCTION UNDER TEST ROUTINE	
00001EC4				1706+X39 DS OF		
00001EC4	E710 8F48 0006	00001148	1707+	VL V1,V1FUDGE	pollute V1	
00001ECA	E320 5050 0004	00001EF8	1708+	LG R2,RE39+16	get R2 source	
00001ED0	E612 00B8 9058		1709+	VCVD V1,R2,137,11	test instruction	
00001ED6	E710 8F10 000E	00001110	1710+	VST V1,V1OUTPUT	save	
00001EDC	B98D 0020		1711+	EPSW R2,R0	extract psw	
00001EE0	5020 8EE8	000010E8	1712+	ST R2,CCPSW	to save CC	
00001EE4	07FB		1713+ BR	R11	return	
00001EE8			1714+REA39 DC	OF		
00001EE8			1715+ DROP	R5		
00001EE8	00000000 00000000		1716	DC XL16' 000000000000000000000000147483647F'	V1 result	
00001EF0	00000014 7483647F		1717	DC FD' 2147483647'	R2 source	
00001EF8	00000000 7FFFFFFF		1718			
			1719 VRR_K	VCVD, 137, 11, 3	INT_MIN	
00001F00		00001F00	1720+ DS	OFD		
00001F00			1721+ USING	*, R5	base for test data and test routine	
00001F00	00001F1C		1722+T40 DC	A(X40)	address of test routine	
00001F04	0028		1723+ DC	H'40'	test number	
00001F06	00		1724+ DC	XL1'00'		
00001F07	89		1725+ DC	HL1'137'	i3	
00001F08	OB		1726+ DC	HL1'11'	m4	
00001F09	03		1727+ DC	HL1'3'	cc	
00001F0A	OE		1728+ DC	HL1'14'	cc failed mask	
00001F0B	E5C3E5C4 40404040		1729+ DC	CL8'VCVD'	instruction name	
00001F14	00000010		1730+ DC	A(16)	result length	
00001F18	00001F40		1731+REA40 DC	A(REA40)	result address	
			1732+*		INSTRUCTION UNDER TEST ROUTINE	
00001F1C			1733+X40 DS	OF		
00001F1C	E710 8F48 0006	00001148	1734+ VL	V1,V1FUDGE	pollute V1	
00001F22	E320 5050 0004	00001F50	1735+ LG	R2,RE40+16	get R2 source	
00001F28	E612 00B8 9058		1736+ VCVD	V1,R2,137,11	test instruction	
00001F2E	E710 8F10 000E	00001110	1737+ VST	V1,V1OUTPUT	save	
00001F34	B98D 0020		1738+ EPSW	R2,R0	extract psw	
00001F38	5020 8EE8	000010E8	1739+ ST	R2,CCPSW	to save CC	
00001F3C	07FB		1740+ BR	R11	return	
00001F40			1741+REA40 DC	OF		
00001F40	00000000 00000000		1742+ DROP	R5		
00001F48	00000014 7483648F		1743 DC	XL16' 000000000000000000000000147483648F'	V1 result	
00001F50	FFFFFFFFFF 80000000		1744 DC	FD' -2147483648'		
			1745			
			1746			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				1747 *-----	
				1748 * VCVDG - VECTOR CONVERT TO DECIMAL (64)	
				1749 *-----	
				1750 * VCVDG simple	m4= 1 (LB=0, P1=0 , CS=1)
				1751 *	m4= 3 (LB=0, P1=1 , CS=1)
				1752 *	m4= 9 (LB=1, P1=0 , CS=1)
				1753 *	m4= 11 (LB=1, P1=1 , CS=1)
				1754 *	
				1755 *	i3= 137 (IOM=1, RDC= 9)
				1756 *	i3= 159 (IOM=1, RDC=31)
				1757 *	
				1758 * VCVDG	m4= 1 (LB=0, P1=0 , CS=1)
				1759 *	i3= 159 (IOM=1, RDC=31)
				1760	
00001F58				1761 VRR_K VCVDG, 159, 1, 0	
00001F58		00001F58		1762+ DS OFD	
00001F58	00001F74			1763+ USING *, R5	base for test data and test routine
00001F5C	0029			1764+T41 DC A(X41)	address of test routine
00001F5E	00			1765+ DC H' 41'	test number
00001F5F	9F			1766+ DC XL1' 00'	
00001F60	01			1767+ DC HL1' 159'	i3
00001F61	00			1768+ DC HL1' 1'	m4
00001F62	07			1769+ DC HL1' 0'	cc
00001F63	E5C3E5C4 C7404040			1770+ DC HL1' 7'	cc failed mask
00001F6C	00000010			1771+ DC CL8' VCVDG'	instruction name
00001F70	00001F98			1772+ DC A(16)	result length
				1773+REA41 DC A(REA41)	result address
				1774+*	INSTRUCTION UNDER TEST ROUTINE
00001F74				1775+X41 DS OF	
00001F74	E710 8F48 0006	00001148		1776+ VL V1, V1FUDGE	pollute V1
00001F7A	E320 5050 0004	00001FA8		1777+ LG R2, RE41+16	get R2 source
00001F80	E612 0019 F05A			1778+ VCVDG V1, R2, 159, 1	test instruction
00001F86	E710 8F10 000E	00001110		1779+ VST V1, V1OUTPUT	save
00001F8C	B98D 0020			1780+ EPSW R2, R0	extract psw
00001F90	5020 8EE8	000010E8		1781+ ST R2, CCPSW	to save CC
00001F94	07FB			1782+ BR R11	return
00001F98				1783+REA41 DC OF	
00001F98				1784+ DROP R5	
00001F98	00000000 00000000			1785 DC XL16' 00000000000000000000000000000000C'	V1 result
00001FA0	00000000 0000000C				
00001FA8	00000000 00000000			1786 DC FD' 0'	R2 source
				1787	
00001FB0				1788 VRR_K VCVDG, 159, 1, 0	
00001FB0		00001FB0		1789+ DS OFD	
00001FB0	00001FCC			1790+ USING *, R5	base for test data and test routine
00001FB0	002A			1791+T42 DC A(X42)	address of test routine
00001FB4	00			1792+ DC H' 42'	test number
00001FB6	9F			1793+ DC XL1' 00'	
00001FB7	01			1794+ DC HL1' 159'	i3
00001FB8	00			1795+ DC HL1' 1'	m4
00001FB9	07			1796+ DC HL1' 0'	cc
00001FBA	E5C3E5C4 C7404040			1797+ DC CL8' VCVDG'	cc failed mask
00001FC4	00000010			1798+ DC A(16)	instruction name
00001FC8	00001FF0			1799+REA42 DC A(REA42)	result length
				1800+*	result address
				1801+*	INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001FCC				1802+X42	DS OF	
00001FCC	E710 8F48 0006	00001148	1803+	VL V1, V1FUDGE	pollute V1	
00001FD2	E320 5050 0004	00002000	1804+	LG R2, RE42+16	get R2 source	
00001FD8	E612 0019 F05A		1805+	VCVDG V1, R2, 159, 1	test instruction	
00001FDE	E710 8F10 000E	00001110	1806+	VST V1, V1OUTPUT	save	
00001FE4	B98D 0020		1807+	EPSW R2, R0	extract psw	
00001FE8	5020 8EE8	000010E8	1808+	ST R2, CCPSW	to save CC	
00001FEC	07FB		1809+	BR R11	return	
00001FF0			1810+RE42	DC OF		
00001FF0			1811+	DROP R5		
00001FF0	00000000 00000000		1812	DC XL16' 000000000000000000000000000000001C'	V1 result	
00001FF8	00000000 0000001C		1813	DC FD' 1'		
00002000	00000000 00000001		1814		R2 source	
			1815	VRR_K VCVGDG, 159, 1, 0		
00002008			1816+	DS OFD		
00002008		00002008	1817+	USING *, R5	base for test data and test routine	
00002008	00002024		1818+T43	DC A(X43)	address of test routine	
0000200C	002B		1819+	DC H' 43'	test number	
0000200E	00		1820+	DC XL1' 00'		
0000200F	9F		1821+	DC HL1' 159'	i3	
00002010	01		1822+	DC HL1' 1'	m4	
00002011	00		1823+	DC HL1' 0'	cc	
00002012	07		1824+	DC HL1' 7'	cc failed mask	
00002013	E5C3E5C4 C7404040		1825+	DC CL8' VCVGDG'	instruction name	
0000201C	00000010		1826+	DC A(16)	result length	
00002020	00002048		1827+REA43	DC A(RE43)	result address	
			1828+*		INSTRUCTION UNDER TEST ROUTINE	
00002024			1829+X43	DS OF		
00002024	E710 8F48 0006	00001148	1830+	VL V1, V1FUDGE	pollute V1	
0000202A	E320 5050 0004	00002058	1831+	LG R2, RE43+16	get R2 source	
00002030	E612 0019 F05A		1832+	VCVDG V1, R2, 159, 1	test instruction	
00002036	E710 8F10 000E	00001110	1833+	VST V1, V1OUTPUT	save	
0000203C	B98D 0020		1834+	EPSW R2, R0	extract psw	
00002040	5020 8EE8	000010E8	1835+	ST R2, CCPSW	to save CC	
00002044	07FB		1836+	BR R11	return	
00002048			1837+RE43	DC OF		
00002048			1838+	DROP R5		
00002048	00000000 00000000		1839	DC XL16' 000000000000000000000000000000001D'	V1 result	
00002050	00000000 0000001D		1840	DC FD' - 1'		
00002058	FFFFFF FFFFFFFF		1841		R2 source	
			1842	VRR_K VCVGDG, 159, 1, 0	INT_MAX	
00002060			1843+	DS OFD		
00002060		00002060	1844+	USING *, R5	base for test data and test routine	
00002060	0000207C		1845+T44	DC A(X44)	address of test routine	
00002064	002C		1846+	DC H' 44'	test number	
00002066	00		1847+	DC XL1' 00'		
00002067	9F		1848+	DC HL1' 159'	i3	
00002068	01		1849+	DC HL1' 1'	m4	
00002069	00		1850+	DC HL1' 0'	cc	
0000206A	07		1851+	DC HL1' 7'	cc failed mask	
0000206B	E5C3E5C4 C7404040		1852+	DC CL8' VCVGDG'	instruction name	
00002074	00000010		1853+	DC A(16)	result length	
00002078	000020A0		1854+REA44	DC A(RE44)	result address	
			1855+*		INSTRUCTION UNDER TEST ROUTINE	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
0000207C				1856+X44	DS OF	
0000207C	E710 8F48 0006	00001148	1857+	VL V1, V1FUDGE	pollute V1	
00002082	E320 5050 0004	000020B0	1858+	LG R2, RE44+16	get R2 source	
00002088	E612 0019 F05A		1859+	VCVDG V1, R2, 159, 1	test instruction	
0000208E	E710 8F10 000E	00001110	1860+	VST V1, V1OUTPUT	save	
00002094	B98D 0020		1861+	EPSW R2, R0	extract psw	
00002098	5020 8EE8	000010E8	1862+	ST R2, CCPSW	to save CC	
0000209C	07FB		1863+	BR R11	return	
000020A0			1864+RE44	DC OF		
000020A0			1865+	DROP R5		
000020A0	00000000 00000000		1866	DC XL16' 000000000000000000000000000000002147483647C'	V1 result	
000020A8	00000214 7483647C					
000020B0	00000000 7FFFFFFF		1867	DC FD' 2147483647'	R2 source	
			1868			
			1869	VRR_K VCVDG, 159, 1, 0	INT_MIN	
000020B8			1870+	DS OFD		
000020B8		000020B8	1871+	USING *, R5	base for test data and test routine	
000020B8	000020D4		1872+T45	DC A(X45)	address of test routine	
000020BC	002D		1873+	DC H' 45'	test number	
000020BE	00		1874+	DC XL1' 00'		
000020BF	9F		1875+	DC HL1' 159'	i3	
000020C0	01		1876+	DC HL1' 1'	m4	
000020C1	00		1877+	DC HL1' 0'	cc	
000020C2	07		1878+	DC HL1' 7'	cc failed mask	
000020C3	E5C3E5C4 C7404040		1879+	DC CL8' VCVDG'	instruction name	
000020CC	00000010		1880+	DC A(16)	result length	
000020D0	000020F8		1881+REA45	DC A(RE45)	result address	
			1882+*		INSTRUCTION UNDER TEST ROUTINE	
			1883+X45	DS OF		
000020D4	E710 8F48 0006	00001148	1884+	VL V1, V1FUDGE	pollute V1	
000020DA	E320 5050 0004	00002108	1885+	LG R2, RE45+16	get R2 source	
000020E0	E612 0019 F05A		1886+	VCVDG V1, R2, 159, 1	test instruction	
000020E6	E710 8F10 000E	00001110	1887+	VST V1, V1OUTPUT	save	
000020EC	B98D 0020		1888+	EPSW R2, R0	extract psw	
000020F0	5020 8EE8	000010E8	1889+	ST R2, CCPSW	to save CC	
000020F4	07FB		1890+	BR R11	return	
000020F8			1891+RE45	DC OF		
000020F8			1892+	DROP R5		
000020F8	00000000 00000000		1893	DC XL16' 000000000000000000000000000000002147483648D'	V1 result	
00002100	00000214 7483648D					
00002108	FFFFFFFFFF 80000000		1894	DC FD' -2147483648'	R2 source	
			1895			
			1896	VRR_K VCVDG, 159, 1, 0	LONG_MAX	
00002110			1897+	DS OFD		
00002110		00002110	1898+	USING *, R5	base for test data and test routine	
00002110	0000212C		1899+T46	DC A(X46)	address of test routine	
00002114	002E		1900+	DC H' 46'	test number	
00002116	00		1901+	DC XL1' 00'		
00002117	9F		1902+	DC HL1' 159'	i3	
00002118	01		1903+	DC HL1' 1'	m4	
00002119	00		1904+	DC HL1' 0'	cc	
0000211A	07		1905+	DC HL1' 7'	cc failed mask	
0000211B	E5C3E5C4 C7404040		1906+	DC CL8' VCVDG'	instruction name	
00002124	00000010		1907+	DC A(16)	result length	
00002128	00002150		1908+REA46	DC A(RE46)	result address	
			1909+*		INSTRUCTION UNDER TEST ROUTINE	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
0000212C				1910+X46	DS OF	
0000212C	E710 8F48 0006	00001148	1911+	VL V1, V1FUDGE	pollute V1	
00002132	E320 5050 0004	00002160	1912+	LG R2, RE46+16	get R2 source	
00002138	E612 0019 F05A		1913+	VCVDG V1, R2, 159, 1	test instruction	
0000213E	E710 8F10 000E	00001110	1914+	VST V1, V1OUTPUT	save	
00002144	B98D 0020		1915+	EPSW R2, R0	extract psw	
00002148	5020 8EE8	000010E8	1916+	ST R2, CCPSW	to save CC	
0000214C	07FB		1917+	BR R11	return	
00002150			1918+RE46	DC OF		
00002150			1919+	DROP R5		
00002150	00000000 00009223		1920	DC XL16' 0000000000009223372036854775807C'	V1 source	
00002158	37203685 4775807C					
00002160	7FFFFFFF FFFFFFFF		1921	DC XL08' 7FFFFFFFFFFFFF'	R1 result	
			1922			
00002168			1923	VRR_K VCVDG, 159, 1, 0	LONG_MIN	
00002168		00002168	1924+	DS OFD		
00002168	00002184		1925+	USING *, R5	base for test data and test routine	
0000216C	002F		1926+T47	DC A(X47)	address of test routine	
0000216E	00		1927+	DC H' 47'	test number	
0000216F	9F		1928+	DC XL1' 00'		
00002170	01		1929+	DC HL1' 159'	i3	
00002171	00		1930+	DC HL1' 1'	m4	
00002172	00		1931+	DC HL1' 0'	cc	
00002173	07		1932+	DC HL1' 7'	cc failed mask	
00002173	E5C3E5C4 C7404040		1933+	DC CL8' VCVDG'	instruction name	
0000217C	00000010		1934+	DC A(16)	result length	
00002180	000021A8		1935+REA47	DC A(REA47)	result address	
			1936+*		INSTRUCTION UNDER TEST ROUTINE	
00002184			1937+X47	DS OF		
00002184	E710 8F48 0006	00001148	1938+	VL V1, V1FUDGE	pollute V1	
0000218A	E320 5050 0004	000021B8	1939+	LG R2, RE47+16	get R2 source	
00002190	E612 0019 F05A		1940+	VCVDG V1, R2, 159, 1	test instruction	
00002196	E710 8F10 000E	00001110	1941+	VST V1, V1OUTPUT	save	
0000219C	B98D 0020		1942+	EPSW R2, R0	extract psw	
000021A0	5020 8EE8	000010E8	1943+	ST R2, CCPSW	to save CC	
000021A4	07FB		1944+	BR R11	return	
000021A8			1945+RE47	DC OF		
000021A8			1946+	DROP R5		
000021A8	00000000 00009223		1947	DC XL16' 0000000000009223372036854775808D'	V1 source	
000021B0	37203685 4775808D					
000021B8	80000000 00000000		1948	DC XL08' 8000000000000000'	R1 result	
			1949			
000021C0			1950	VRR_K VCVDG, 159, 1, 0	ULONG_MAX	
000021C0			1951+	DS OFD		
000021C0	000021DC	000021C0	1952+	USING *, R5	base for test data and test routine	
000021C0	0030		1953+T48	DC A(X48)	address of test routine	
000021C4	00		1954+	DC H' 48'	test number	
000021C6	9F		1955+	DC XL1' 00'		
000021C7	01		1956+	DC HL1' 159'	i3	
000021C8	00		1957+	DC HL1' 1'	m4	
000021C9	07		1958+	DC HL1' 0'	cc	
000021CA	07		1959+	DC HL1' 7'	cc failed mask	
000021CB	E5C3E5C4 C7404040		1960+	DC CL8' VCVDG'	instruction name	
000021D4	00000010		1961+	DC A(16)	result length	
000021D8	00002200		1962+REA48	DC A(REA48)	result address	
			1963+*		INSTRUCTION UNDER TEST ROUTINE	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000021DC				1964+X48	DS OF	
000021DC	E710 8F48 0006	00001148	1965+	VL V1, V1FUDGE	pollute V1	
000021E2	E320 A010 0004	00002210	1966+	LG R2, RE48+16	get R2 source	
000021E8	E612 0019 F05A		1967+	VCVDG V1, R2, 159, 1	test instruction	
000021EE	E710 8F10 000E	00001110	1968+	VST V1, V1OUTPUT	save	
000021F4	B98D 0020		1969+	EPSW R2, R0	extract psw	
000021F8	5020 8EE8	000010E8	1970+	ST R2, CCPSW	to save CC	
000021FC	07FB		1971+	BR R11	return	
00002200			1972+RE48	DC OF		
00002200			1973+	DROP R5		
00002200	00000000 00000000		1974	DC XL16' 000000000000000000000000000000001D'	V1 source	
00002208	00000000 0000001D		1975	DC XL08' FFFFFFFFFFFFFF'	R1 result	
00002210	FFFFFFFFFF FFFFFFFF		1976			
			1977 * VCVGDG	m4= 1 (LB=0, P1=0 , CS=1)		
			1978 *	i3= 137 (IOM=1, RDC= 9)		
			1979			
00002218			1980	VRR_K VCVGDG, 137, 1, 0		
00002218		00002218	1981+	DS OFD	base for test data and test routine	
00002218	00002234		1982+	USING *, R5	address of test routine	
0000221C	0031		1983+T49	DC A(X49)	test number	
0000221E	00		1984+	DC H' 49'		
0000221F	89		1985+	DC XL1' 00'		
00002220	01		1986+	DC HL1' 137'	i3	
00002221	00		1987+	DC HL1' 1'	m4	
00002222	07		1988+	DC HL1' 0'	cc	
00002223	E5C3E5C4 C7404040		1989+	DC HL1' 7'	cc failed mask	
0000222C	00000010		1990+	DC CL8' VCVGDG'	instruction name	
00002230	00002258		1991+	DC A(16)	result length	
00002234	00002258		1992+REA49	DC A(RE49)	result address	
00002234	00002258		1993+*		INSTRUCTION UNDER TEST ROUTINE	
00002234	E710 8F48 0006	00001148	1994+X49	DS OF		
0000223A	E320 5050 0004	00002268	1995+	VL V1, V1FUDGE	pollute V1	
00002240	E612 0018 905A		1996+	LG R2, RE49+16	get R2 source	
00002246	E710 8F10 000E	00001110	1997+	VCVDG V1, R2, 137, 1	test instruction	
0000224C	B98D 0020		1998+	VST V1, V1OUTPUT	save	
00002250	5020 8EE8	000010E8	1999+	EPSW R2, R0	extract psw	
00002254	07FB		2000+	ST R2, CCPSW	to save CC	
00002258			2001+	BR R11	return	
00002258			2002+RE49	DC OF		
00002258			2003+	DROP R5		
00002258	00000000 00000000		2004	DC XL16' 00000000000000000000000000000000C'	V1 result	
00002260	00000000 0000000C					
00002268	00000000 00000000		2005	DC FD' 0'	R2 source	
00002270			2006			
00002270		00002270	2007	VRR_K VCVGDG, 137, 1, 0		
00002270	0000228C		2008+	DS OFD	base for test data and test routine	
00002274	0032		2009+	USING *, R5	address of test routine	
00002276	00		2010+T50	DC A(X50)	test number	
00002277	89		2011+	DC H' 50'		
00002278	01		2012+	DC XL1' 00'		
00002279	00		2013+	DC HL1' 137'	i3	
0000227A	07		2014+	DC HL1' 1'	m4	
0000227B	E5C3E5C4 C7404040		2015+	DC HL1' 0'	cc	
			2016+	DC HL1' 7'	cc failed mask	
			2017+	DC CL8' VCVGDG'	instruction name	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002284	00000010			2018+ DC A(16)		result length
00002288	000022B0			2019+REA50 DC A(REA50)		result address
				2020+*		INSTRUCTION UNDER TEST ROUTINE
0000228C				2021+X50 DS OF		
0000228C	E710 8F48 0006	00001148		2022+ VL V1, V1FUDGE		pollute V1
00002292	E320 5050 0004	000022C0		2023+ LG R2, RE50+16		get R2 source
00002298	E612 0018 905A			2024+ VCVDG V1, R2, 137, 1		test instruction
0000229E	E710 8F10 000E	00001110		2025+ VST V1, V1OUTPUT		save
000022A4	B98D 0020			2026+ EPSW R2, R0		extract psw
000022A8	5020 8EE8	000010E8		2027+ ST R2, CCPSW		to save CC
000022AC	07FB			2028+ BR R11		return
000022B0				2029+RE50 DC OF		
000022B0				2030+ DROP R5		
000022B0	00000000 00000000			2031 DC XL16' 000000000000000000000000000000001C'	V1 result	
000022B8	00000000 0000001C					
000022C0	00000000 00000001			2032 DC FD' 1'		R2 source
				2033		
000022C8				2034 VRR_K VCVDG, 137, 1, 0		
000022C8		000022C8		2035+ DS OFD		
000022C8	000022E4			2036+ USING *, R5		base for test data and test routine
000022CC	0033			2037+T51 DC A(X51)		address of test routine
000022CE	00			2038+ DC H' 51'		test number
000022CF	89			2039+ DC XL1' 00'		
000022D0	01			2040+ DC HL1' 137'	i3	
000022D1	00			2041+ DC HL1' 1'	m4	
000022D2	07			2042+ DC HL1' 0'	cc	
000022D3	E5C3E5C4 C7404040			2043+ DC HL1' 7'	cc failed mask	
000022DC	00000010			2044+ DC CL8' VCVDG'	instruction name	
000022E0	00002308			2045+ DC A(16)	result length	
				2046+REA51 DC A(REA51)	result address	
				2047+*	INSTRUCTION UNDER TEST ROUTINE	
000022E4				2048+X51 DS OF		
000022E4	E710 8F48 0006	00001148		2049+ VL V1, V1FUDGE	pollute V1	
000022EA	E320 5050 0004	00002318		2050+ LG R2, RE51+16	get R2 source	
000022F0	E612 0018 905A			2051+ VCVDG V1, R2, 137, 1	test instruction	
000022F6	E710 8F10 000E	00001110		2052+ VST V1, V1OUTPUT	save	
000022FC	B98D 0020			2053+ EPSW R2, R0	extract psw	
00002300	5020 8EE8	000010E8		2054+ ST R2, CCPSW	to save CC	
00002304	07FB			2055+ BR R11	return	
00002308				2056+RE51 DC OF		
00002308				2057+ DROP R5		
00002308	00000000 00000000			2058 DC XL16' 000000000000000000000000000000001D'	V1 result	
00002310	00000000 0000001D					
00002318	FFFFFF FFFFFFFF			2059 DC FD' -1'		R2 source
				2060		
00002320				2061 VRR_K VCVDG, 137, 1, 3		INT_MAX
00002320		00002320		2062+ DS OFD		
00002320	0000233C			2063+ USING *, R5		base for test data and test routine
00002324	0034			2064+T52 DC A(X52)		address of test routine
00002326	00			2065+ DC H' 52'		test number
00002327	89			2066+ DC XL1' 00'	i3	
00002328	01			2067+ DC HL1' 137'	m4	
00002329	03			2068+ DC HL1' 1'	cc	
0000232A	0E			2069+ DC HL1' 3'	cc failed mask	
0000232B	E5C3E5C4 C7404040			2070+ DC HL1' 14'	instruction name	
				2071+ DC CL8' VCVDG'		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002334	00000010			2072+	DC	A(16)
00002338	00002360			2073+REA52	DC	A(REA52)
				2074+*		
0000233C				2075+X52	DS	OF
0000233C	E710 8F48 0006	00001148		2076+	VL	V1, V1FUDGE
00002342	E320 5050 0004	00002370		2077+	LG	R2, RE52+16
00002348	E612 0018 905A			2078+	VCVDG	V1, R2, 137, 1
0000234E	E710 8F10 000E	00001110		2079+	VST	V1, V1OUTPUT
00002354	B98D 0020			2080+	EPSW	R2, R0
00002358	5020 8EE8	000010E8		2081+	ST	R2, CCPSW
0000235C	07FB			2082+	BR	R11
00002360				2083+RE52	DC	OF
00002360				2084+	DROP	R5
00002360	00000000 00000000			2085	DC	XL16' 000000000000000000000000147483647C'
00002368	00000014 7483647C					V1 result
00002370	00000000 7FFFFFFF			2086	DC	FD' 2147483647'
				2087		
				2088	VRR_K	VCVDG, 137, 1, 3
00002378		00002378		2089+	DS	OFD
00002378				2090+	USING	*, R5
00002378	00002394			2091+T53	DC	A(X53)
0000237C	0035			2092+	DC	H' 53'
0000237E	00			2093+	DC	XL1' 00'
0000237F	89			2094+	DC	HL1' 137'
00002380	01			2095+	DC	HL1' 1'
00002381	03			2096+	DC	HL1' 3'
00002382	0E			2097+	DC	HL1' 14'
00002383	E5C3E5C4 C7404040			2098+	DC	CL8' VCVDG'
0000238C	00000010			2099+	DC	A(16)
00002390	000023B8			2100+REA53	DC	A(REA53)
				2101+*		
				2102+X53	DS	OF
00002394	E710 8F48 0006	00001148		2103+	VL	V1, V1FUDGE
0000239A	E320 5050 0004	000023C8		2104+	LG	R2, RE53+16
000023A0	E612 0018 905A			2105+	VCVDG	V1, R2, 137, 1
000023A6	E710 8F10 000E	00001110		2106+	VST	V1, V1OUTPUT
000023AC	B98D 0020			2107+	EPSW	R2, R0
000023B0	5020 8EE8	000010E8		2108+	ST	R2, CCPSW
000023B4	07FB			2109+	BR	R11
000023B8				2110+RE53	DC	OF
000023B8				2111+	DROP	R5
000023B8	00000000 00000000			2112	DC	XL16' 000000000000000000000000147483648D'
000023C0	00000014 7483648D					V1 result
000023C8	FFFFFFFFFF 80000000			2113	DC	FD' -2147483648'
				2114		
				2115	VRR_K	VCVDG, 137, 1, 3
000023D0		000023D0		2116+	DS	OFD
000023D0				2117+	USING	*, R5
000023D0	000023EC			2118+T54	DC	A(X54)
000023D4	0036			2119+	DC	H' 54'
000023D6	00			2120+	DC	XL1' 00'
000023D7	89			2121+	DC	HL1' 137'
000023D8	01			2122+	DC	HL1' 1'
000023D9	03			2123+	DC	HL1' 3'
000023DA	0E			2124+	DC	HL1' 14'
000023DB	E5C3E5C4 C7404040			2125+	DC	CL8' VCVDG'

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000023E4	00000010			2126+	DC	A(16)
000023E8	00002410			2127+REA54	DC	A(REA54)
				2128+*		
000023EC				2129+X54	DS	OF
000023EC	E710 8F48 0006	00001148	2130+	VL	V1, V1FUDGE	pollute V1
000023F2	E320 5050 0004	00002420	2131+	LG	R2, RE54+16	get R2 source
000023F8	E612 0018 905A		2132+	VCVDG	V1, R2, 137, 1	test instruction
000023FE	E710 8F10 000E	00001110	2133+	VST	V1, V1OUTPUT	save
00002404	B98D 0020		2134+	EPSW	R2, R0	extract psw
00002408	5020 8EE8	000010E8	2135+	ST	R2, CCPSW	to save CC
0000240C	07FB		2136+	BR	R11	return
00002410			2137+RE54	DC	OF	
00002410			2138+	DROP	R5	
00002410	00000000 00000000		2139	DC	XL16' 00000000000000000000000000000000854775807C'	V1 source
00002418	00000085 4775807C					
00002420	7FFFFFFF FFFFFFFF		2140	DC	XL08' 7FFFFFFFFFFFFF'	R1 result
			2141			
			2142	VRR_K	VCVDG, 137, 1, 3	LONG_MIN
00002428		00002428	2143+	DS	OFD	
00002428			2144+	USING	*, R5	base for test data and test routine
00002428	00002444		2145+T55	DC	A(X55)	address of test routine
0000242C	0037		2146+	DC	H' 55'	test number
0000242E	00		2147+	DC	XL1' 00'	
0000242F	89		2148+	DC	HL1' 137'	i3
00002430	01		2149+	DC	HL1' 1'	m4
00002431	03		2150+	DC	HL1' 3'	cc
00002432	0E		2151+	DC	HL1' 14'	cc failed mask
00002433	E5C3E5C4 C7404040		2152+	DC	CL8' VCVDG'	instruction name
0000243C	00000010		2153+	DC	A(16)	result length
00002440	00002468		2154+REA55	DC	A(REA55)	result address
			2155+*			INSTRUCTION UNDER TEST ROUTINE
00002444			2156+X55	DS	OF	
00002444	E710 8F48 0006	00001148	2157+	VL	V1, V1FUDGE	pollute V1
0000244A	E320 5050 0004	00002478	2158+	LG	R2, RE55+16	get R2 source
00002450	E612 0018 905A		2159+	VCVDG	V1, R2, 137, 1	test instruction
00002456	E710 8F10 000E	00001110	2160+	VST	V1, V1OUTPUT	save
0000245C	B98D 0020		2161+	EPSW	R2, R0	extract psw
00002460	5020 8EE8	000010E8	2162+	ST	R2, CCPSW	to save CC
00002464	07FB		2163+	BR	R11	return
00002468			2164+RE55	DC	OF	
00002468			2165+	DROP	R5	
00002468	00000000 00000000		2166	DC	XL16' 00000000000000000000000000000000854775808D'	V1 source
00002470	00000085 4775808D					
00002478	80000000 00000000		2167	DC	XL08' 8000000000000000'	R1 result
			2168			
			2169	VRR_K	VCVDG, 137, 1, 0	ULONG_MAX
00002480		00002480	2170+	DS	OFD	
00002480			2171+	USING	*, R5	base for test data and test routine
00002480	0000249C		2172+T56	DC	A(X56)	address of test routine
00002484	0038		2173+	DC	H' 56'	test number
00002486	00		2174+	DC	XL1' 00'	
00002487	89		2175+	DC	HL1' 137'	i3
00002488	01		2176+	DC	HL1' 1'	m4
00002489	00		2177+	DC	HL1' 0'	cc
0000248A	07		2178+	DC	HL1' 7'	cc failed mask
0000248B	E5C3E5C4 C7404040		2179+	DC	CL8' VCVDG'	instruction name

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002494	00000010			2180+ DC A(16)		result length
00002498	000024C0			2181+REA56 DC A(REA56)		result address
				2182+*		INSTRUCTION UNDER TEST ROUTINE
0000249C				2183+X56 DS OF		
0000249C	E710 8F48 0006	00001148		2184+ VL V1, V1FUDGE		pollute V1
000024A2	E320 5050 0004	000024D0		2185+ LG R2, RE56+16		get R2 source
000024A8	E612 0018 905A			2186+ VCVDG V1, R2, 137, 1		test instruction
000024AE	E710 8F10 000E	00001110		2187+ VST V1, V1OUTPUT		save
000024B4	B98D 0020			2188+ EPSW R2, R0		extract psw
000024B8	5020 8EE8	000010E8		2189+ ST R2, CCPSW		to save CC
000024BC	07FB			2190+ BR R11		return
000024C0				2191+REA56 DC OF		
000024C0				2192+ DROP R5		
000024C0	00000000 00000000			2193 DC XL16' 000000000000000000000000000000001D'	V1 source	
000024C8	00000000 0000001D					
000024D0	FFFFFFFFFF FFFFFFFF			2194 DC XL08' FFFFFFFFFFFFFF'		R1 result
				2195		
				2196 *-		
				2197 * VCVDG	m4= 3 (LB=0, P1=1 , CS=1)	base for test data and test routine
				2198 * i3= 159 (IOM=1, RDC=31)		address of test routine
				2199		test number
000024D8		000024D8		2200 DS VRR_K VCVDG, 159, 3, 0		
				2201+ DS OFD		
000024D8				2202+ USING *, R5		
000024D8	000024F4			2203+T57 DC A(X57)		
000024DC	0039			2204+ DC H' 57'		
000024DE	00			2205+ DC XL1' 00'		
000024DF	9F			2206+ DC HL1' 159'	i3	
000024E0	03			2207+ DC HL1' 3'	m4	
000024E1	00			2208+ DC HL1' 0'	cc	
000024E2	07			2209+ DC HL1' 7'	cc failed mask	
000024E3	E5C3E5C4 C7404040			2210+ DC CL8' VCVDG'	instruction name	
000024EC	00000010			2211+ DC A(16)	result length	
000024F0	00002518			2212+REA57 DC A(REA57)	result address	
				2213+*		INSTRUCTION UNDER TEST ROUTINE
000024F4				2214+X57 DS OF		
000024F4	E710 8F48 0006	00001148		2215+ VL V1, V1FUDGE		pollute V1
000024FA	E320 5050 0004	00002528		2216+ LG R2, RE57+16		get R2 source
00002500	E612 0039 F05A			2217+ VCVDG V1, R2, 159, 3		test instruction
00002506	E710 8F10 000E	00001110		2218+ VST V1, V1OUTPUT		save
0000250C	B98D 0020			2219+ EPSW R2, R0		extract psw
00002510	5020 8EE8	000010E8		2220+ ST R2, CCPSW		to save CC
00002514	07FB			2221+ BR R11		return
00002518				2222+REA57 DC OF		
00002518	00000000 00000000			2223+ DROP R5		
00002520	00000000 0000000F			2224 DC XL16' 00000000000000000000000000000000F'	V1 result	
00002528	00000000 00000000			2225 DC FD' 0'		R2 source
				2226		
				2227 DS VRR_K VCVDG, 159, 3, 0		
00002530		00002530		2228+ DS OFD		
00002530				2229+ USING *, R5		
00002530	0000254C			2230+T58 DC A(X58)		
00002534	003A			2231+ DC H' 58'		
00002536	00			2232+ DC XL1' 00'		
00002537	9F			2233+ DC HL1' 159'	i3	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002538	03			2234+ DC HL1' 3'	m4	
00002539	00			2235+ DC HL1' 0'	cc	
0000253A	07			2236+ DC HL1' 7'	cc failed mask	
0000253B	E5C3E5C4 C7404040			2237+ DC CL8' VCVDG'	instruction name	
00002544	00000010			2238+ DC A(16)	result length	
00002548	00002570			2239+REA58 DC A(RE58)	result address	
				2240+* 2241+X58 DS OF	INSTRUCTION UNDER TEST ROUTINE	
0000254C	E710 8F48 0006	00001148		2242+ VL V1, V1FUDGE	pollute V1	
00002552	E320 5050 0004	00002580		2243+ LG R2, RE58+16	get R2 source	
00002558	E612 0039 F05A			2244+ VCVDG V1, R2, 159, 3	test instruction	
0000255E	E710 8F10 000E	00001110		2245+ VST V1, V1OUTPUT	save	
00002564	B98D 0020			2246+ EPSW R2, R0	extract psw	
00002568	5020 8EE8	000010E8		2247+ ST R2, CCPSW	to save CC	
0000256C	07FB			2248+ BR R11	return	
00002570				2249+REA58 DC OF		
00002570				2250+ DROP R5		
00002570	00000000 00000000			2251 DC XL16' 000000000000000000000000000000001F'	V1 result	
00002578	00000000 0000001F			2252 DC FD' 1'	R2 source	
00002580	00000000 00000001			2253		
				2254 DS VRR_K VCVDG, 159, 3, 0		
				2255+ DS OFD		
00002588		00002588		2256+ USING *, R5	base for test data and test routine	
00002588	000025A4			2257+T59 DC A(X59)	address of test routine	
0000258C	003B			2258+ DC H' 59'	test number	
0000258E	00			2259+ DC XL1' 00'		
0000258F	9F			2260+ DC HL1' 159'	i3	
00002590	03			2261+ DC HL1' 3'	m4	
00002591	00			2262+ DC HL1' 0'	cc	
00002592	07			2263+ DC HL1' 7'	cc failed mask	
00002593	E5C3E5C4 C7404040			2264+ DC CL8' VCVDG'	instruction name	
0000259C	00000010			2265+ DC A(16)	result length	
000025A0	000025C8			2266+REA59 DC A(RE59)	result address	
				2267+*	INSTRUCTION UNDER TEST ROUTINE	
000025A4				2268+X59 DS OF		
000025A4	E710 8F48 0006	00001148		2269+ VL V1, V1FUDGE	pollute V1	
000025AA	E320 5050 0004	000025D8		2270+ LG R2, RE59+16	get R2 source	
000025B0	E612 0039 F05A			2271+ VCVDG V1, R2, 159, 3	test instruction	
000025B6	E710 8F10 000E	00001110		2272+ VST V1, V1OUTPUT	save	
000025BC	B98D 0020			2273+ EPSW R2, R0	extract psw	
000025C0	5020 8EE8	000010E8		2274+ ST R2, CCPSW	to save CC	
000025C4	07FB			2275+ BR R11	return	
000025C8				2276+REA59 DC OF		
000025C8				2277+ DROP R5		
000025C8	00000000 00000000			2278 DC XL16' 000000000000000000000000000000001F'	V1 result	
000025D0	00000000 0000001F			2279 DC FD' - 1'	R2 source	
000025D8	FFFFFF FFFFFFFF			2280		
				2281 DS VRR_K VCVDG, 159, 3, 0	INT_MAX	
				2282+ DS OFD		
000025E0		000025E0		2283+ USING *, R5	base for test data and test routine	
000025E0	000025FC			2284+T60 DC A(X60)	address of test routine	
000025E4	003C			2285+ DC H' 60'	test number	
000025E6	00			2286+ DC XL1' 00'		
000025E7	9F			2287+ DC HL1' 159'	i3	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000025E8	03			2288+ DC HL1' 3'	m4	
000025E9	00			2289+ DC HL1' 0'	cc	
000025EA	07			2290+ DC HL1' 7'	cc failed mask	
000025EB	E5C3E5C4 C7404040			2291+ DC CL8' VCVGDG'	instruction name	
000025F4	00000010			2292+ DC A(16)	result length	
000025F8	00002620			2293+REA60 DC A(RE60)	result address	
				2294+* 2295+X60 DS OF	INSTRUCTION UNDER TEST ROUTINE	
000025FC	E710 8F48 0006	00001148		2296+ VL V1, V1FUDGE	pollute V1	
00002602	E320 5050 0004	00002630		2297+ LG R2, RE60+16	get R2 source	
00002608	E612 0039 F05A			2298+ VCVGDG V1, R2, 159, 3	test instruction	
0000260E	E710 8F10 000E	00001110		2299+ VST V1, V1OUTPUT	save	
00002614	B98D 0020			2300+ EPSW R2, R0	extract psw	
00002618	5020 8EE8	000010E8		2301+ ST R2, CCPSW	to save CC	
0000261C	07FB			2302+ BR R11	return	
00002620				2303+REA60 DC OF		
00002620				2304+ DROP R5		
00002620	00000000 00000000			2305 DC XL16' 000000000000000000000000000000002147483647F'	V1 result	
00002628	00000214 7483647F			2306 DC FD' 2147483647'	R2 source	
00002630	00000000 7FFFFFFF			2307		
				2308 VRR_K VCVGDG, 159, 3, 0	INT_MIN	
00002638		00002638		2309+ DS OFD		
00002638				2310+ USING *, R5	base for test data and test routine	
00002638	00002654			2311+T61 DC A(X61)	address of test routine	
0000263C	003D			2312+ DC H' 61'	test number	
0000263E	00			2313+ DC XL1' 00'		
0000263F	9F			2314+ DC HL1' 159'	i3	
00002640	03			2315+ DC HL1' 3'	m4	
00002641	00			2316+ DC HL1' 0'	cc	
00002642	07			2317+ DC HL1' 7'	cc failed mask	
00002643	E5C3E5C4 C7404040			2318+ DC CL8' VCVGDG'	instruction name	
0000264C	00000010			2319+ DC A(16)	result length	
00002650	00002678			2320+REA61 DC A(RE61)	result address	
				2321+*	INSTRUCTION UNDER TEST ROUTINE	
00002654				2322+X61 DS OF		
00002654	E710 8F48 0006	00001148		2323+ VL V1, V1FUDGE	pollute V1	
0000265A	E320 5050 0004	00002688		2324+ LG R2, RE61+16	get R2 source	
00002660	E612 0039 F05A			2325+ VCVGDG V1, R2, 159, 3	test instruction	
00002666	E710 8F10 000E	00001110		2326+ VST V1, V1OUTPUT	save	
0000266C	B98D 0020			2327+ EPSW R2, R0	extract psw	
00002670	5020 8EE8	000010E8		2328+ ST R2, CCPSW	to save CC	
00002674	07FB			2329+ BR R11	return	
00002678				2330+REA61 DC OF		
00002678	00000000 00000000			2331+ DROP R5		
00002678	00000214 7483648F			2332 DC XL16' 000000000000000000000000000000002147483648F'	V1 result	
00002688	FFFFFFFFFF 80000000			2333 DC FD' -2147483648'	R2 source	
				2334		
				2335 VRR_K VCVGDG, 159, 3, 0	LONG_MAX	
00002690		00002690		2336+ DS OFD		
00002690				2337+ USING *, R5	base for test data and test routine	
00002690	000026AC			2338+T62 DC A(X62)	address of test routine	
00002694	003E			2339+ DC H' 62'	test number	
00002696	00			2340+ DC XL1' 00'		
00002697	9F			2341+ DC HL1' 159'	i3	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002698	03			2342+ DC HL1' 3'	m4	
00002699	00			2343+ DC HL1' 0'	cc	
0000269A	07			2344+ DC HL1' 7'	cc failed mask	
0000269B	E5C3E5C4 C7404040			2345+ DC CL8' VCVDG'	instruction name	
000026A4	00000010			2346+ DC A(16)	result length	
000026A8	000026D0			2347+REA62 DC A(RE62)	result address	
				2348+* DS OF	INSTRUCTION UNDER TEST ROUTINE	
000026AC				2349+X62 VL V1, V1FUDGE		
000026AC	E710 8F48 0006	00001148		2350+ LG R2, RE62+16	pollute V1	
000026B2	E320 5050 0004	000026E0		2351+ VCVDG V1, R2, 159, 3	get R2 source	
000026B8	E612 0039 F05A			2352+ VST V1, V1OUTPUT	test instruction	
000026BE	E710 8F10 000E	00001110		2353+ EPSW R2, R0	save	
000026C4	B98D 0020			2354+ ST R2, CCPSW	extract psw	
000026C8	5020 8EE8	000010E8		2355+ BR R11	to save CC	
000026CC	07FB			2356+ DC OF	return	
000026D0				2357+RE62 DROP R5		
000026D0	00000000 00009223			2359 DC XL16' 0000000000009223372036854775807F'	V1 source	
000026D8	37203685 4775807F			2360 DC XL08' 7FFFFFFFFFFFFF'	R1 result	
000026E0	7FFFFFFF FFFFFFFF			2361		
				2362 DS VRR_K VCVDG, 159, 3, 0	LONG_MIN	
				2363+ DS OFD		
000026E8		000026E8		2364+ USING *, R5	base for test data and test routine	
000026E8	00002704			2365+T63 DC A(X63)	address of test routine	
000026EC	003F			2366+ DC H' 63'	test number	
000026EE	00			2367+ DC XL1' 00'		
000026EF	9F			2368+ DC HL1' 159'	i3	
000026F0	03			2369+ DC HL1' 3'	m4	
000026F1	00			2370+ DC HL1' 0'	cc	
000026F2	07			2371+ DC HL1' 7'	cc failed mask	
000026F3	E5C3E5C4 C7404040			2372+ DC CL8' VCVDG'	instruction name	
000026FC	00000010			2373+ DC A(16)	result length	
00002700	00002728			2374+REA63 DC A(RE63)	result address	
				2375+* DS OF	INSTRUCTION UNDER TEST ROUTINE	
00002704				2376+X63 VL V1, V1FUDGE		
00002704	E710 8F48 0006	00001148		2377+ LG R2, RE63+16	pollute V1	
0000270A	E320 5050 0004	00002738		2378+ VCVDG V1, R2, 159, 3	get R2 source	
00002710	E612 0039 F05A			2379+ VST V1, V1OUTPUT	test instruction	
00002716	E710 8F10 000E	00001110		2380+ EPSW R2, R0	save	
0000271C	B98D 0020			2381+ ST R2, CCPSW	extract psw	
00002720	5020 8EE8	000010E8		2382+ BR R11	to save CC	
00002724	07FB			2383+ DC OF	return	
00002728				2384+RE63 DROP R5		
00002728	00000000 00009223			2385+ DC XL16' 0000000000009223372036854775808F'	V1 source	
00002730	37203685 4775808F			2386 DC XL08' 8000000000000000'	R1 result	
00002738	80000000 00000000			2387 DS VRR_K VCVDG, 159, 3, 0	ULONG_MAX	
				2388 DS OFD		
				2389 USING *, R5	base for test data and test routine	
00002740	0000275C	00002740		2390+ DC A(X64)	address of test routine	
00002744	0040			2391+ DC H' 64'	test number	
00002746	00			2392+T64 DC XL1' 00'		
00002747	9F			2393+ DC HL1' 159'	i3	
				2394+ DC OF		
				2395+ DC XL08' 8000000000000000'		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002748	03			2396+ DC HL1' 3'	m4	
00002749	00			2397+ DC HL1' 0'	cc	
0000274A	07			2398+ DC HL1' 7'	cc failed mask	
0000274B	E5C3E5C4 C7404040			2399+ DC CL8' VCVDG'	instruction name	
00002754	00000010			2400+ DC A(16)	result length	
00002758	00002780			2401+REA64 DC A(REA64)	result address	
				2402+* DC	INSTRUCTION UNDER TEST ROUTINE	
0000275C				2403+X64 DS OF		
0000275C	E710 8F48 0006	00001148		2404+ VL V1, V1FUDGE	pollute V1	
00002762	E320 5050 0004	00002790		2405+ LG R2, RE64+16	get R2 source	
00002768	E612 0039 F05A			2406+ VCVDG V1, R2, 159, 3	test instruction	
0000276E	E710 8F10 000E	00001110		2407+ VST V1, V1OUTPUT	save	
00002774	B98D 0020			2408+ EPSW R2, R0	extract psw	
00002778	5020 8EE8	000010E8		2409+ ST R2, CCPSW	to save CC	
0000277C	07FB			2410+ BR R11	return	
00002780				2411+REA64 DC OF		
00002780				2412+ DROP R5		
00002780	00000000 00000000			2413 DC XL16' 000000000000000000000000000000001F'	V1 source	
00002788	00000000 0000001F			2414 DC XL08' FFFFFFFFFFFFFF'	R1 result	
00002790	FFFFFFFFFF FFFFFFFF			2415		
				2416 * VCVDG	m4= 3 (LB=0, P1=1 , CS=1)	
				2417 *	i3= 137 (IOM=1, RDC= 9)	
00002798		00002798		2418		
00002798				2419 VRR_K VCVDG, 137, 3, 0		
00002798	000027B4			2420+ DS OFD	base for test data and test routine	
00002798	0041			2421+ USING *, R5	address of test routine	
0000279C				2422+T65 DC A(X65)	test number	
0000279E	00			2423+ DC H' 65'		
0000279F	89			2424+ DC XL1' 00'		
000027A0	03			2425+ DC HL1' 137'	i3	
000027A1	00			2426+ DC HL1' 3'	m4	
000027A2	07			2427+ DC HL1' 0'	cc	
000027A3	E5C3E5C4 C7404040			2428+ DC HL1' 7'	cc failed mask	
000027AC	00000010			2429+ DC CL8' VCVDG'	instruction name	
000027B0	000027D8			2430+ DC A(16)	result length	
				2431+REA65 DC A(REA65)	result address	
				2432+*	INSTRUCTION UNDER TEST ROUTINE	
000027B4				2433+X65 DS OF		
000027B4	E710 8F48 0006	00001148		2434+ VL V1, V1FUDGE	pollute V1	
000027BA	E320 5050 0004	000027E8		2435+ LG R2, RE65+16	get R2 source	
000027C0	E612 0038 905A			2436+ VCVDG V1, R2, 137, 3	test instruction	
000027C6	E710 8F10 000E	00001110		2437+ VST V1, V1OUTPUT	save	
000027CC	B98D 0020			2438+ EPSW R2, R0	extract psw	
000027D0	5020 8EE8	000010E8		2439+ ST R2, CCPSW	to save CC	
000027D4	07FB			2440+ BR R11	return	
000027D8				2441+REA65 DC OF		
000027D8	00000000 00000000			2442+ DROP R5		
000027D8	00000000 0000000F			2443 DC XL16' 00000000000000000000000000000000F'	V1 result	
000027E8	00000000 00000000			2444 DC FD' 0'	R2 source	
000027F0		000027F0		2445		
000027F0				2446 VRR_K VCVDG, 137, 3, 0		
000027F0	0000280C			2447+ DS OFD	base for test data and test routine	
				2448+ USING *, R5	address of test routine	
				2449+T66 DC A(X66)		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000027F4	0042			2450+ DC H' 66'		test number
000027F6	00			2451+ DC XL1' 00'		
000027F7	89			2452+ DC HL1' 137'	i3	
000027F8	03			2453+ DC HL1' 3'	m4	
000027F9	00			2454+ DC HL1' 0'	cc	
000027FA	07			2455+ DC HL1' 7'	cc failed mask	
000027FB	E5C3E5C4 C7404040			2456+ DC CL8' VCVDG'	instruction name	
00002804	00000010			2457+ DC A(16)	result length	
00002808	00002830			2458+REA66 DC A(REA66)	result address	
				2459+*	INSTRUCTION UNDER TEST ROUTINE	
0000280C				2460+X66 DS OF		
0000280C	E710 8F48 0006	00001148		2461+ VL V1, V1FUDGE	pollute V1	
00002812	E320 5050 0004	00002840		2462+ LG R2, RE66+16	get R2 source	
00002818	E612 0038 905A			2463+ VCVDG V1, R2, 137, 3	test instruction	
0000281E	E710 8F10 000E	00001110		2464+ VST V1, V1OUTPUT	save	
00002824	B98D 0020			2465+ EPSW R2, R0	extract psw	
00002828	5020 8EE8	000010E8		2466+ ST R2, CCPSW	to save CC	
0000282C	07FB			2467+ BR R11	return	
00002830				2468+RE66 DC OF		
00002830				2469+ DROP R5		
00002830	00000000 00000000			2470 DC XL16' 000000000000000000000000000000001F'	V1 result	
00002838	00000000 0000001F					
00002840	00000000 00000001			2471 DC FD' 1'	R2 source	
				2472		
00002848		00002848		2473 VRR_K VCVDG, 137, 3, 0		
00002848				2474+ DS OFD		
00002848	00002864			2475+ USING *, R5	base for test data and test routine	
0000284C	0043			2476+T67 DC A(X67)	address of test routine	
0000284E	00			2477+ DC H' 67'	test number	
0000284F	89			2478+ DC XL1' 00'		
00002850	03			2479+ DC HL1' 137'	i3	
00002851	00			2480+ DC HL1' 3'	m4	
00002852	07			2481+ DC HL1' 0'	cc	
00002853	E5C3E5C4 C7404040			2482+ DC HL1' 7'	cc failed mask	
0000285C	00000010			2483+ DC CL8' VCVDG'	instruction name	
00002860	00002888			2484+ DC A(16)	result length	
				2485+REA67 DC A(REA67)	result address	
				2486+*	INSTRUCTION UNDER TEST ROUTINE	
00002864				2487+X67 DS OF		
00002864	E710 8F48 0006	00001148		2488+ VL V1, V1FUDGE	pollute V1	
0000286A	E320 5050 0004	00002898		2489+ LG R2, RE67+16	get R2 source	
00002870	E612 0038 905A			2490+ VCVDG V1, R2, 137, 3	test instruction	
00002876	E710 8F10 000E	00001110		2491+ VST V1, V1OUTPUT	save	
0000287C	B98D 0020			2492+ EPSW R2, R0	extract psw	
00002880	5020 8EE8	000010E8		2493+ ST R2, CCPSW	to save CC	
00002884	07FB			2494+ BR R11	return	
00002888				2495+RE67 DC OF		
00002888	00000000 00000000			2496+ DROP R5		
00002888	00000000 0000001F			2497 DC XL16' 000000000000000000000000000000001F'	V1 result	
00002890	FFFFFFFFFF FFFFFFFF					
00002898				2498 DC FD' -1'	R2 source	
				2499		
000028A0		000028A0		2500 VRR_K VCVDG, 137, 3, 3	INT_MAX	
000028A0				2501+ DS OFD		
000028A0	000028BC			2502+ USING *, R5	base for test data and test routine	
				2503+T68 DC A(X68)	address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000028A4	0044			2504+ DC H' 68'	test number	
000028A6	00			2505+ DC XL1' 00'		
000028A7	89			2506+ DC HL1' 137'	i3	
000028A8	03			2507+ DC HL1' 3'	m4	
000028A9	03			2508+ DC HL1' 3'	cc	
000028AA	OE			2509+ DC HL1' 14'	cc failed mask	
000028AB	E5C3E5C4 C7404040			2510+ DC CL8' VCVDG'	instruction name	
000028B4	00000010			2511+ DC A(16)	result length	
000028B8	000028E0			2512+REA68 DC A(RE68)	result address	
				2513+*	INSTRUCTION UNDER TEST ROUTINE	
000028BC				2514+X68 DS OF		
000028BC	E710 8F48 0006	00001148		2515+ VL V1, V1FUDGE	pollute V1	
000028C2	E320 5050 0004	000028F0		2516+ LG R2, RE68+16	get R2 source	
000028C8	E612 0038 905A			2517+ VCVDG V1, R2, 137, 3	test instruction	
000028CE	E710 8F10 000E	00001110		2518+ VST V1, V1OUTPUT	save	
000028D4	B98D 0020			2519+ EPSW R2, R0	extract psw	
000028D8	5020 8EE8	000010E8		2520+ ST R2, CCPSW	to save CC	
000028DC	07FB			2521+ BR R11	return	
000028E0				2522+RE68 DC OF		
000028E0				2523+ DROP R5		
000028E0	00000000 00000000			2524 DC XL16' 000000000000000000000000147483647F'	V1 result	
000028E8	00000014 7483647F			2525 DC FD' 2147483647'	R2 source	
000028F0	00000000 7FFFFFFF			2526	INT_MIN	
000028F8		000028F8		2527 VRR_K VCVDG, 137, 3, 3		
000028F8				2528+ DS OFD		
000028F8	00002914			2529+ USING *, R5	base for test data and test routine	
000028FC	0045			2530+T69 DC A(X69)	address of test routine	
000028FE	00			2531+ DC H' 69'	test number	
000028FF	89			2532+ DC XL1' 00'		
00002900	03			2533+ DC HL1' 137'	i3	
00002901	03			2534+ DC HL1' 3'	m4	
00002902	0E			2535+ DC HL1' 3'	cc	
00002903	E5C3E5C4 C7404040			2536+ DC HL1' 14'	cc failed mask	
0000290C	00000010			2537+ DC CL8' VCVDG'	instruction name	
00002910	00002938			2538+ DC A(16)	result length	
				2539+REA69 DC A(RE69)	result address	
				2540+*	INSTRUCTION UNDER TEST ROUTINE	
00002914				2541+X69 DS OF		
00002914	E710 8F48 0006	00001148		2542+ VL V1, V1FUDGE	pollute V1	
0000291A	E320 5050 0004	00002948		2543+ LG R2, RE69+16	get R2 source	
00002920	E612 0038 905A			2544+ VCVDG V1, R2, 137, 3	test instruction	
00002926	E710 8F10 000E	00001110		2545+ VST V1, V1OUTPUT	save	
0000292C	B98D 0020			2546+ EPSW R2, R0	extract psw	
00002930	5020 8EE8	000010E8		2547+ ST R2, CCPSW	to save CC	
00002934	07FB			2548+ BR R11	return	
00002938				2549+RE69 DC OF		
00002938	00000000 00000000			2550+ DROP R5		
00002938	00000014 7483648F			2551 DC XL16' 000000000000000000000000147483648F'	V1 result	
00002948	FFFFFFFFFF 80000000			2552 DC FD' - 2147483648'		
				2553	LONG_MAX	
00002950		00002950		2554 VRR_K VCVDG, 137, 3, 3		
00002950				2555+ DS OFD		
00002950	0000296C			2556+ USING *, R5	base for test data and test routine	
				2557+T70 DC A(X70)	address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002954	0046			2558+ DC H' 70'	test number	
00002956	00			2559+ DC XL1' 00'		
00002957	89			2560+ DC HL1' 137'	i3	
00002958	03			2561+ DC HL1' 3'	m4	
00002959	03			2562+ DC HL1' 3'	cc	
0000295A	OE			2563+ DC HL1' 14'	cc failed mask	
0000295B	E5C3E5C4 C7404040			2564+ DC CL8' VCVDG'	instruction name	
00002964	00000010			2565+ DC A(16)	result length	
00002968	00002990			2566+REA70 DC A(RE70)	result address	
				2567+*	INSTRUCTION UNDER TEST ROUTINE	
0000296C				2568+X70 DS OF		
0000296C	E710 8F48 0006	00001148		2569+ VL V1, V1FUDGE	pollute V1	
00002972	E320 5050 0004	000029A0		2570+ LG R2, RE70+16	get R2 source	
00002978	E612 0038 905A			2571+ VCVDG V1, R2, 137, 3	test instruction	
0000297E	E710 8F10 000E	00001110		2572+ VST V1, V1OUTPUT	save	
00002984	B98D 0020			2573+ EPSW R2, R0	extract psw	
00002988	5020 8EE8	000010E8		2574+ ST R2, CCPSW	to save CC	
0000298C	07FB			2575+ BR R11	return	
00002990				2576+RE70 DC OF		
00002990				2577+ DROP R5		
00002990	00000000 00000000			2578 DC XL16' 00000000000000000000000000000000854775807F'	V1 source	
00002998	00000085 4775807F			2579 DC XL08' 7FFFFFFFFFFFFF'	R1 result	
000029A0	7FFFFFFF FFFFFFFF			2580	LONG_MIN	
000029A8		000029A8		2581 VRR_K VCVDG, 137, 3, 3		
000029A8				2582+ DS OFD		
000029A8	000029C4			2583+ USING *, R5	base for test data and test routine	
000029AC	0047			2584+T71 DC A(X71)	address of test routine	
000029AE	00			2585+ DC H' 71'	test number	
000029AF	89			2586+ DC XL1' 00'		
000029B0	03			2587+ DC HL1' 137'	i3	
000029B1	03			2588+ DC HL1' 3'	m4	
000029B2	0E			2589+ DC HL1' 3'	cc	
000029B3	E5C3E5C4 C7404040			2590+ DC HL1' 14'	cc failed mask	
000029BC	00000010			2591+ DC CL8' VCVDG'	instruction name	
000029C0	000029E8			2592+ DC A(16)	result length	
				2593+REA71 DC A(RE71)	result address	
				2594+*	INSTRUCTION UNDER TEST ROUTINE	
000029C4				2595+X71 DS OF		
000029C4	E710 8F48 0006	00001148		2596+ VL V1, V1FUDGE	pollute V1	
000029CA	E320 5050 0004	000029F8		2597+ LG R2, RE71+16	get R2 source	
000029D0	E612 0038 905A			2598+ VCVDG V1, R2, 137, 3	test instruction	
000029D6	E710 8F10 000E	00001110		2599+ VST V1, V1OUTPUT	save	
000029DC	B98D 0020			2600+ EPSW R2, R0	extract psw	
000029E0	5020 8EE8	000010E8		2601+ ST R2, CCPSW	to save CC	
000029E4	07FB			2602+ BR R11	return	
000029E8				2603+RE71 DC OF		
000029E8	00000000 00000000			2604+ DROP R5		
000029F0	00000085 4775808F			2605 DC XL16' 00000000000000000000000000000000854775808F'	V1 source	
000029F8	80000000 00000000			2606 DC XL08' 8000000000000000'	R1 result	
2607					ULONG_MAX	
00002A00		00002A00		2608 VRR_K VCVDG, 137, 3, 0		
00002A00				2609+ DS OFD		
00002A00	00002A1C			2610+ USING *, R5	base for test data and test routine	
				2611+T72 DC A(X72)	address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002A04	0048			2612+ DC H' 72'	test number	
00002A06	00			2613+ DC XL1' 00'		
00002A07	89			2614+ DC HL1' 137'	i 3	
00002A08	03			2615+ DC HL1' 3'	m4	
00002A09	00			2616+ DC HL1' 0'	cc	
00002A0A	07			2617+ DC HL1' 7'	cc failed mask	
00002A0B	E5C3E5C4 C7404040			2618+ DC CL8' VCVDG'	instruction name	
00002A14	00000010			2619+ DC A(16)	result length	
00002A18	00002A40			2620+REA72 DC A(RE72)	result address	
				2621+*	INSTRUCTION UNDER TEST ROUTINE	
				2622+X72 DS OF		
00002A1C	E710 8F48 0006	00001148		2623+ VL V1, V1FUDGE	pollute V1	
00002A22	E320 5050 0004	00002A50		2624+ LG R2, RE72+16	get R2 source	
00002A28	E612 0038 905A			2625+ VCVDG V1, R2, 137, 3	test instruction	
00002A2E	E710 8F10 000E	00001110		2626+ VST V1, V1OUTPUT	save	
00002A34	B98D 0020			2627+ EPSW R2, R0	extract psw	
00002A38	5020 8EE8	000010E8		2628+ ST R2, CCPSW	to save CC	
00002A3C	07FB			2629+ BR R11	return	
00002A40				2630+REA72 DC OF		
00002A40				2631+ DROP R5		
00002A40	00000000 00000000			2632 DC XL16' 000000000000000000000000000000001F'	V1 source	
00002A48	00000000 0000001F			2633 DC XL08' FFFFFFFFFFFFFF'	R1 result	
00002A50	FFFFFFFFFF FFFFFFFF			2634		
				2635 *--		
				2636 * VCVDG m4= 9 (LB=1, P1=0 , CS=1)		
				2637 * i3= 159 (IOM=1, RDC=31)		
				2638		
				2639 VRR_K VCVDG, 159, 9, 0		
00002A58		00002A58		2640+ DS OFD		
00002A58				2641+ USING *, R5	base for test data and test routine	
00002A58	00002A74			2642+T73 DC A(X73)	address of test routine	
00002A5C	0049			2643+ DC H' 73'	test number	
00002A5E	00			2644+ DC XL1' 00'		
00002A5F	9F			2645+ DC HL1' 159'	i 3	
00002A60	09			2646+ DC HL1' 9'	m4	
00002A61	00			2647+ DC HL1' 0'	cc	
00002A62	07			2648+ DC HL1' 7'	cc failed mask	
00002A63	E5C3E5C4 C7404040			2649+ DC CL8' VCVDG'	instruction name	
00002A6C	00000010			2650+ DC A(16)	result length	
00002A70	00002A98			2651+REA73 DC A(RE73)	result address	
				2652+*	INSTRUCTION UNDER TEST ROUTINE	
00002A74				2653+X73 DS OF		
00002A74	E710 8F48 0006	00001148		2654+ VL V1, V1FUDGE	pollute V1	
00002A7A	E320 5050 0004	00002AA8		2655+ LG R2, RE73+16	get R2 source	
00002A80	E612 0099 F05A			2656+ VCVDG V1, R2, 159, 9	test instruction	
00002A86	E710 8F10 000E	00001110		2657+ VST V1, V1OUTPUT	save	
00002A8C	B98D 0020			2658+ EPSW R2, R0	extract psw	
00002A90	5020 8EE8	000010E8		2659+ ST R2, CCPSW	to save CC	
00002A94	07FB			2660+ BR R11	return	
00002A98				2661+REA73 DC OF		
00002A98				2662+ DROP R5		
00002A98	00000000 00000000			2663 DC XL16' 00000000000000000000000000000000C'	V1 result	
00002AA0	00000000 0000000C			2664 DC FD' 0'		
00002AA8	00000000 00000000			2665 DC	R2 source	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002AB0				2666 2667+	VRR_K VCVDG, 159, 9, 0 DS OFD	
00002AB0	00002ACC	00002AB0		2668+ 2669+T74	USING *, R5 DC A(X74)	base for test data and test routine
00002AB4	004A			2670+	DC H' 74'	address of test routine
00002AB6	00			2671+	DC XL1' 00'	test number
00002AB7	9F			2672+	DC HL1' 159'	i3
00002AB8	09			2673+	DC HL1' 9'	m4
00002AB9	00			2674+	DC HL1' 0'	cc
00002ABA	07			2675+	DC HL1' 7'	cc failed mask
00002ABB	E5C3E5C4 C7404040			2676+	DC CL8' VCVDG'	instruction name
00002AC4	00000010			2677+	DC A(16)	result length
00002AC8	00002AF0			2678+REA74 2679+*	DC A(RE74)	result address
						INSTRUCTION UNDER TEST ROUTINE
00002ACC				2680+X74	DS OF	
00002ACC	E710 8F48 0006	00001148		2681+	VL V1, V1FUDGE	pollute V1
00002AD2	E320 5050 0004	00002B00		2682+	LG R2, RE74+16	get R2 source
00002AD8	E612 0099 F05A			2683+	VCVDG V1, R2, 159, 9	test instruction
00002ADE	E710 8F10 000E	00001110		2684+	VST V1, V1OUTPUT	save
00002AE4	B98D 0020			2685+	EPSW R2, R0	extract psw
00002AE8	5020 8EE8	000010E8		2686+	ST R2, CCPSW	to save CC
00002AEC	07FB			2687+	BR R11	return
00002AF0				2688+REA74	DC OF	
00002AF0				2689+	DROP R5	
00002AF0	00000000 00000000			2690	DC XL16' 00000000000000000000000000000001C'	V1 result
00002AF8	00000000 0000001C			2691	DC FD' 1'	R2 source
00002B00	00000000 00000001			2692		
				2693	VRR_K VCVDG, 159, 9, 0	UINT_MAX
00002B08				2694+	DS OFD	
00002B08	00002B24	00002B08		2695+	USING *, R5	base for test data and test routine
00002B08	004B			2696+T75	DC A(X75)	address of test routine
00002B0C	00			2697+	DC H' 75'	test number
00002BOE	9F			2698+	DC XL1' 00'	
00002B0F	09			2699+	DC HL1' 159'	i3
00002B10	00			2700+	DC HL1' 9'	m4
00002B11	07			2701+	DC HL1' 0'	cc
00002B12	E5C3E5C4 C7404040			2702+	DC HL1' 7'	cc failed mask
00002B13	00000010			2703+	DC CL8' VCVDG'	instruction name
00002B1C	00002B48			2704+	DC A(16)	result length
00002B20				2705+REA75	DC A(RE75)	result address
				2706+*		INSTRUCTION UNDER TEST ROUTINE
00002B24				2707+X75	DS OF	
00002B24	E710 8F48 0006	00001148		2708+	VL V1, V1FUDGE	pollute V1
00002B2A	E320 5050 0004	00002B58		2709+	LG R2, RE75+16	get R2 source
00002B30	E612 0099 F05A			2710+	VCVDG V1, R2, 159, 9	test instruction
00002B36	E710 8F10 000E	00001110		2711+	VST V1, V1OUTPUT	save
00002B3C	B98D 0020			2712+	EPSW R2, R0	extract psw
00002B40	5020 8EE8	000010E8		2713+	ST R2, CCPSW	to save CC
00002B44	07FB			2714+	BR R11	return
00002B48				2715+REA75	DC OF	
00002B48				2716+	DROP R5	
00002B48	00000000 00018446			2717	DC XL16' 00000000000018446744073709551615C'	V1 source
00002B50	74407370 9551615C			2718	DC FD' -1'	R2 source
00002B58	FFFFFFFFFF FFFFFFFF			2719		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002B60				2720 2721+ DS	VRR_K VCVDG, 159, 9, 0 OFD	INT_MAX
00002B60		00002B60		2722+ 2723+T76 DC	USING *, R5 A(X76)	base for test data and test routine
00002B60	00002B7C			2724+ DC	H' 76'	address of test routine
00002B64	004C					test number
00002B66	00			2725+ DC	XL1' 00'	
00002B67	9F			2726+ DC	HL1' 159'	i3
00002B68	09			2727+ DC	HL1' 9'	m4
00002B69	00			2728+ DC	HL1' 0'	cc
00002B6A	07			2729+ DC	HL1' 7'	cc failed mask
00002B6B	E5C3E5C4 C7404040			2730+ DC	CL8' VCVDG'	instruction name
00002B74	00000010			2731+ DC	A(16)	result length
00002B78	00002BA0			2732+REA76 DC	A(RE76)	result address
				2733+*		INSTRUCTION UNDER TEST ROUTINE
00002B7C				2734+X76 DS	OF	
00002B7C	E710 8F48 0006	00001148		2735+ VL	V1, V1FUDGE	pollute V1
00002B82	E320 5050 0004	00002BB0		2736+ LG	R2, RE76+16	get R2 source
00002B88	E612 0099 F05A			2737+ VCVDG	V1, R2, 159, 9	test instruction
00002B8E	E710 8F10 000E	00001110		2738+ VST	V1, V1OUTPUT	save
00002B94	B98D 0020			2739+ EPSW	R2, R0	extract psw
00002B98	5020 8EE8	000010E8		2740+ ST	R2, CCPSW	to save CC
00002B9C	07FB			2741+ BR	R11	return
00002BA0				2742+REA76 DC	OF	
00002BA0				2743+ DROP	R5	
00002BA0	00000000 00000000			2744 DC	XL16' 000000000000000000000000000000002147483647C'	V1 result
00002BA8	00000214 7483647C			2745 DC	FD' 2147483647'	R2 source
00002BB0	00000000 7FFFFFFF			2746		
				2747 VRR_K	VCVDG, 159, 9, 0	INT_MIN
00002BB8				2748+ DS	OFD	
00002BB8		00002BB8		2749+ USING	*, R5	base for test data and test routine
00002BB8	00002BD4			2750+T77 DC	A(X77)	address of test routine
00002BBC	004D			2751+ DC	H' 77'	test number
00002BBE	00			2752+ DC	XL1' 00'	
00002BBF	9F			2753+ DC	HL1' 159'	i3
00002BC0	09			2754+ DC	HL1' 9'	m4
00002BC1	00			2755+ DC	HL1' 0'	cc
00002BC2	07			2756+ DC	HL1' 7'	cc failed mask
00002BC3	E5C3E5C4 C7404040			2757+ DC	CL8' VCVDG'	instruction name
00002BCC	00000010			2758+ DC	A(16)	result length
00002BDO	00002BF8			2759+REA77 DC	A(RE77)	result address
				2760+*		INSTRUCTION UNDER TEST ROUTINE
00002BD4				2761+X77 DS	OF	
00002BD4	E710 8F48 0006	00001148		2762+ VL	V1, V1FUDGE	pollute V1
00002BDA	E320 5050 0004	00002C08		2763+ LG	R2, RE77+16	get R2 source
00002BE0	E612 0099 F05A			2764+ VCVDG	V1, R2, 159, 9	test instruction
00002BE6	E710 8F10 000E	00001110		2765+ VST	V1, V1OUTPUT	save
00002BEC	B98D 0020			2766+ EPSW	R2, R0	extract psw
00002BF0	5020 8EE8	000010E8		2767+ ST	R2, CCPSW	to save CC
00002BF4	07FB			2768+ BR	R11	return
00002BF8				2769+REA77 DC	OF	
00002BF8				2770+ DROP	R5	
00002BF8	00000000 00018446			2771 DC	XL16' 00000000000018446744071562067968C'	V1 result
00002C00	74407156 2067968C			2772 DC	XL8' FFFFFFFF80000000'	R2 source
00002C08	FFFFFFFFFF 80000000			2773 * DC	FD' - 2147483648'	R2 sourc

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				2774		
				2775	VRR_K VCVDG, 159, 9, 0	LONG_MAX
00002C10				2776+	DS OFD	
00002C10		00002C10		2777+	USING *, R5	base for test data and test routine
00002C10	00002C2C			2778+T78	DC A(X78)	address of test routine
00002C14	004E			2779+	DC H'78'	test number
00002C16	00			2780+	DC XL1'00'	
00002C17	9F			2781+	DC HL1'159'	i3
00002C18	09			2782+	DC HL1'9'	m4
00002C19	00			2783+	DC HL1'0'	cc
00002C1A	07			2784+	DC HL1'7'	cc failed mask
00002C1B	E5C3E5C4 C7404040			2785+	DC CL8'VCVDG'	instruction name
00002C24	00000010			2786+	DC A(16)	result length
00002C28	00002C50			2787+REA78	DC A(REA78)	result address
				2788+*		INSTRUCTION UNDER TEST ROUTINE
00002C2C				2789+X78	DS OF	
00002C2C	E710 8F48 0006		00001148	2790+	VL V1, V1FUDGE	pollute V1
00002C32	E320 5050 0004		00002C60	2791+	LG R2, RE78+16	get R2 source
00002C38	E612 0099 F05A			2792+	VCVDG V1, R2, 159, 9	test instruction
00002C3E	E710 8F10 000E		00001110	2793+	VST V1, V1OUTPUT	save
00002C44	B98D 0020			2794+	EPSW R2, R0	extract psw
00002C48	5020 8EE8		000010E8	2795+	ST R2, CCPSW	to save CC
00002C4C	07FB			2796+	BR R11	return
00002C50				2797+RE78	DC OF	
00002C50				2798+	DROP R5	
00002C50	00000000 00009223			2799	DC XL16' 0000000000009223372036854775807C'	V1 source
00002C58	37203685 4775807C			2800	DC XL08' 7FFFFFFFFFFFFF'	R1 result
00002C60	7FFFFFFF FFFFFFFF			2801		
				2802	VRR_K VCVDG, 159, 9, 0	LONG_MIN
00002C68				2803+	DS OFD	
00002C68		00002C68		2804+	USING *, R5	base for test data and test routine
00002C68	00002C84			2805+T79	DC A(X79)	address of test routine
00002C6C	004F			2806+	DC H'79'	test number
00002C6E	00			2807+	DC XL1'00'	
00002C6F	9F			2808+	DC HL1'159'	i3
00002C70	09			2809+	DC HL1'9'	m4
00002C71	00			2810+	DC HL1'0'	cc
00002C72	07			2811+	DC HL1'7'	cc failed mask
00002C73	E5C3E5C4 C7404040			2812+	DC CL8'VCVDG'	instruction name
00002C7C	00000010			2813+	DC A(16)	result length
00002C80	00002CA8			2814+REA79	DC A(REA79)	result address
				2815+*		INSTRUCTION UNDER TEST ROUTINE
00002C84				2816+X79	DS OF	
00002C84	E710 8F48 0006		00001148	2817+	VL V1, V1FUDGE	pollute V1
00002C8A	E320 5050 0004		00002CB8	2818+	LG R2, RE79+16	get R2 source
00002C90	E612 0099 F05A			2819+	VCVDG V1, R2, 159, 9	test instruction
00002C96	E710 8F10 000E		00001110	2820+	VST V1, V1OUTPUT	save
00002C9C	B98D 0020			2821+	EPSW R2, R0	extract psw
00002CA0	5020 8EE8		000010E8	2822+	ST R2, CCPSW	to save CC
00002CA4	07FB			2823+	BR R11	return
00002CA8				2824+RE79	DC OF	
00002CA8				2825+	DROP R5	
00002CA8	00000000 00009223			2826	DC XL16' 0000000000009223372036854775808C'	V1 source
00002CB0	37203685 4775808C			2827	DC XL08' 8000000000000000'	R1 result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				2828		
				2829	VRR_K VCVDG, 159, 9, 0	ULONG_MAX
00002CC0				2830+	DS OFD	
00002CC0		00002CC0		2831+	USING *, R5	base for test data and test routine
00002CC0	00002CDC			2832+T80	DC A(X80)	address of test routine
00002CC4	0050			2833+	DC H'80'	test number
00002CC6	00			2834+	DC XL1'00'	
00002CC7	9F			2835+	DC HL1'159'	i3
00002CC8	09			2836+	DC HL1'9'	m4
00002CC9	00			2837+	DC HL1'0'	cc
00002CCA	07			2838+	DC HL1'7'	cc failed mask
00002CCB	E5C3E5C4 C7404040			2839+	DC CL8'VCVDG'	instruction name
00002CD4	00000010			2840+	DC A(16)	result length
00002CD8	00002D00			2841+REA80	DC A(RE80)	result address
				2842+*		INSTRUCTION UNDER TEST ROUTINE
00002CDC				2843+X80	DS OF	
00002CDC	E710 8F48 0006		00001148	2844+	VL V1, V1FUDGE	pollute V1
00002CE2	E320 5050 0004		00002D10	2845+	LG R2, RE80+16	get R2 source
00002CE8	E612 0099 F05A			2846+	VCVDG V1, R2, 159, 9	test instruction
00002CEE	E710 8F10 000E		00001110	2847+	VST V1, V1OUTPUT	save
00002CF4	B98D 0020			2848+	EPSW R2, R0	extract psw
00002CF8	5020 8EE8		000010E8	2849+	ST R2, CCPSW	to save CC
00002CF8	07FB			2850+	BR R11	return
00002D00				2851+RE80	DC OF	
00002D00				2852+	DROP R5	
00002D00	00000000 00018446			2853	DC XL16' 000000000018446744073709551615C'	V1 source
00002D08	74407370 9551615C					
00002D10	FFFFFFFFFF FFFFFFFF			2854	DC XL08' FFFFFFFFFFFFFF'	R1 result
				2855		
				2856 * VCVDG	m4= 9 (LB=1, P1=0 , CS=1)	
				2857 *	i3= 137 (IOM=1, RDC= 9)	
				2858		
00002D18				2859	VRR_K VCVDG, 137, 9, 0	
00002D18		00002D18		2860+	DS OFD	
00002D18	00002D34			2861+	USING *, R5	base for test data and test routine
00002D1C	0051			2862+T81	DC A(X81)	address of test routine
00002D1E	00			2863+	DC H'81'	test number
00002D1F	89			2864+	DC XL1'00'	
00002D20	09			2865+	DC HL1'137'	i3
00002D21	00			2866+	DC HL1'9'	m4
00002D22	07			2867+	DC HL1'0'	cc
00002D23	E5C3E5C4 C7404040			2868+	DC HL1'7'	cc failed mask
00002D2C	00000010			2869+	DC CL8'VCVDG'	instruction name
00002D30	00002D58			2870+	DC A(16)	result length
				2871+REA81	DC A(RE81)	result address
00002D34				2872+*		INSTRUCTION UNDER TEST ROUTINE
00002D34	E710 8F48 0006		00001148	2873+X81	DS OF	
00002D3A	E320 5050 0004		00002D68	2874+	VL V1, V1FUDGE	pollute V1
00002D40	E612 0098 905A			2875+	LG R2, RE81+16	get R2 source
00002D46	E710 8F10 000E		00001110	2876+	VCVDG V1, R2, 137, 9	test instruction
00002D46	E710 8F10 000E			2877+	VST V1, V1OUTPUT	save
00002D4C	B98D 0020			2878+	EPSW R2, R0	extract psw
00002D50	5020 8EE8		000010E8	2879+	ST R2, CCPSW	to save CC
00002D54	07FB			2880+	BR R11	return
00002D58				2881+RE81	DC OF	
00002D58				2882+	DROP R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002D58	00000000 00000000			2883 DC XL16' 00000000000000000000000000000000C'	V1 result	
00002D60	00000000 0000000C			2884 DC FD' 0'	R2 source	
00002D68	00000000 00000000			2885 2886 VRR_K VCVDG, 137, 9, 0		
00002D70				2887+ DS OFD		
00002D70		00002D70		2888+ USING *, R5	base for test data and test routine	
00002D70	00002D8C			2889+T82 DC A(X82)	address of test routine	
00002D74	0052			2890+ DC H' 82'	test number	
00002D76	00			2891+ DC XL1' 00'		
00002D77	89			2892+ DC HL1' 137'	i3	
00002D78	09			2893+ DC HL1' 9'	m4	
00002D79	00			2894+ DC HL1' 0'	cc	
00002D7A	07			2895+ DC HL1' 7'	cc failed mask	
00002D7B	E5C3E5C4 C7404040			2896+ DC CL8' VCVDG'	instruction name	
00002D84	00000010			2897+ DC A(16)	result length	
00002D88	00002DB0			2898+REA82 DC A(RE82)	result address	
				2899+*	INSTRUCTION UNDER TEST ROUTINE	
00002D8C				2900+X82 DS OF		
00002D8C	E710 8F48 0006		00001148	2901+ VL V1, V1FUDGE	pollute V1	
00002D92	E320 5050 0004		00002DC0	2902+ LG R2, RE82+16	get R2 source	
00002D98	E612 0098 905A			2903+ VCVDG V1, R2, 137, 9	test instruction	
00002D9E	E710 8F10 000E		00001110	2904+ VST V1, V1OUTPUT	save	
00002DA4	B98D 0020			2905+ EPSW R2, R0	extract psw	
00002DA8	5020 8EE8		000010E8	2906+ ST R2, CCPSW	to save CC	
00002DAC	07FB			2907+ BR R11	return	
00002DB0				2908+REA82 DC OF		
00002DB0				2909+ DROP R5		
00002DB0	00000000 00000000			2910 DC XL16' 00000000000000000000000000000001C'	V1 result	
00002DB8	00000000 0000001C			2911 DC FD' 1'	R2 source	
00002DC0	00000000 00000001			2912		
				2913 VRR_K VCVDG, 137, 9, 3	UINT_MAX	
00002DC8				2914+ DS OFD		
00002DC8		00002DC8		2915+ USING *, R5	base for test data and test routine	
00002DC8	00002DE4			2916+T83 DC A(X83)	address of test routine	
00002DCC	0053			2917+ DC H' 83'	test number	
00002DCE	00			2918+ DC XL1' 00'		
00002DCF	89			2919+ DC HL1' 137'	i3	
00002DD0	09			2920+ DC HL1' 9'	m4	
00002DD1	03			2921+ DC HL1' 3'	cc	
00002DD2	0E			2922+ DC HL1' 14'	cc failed mask	
00002DD3	E5C3E5C4 C7404040			2923+ DC CL8' VCVDG'	instruction name	
00002DDC	00000010			2924+ DC A(16)	result length	
00002DE0	00002E08			2925+REA83 DC A(RE83)	result address	
				2926+*	INSTRUCTION UNDER TEST ROUTINE	
00002DE4				2927+X83 DS OF		
00002DE4	E710 8F48 0006		00001148	2928+ VL V1, V1FUDGE	pollute V1	
00002DEA	E320 5050 0004		00002E18	2929+ LG R2, RE83+16	get R2 source	
00002DF0	E612 0098 905A			2930+ VCVDG V1, R2, 137, 9	test instruction	
00002DF6	E710 8F10 000E		00001110	2931+ VST V1, V1OUTPUT	save	
00002DFC	B98D 0020			2932+ EPSW R2, R0	extract psw	
00002E00	5020 8EE8		000010E8	2933+ ST R2, CCPSW	to save CC	
00002E04	07FB			2934+ BR R11	return	
00002E08				2935+REA83 DC OF		
00002E08				2936+ DROP R5		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002E08	00000000 00000000			2937 DC XL16' 00000000000000000000000000000000709551615C'	V1 source	
00002E10	00000070 9551615C			2938 DC FD' -1'	R2 source	
00002E18	FFFFFFF FFFFFFFF			2939 2940 VRR_K VCVDG, 137, 9, 3	INT_MAX	
00002E20				2941+ DS OFD		
00002E20		00002E20		2942+ USING *, R5	base for test data and test routine	
00002E20	00002E3C			2943+T84 DC A(X84)	address of test routine	
00002E24	0054			2944+ DC H' 84'	test number	
00002E26	00			2945+ DC XL1' 00'		
00002E27	89			2946+ DC HL1' 137'	i3	
00002E28	09			2947+ DC HL1' 9'	m4	
00002E29	03			2948+ DC HL1' 3'	cc	
00002E2A	0E			2949+ DC HL1' 14'	cc failed mask	
00002E2B	E5C3E5C4 C7404040			2950+ DC CL8' VCVDG'	instruction name	
00002E34	00000010			2951+ DC A(16)	result length	
00002E38	00002E60			2952+REA84 DC A(REA84)	result address	
				2953+*	INSTRUCTION UNDER TEST ROUTINE	
00002E3C				2954+X84 DS OF		
00002E3C	E710 8F48 0006		00001148	2955+ VL V1, V1FUDGE	pollute V1	
00002E42	E320 5050 0004		00002E70	2956+ LG R2, RE84+16	get R2 source	
00002E48	E612 0098 905A			2957+ VCVDG V1, R2, 137, 9	test instruction	
00002E4E	E710 8F10 000E		00001110	2958+ VST V1, V1OUTPUT	save	
00002E54	B98D 0020			2959+ EPSW R2, R0	extract psw	
00002E58	5020 8EE8		000010E8	2960+ ST R2, CCPSW	to save CC	
00002E5C	07FB			2961+ BR R11	return	
00002E60				2962+REA84 DC OF		
00002E60				2963+ DROP R5		
00002E60	00000000 00000000			2964 DC XL16' 00000000000000000000000000000000147483647C'	V1 result	
00002E68	00000014 7483647C			2965 DC FD' 2147483647'	R2 source	
00002E70	00000000 7FFFFFFF			2966		
				2967 VRR_K VCVDG, 137, 9, 3	INT_MIN	
00002E78				2968+ DS OFD		
00002E78		00002E78		2969+ USING *, R5	base for test data and test routine	
00002E78	00002E94			2970+T85 DC A(X85)	address of test routine	
00002E7C	0055			2971+ DC H' 85'	test number	
00002E7E	00			2972+ DC XL1' 00'		
00002E7F	89			2973+ DC HL1' 137'	i3	
00002E80	09			2974+ DC HL1' 9'	m4	
00002E81	03			2975+ DC HL1' 3'	cc	
00002E82	0E			2976+ DC HL1' 14'	cc failed mask	
00002E83	E5C3E5C4 C7404040			2977+ DC CL8' VCVDG'	instruction name	
00002E8C	00000010			2978+ DC A(16)	result length	
00002E90	00002EB8			2979+REA85 DC A(REA85)	result address	
				2980+*	INSTRUCTION UNDER TEST ROUTINE	
00002E94				2981+X85 DS OF		
00002E94	E710 8F48 0006		00001148	2982+ VL V1, V1FUDGE	pollute V1	
00002E9A	E320 5050 0004		00002EC8	2983+ LG R2, RE85+16	get R2 source	
00002EA0	E612 0098 905A			2984+ VCVDG V1, R2, 137, 9	test instruction	
00002EA6	E710 8F10 000E		00001110	2985+ VST V1, V1OUTPUT	save	
00002EAC	B98D 0020			2986+ EPSW R2, R0	extract psw	
00002EB0	5020 8EE8		000010E8	2987+ ST R2, CCPSW	to save CC	
00002EB4	07FB			2988+ BR R11	return	
00002EB8				2989+REA85 DC OF		
00002EB8				2990+ DROP R5		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002EB8	00000000 00000000			2991 DC XL16' 00000000000000000000000000000000562067968C'	V1 result	
00002EC0	00000056 2067968C			2992 DC FD' -2147483648'		
00002EC8	FFFFFFF8 80000000			2993 2994 VRR_K VCVDG, 137, 9, 3		LONG_MAX
00002ED0				2995+ DS OFD		
00002ED0		00002ED0		2996+ USING *, R5	base for test data and test routine	
00002ED0	00002EEC			2997+T86 DC A(X86)	address of test routine	
00002ED4	0056			2998+ DC H'86'	test number	
00002ED6	00			2999+ DC XL1'00'		
00002ED7	89			3000+ DC HL1'137'	i3	
00002ED8	09			3001+ DC HL1'9'	m4	
00002ED9	03			3002+ DC HL1'3'	cc	
00002EDA	0E			3003+ DC HL1'14'	cc failed mask	
00002EDB	E5C3E5C4 C7404040			3004+ DC CL8'VCVDG'	instruction name	
00002EE4	00000010			3005+ DC A(16)	result length	
00002EE8	00002F10			3006+REA86 DC A(REA86)	result address	
				3007+*	INSTRUCTION UNDER TEST ROUTINE	
00002EEC				3008+X86 DS OF		
00002EEC	E710 8F48 0006		00001148	3009+ VL V1, V1FUDGE	pollute V1	
00002EF2	E320 5050 0004		00002F20	3010+ LG R2, RE86+16	get R2 source	
00002EF8	E612 0098 905A			3011+ VCVDG V1, R2, 137, 9	test instruction	
00002EFE	E710 8F10 000E		00001110	3012+ VST V1, V1OUTPUT	save	
00002F04	B98D 0020			3013+ EPSW R2, R0	extract psw	
00002F08	5020 8EE8		000010E8	3014+ ST R2, CCPSW	to save CC	
00002F0C	07FB			3015+ BR R11	return	
00002F10				3016+REA86 DC OF		
00002F10				3017+ DROP R5		
00002F10	00000000 00000000			3018 DC XL16' 00000000000000000000000000000000854775807C'	V1 source	
00002F18	00000085 4775807C			3019 DC XL08' 7FFFFFFFFFFFF'	R1 result	
00002F20	7FFFFFFF FFFFFFFF			3020		
				3021 VRR_K VCVDG, 137, 9, 3	LONG_MIN	
00002F28				3022+ DS OFD		
00002F28		00002F28		3023+ USING *, R5	base for test data and test routine	
00002F28	00002F44			3024+T87 DC A(X87)	address of test routine	
00002F2C	0057			3025+ DC H'87'	test number	
00002F2E	00			3026+ DC XL1'00'		
00002F2F	89			3027+ DC HL1'137'	i3	
00002F30	09			3028+ DC HL1'9'	m4	
00002F31	03			3029+ DC HL1'3'	cc	
00002F32	0E			3030+ DC HL1'14'	cc failed mask	
00002F33	E5C3E5C4 C7404040			3031+ DC CL8'VCVDG'	instruction name	
00002F3C	00000010			3032+ DC A(16)	result length	
00002F40	00002F68			3033+REA87 DC A(REA87)	result address	
				3034+*	INSTRUCTION UNDER TEST ROUTINE	
00002F44				3035+X87 DS OF		
00002F44	E710 8F48 0006		00001148	3036+ VL V1, V1FUDGE	pollute V1	
00002F4A	E320 5050 0004		00002F78	3037+ LG R2, RE87+16	get R2 source	
00002F50	E612 0098 905A			3038+ VCVDG V1, R2, 137, 9	test instruction	
00002F56	E710 8F10 000E		00001110	3039+ VST V1, V1OUTPUT	save	
00002F5C	B98D 0020			3040+ EPSW R2, R0	extract psw	
00002F60	5020 8EE8		000010E8	3041+ ST R2, CCPSW	to save CC	
00002F64	07FB			3042+ BR R11	return	
00002F68				3043+REA87 DC OF		
00002F68				3044+ DROP R5		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002F68	00000000 00000000			3045 DC XL16' 00000000000000000000000000000000854775808C'	V1 source	
00002F70	00000085 4775808C			3046 DC XL08' 8000000000000000'	R1 result	
00002F78	80000000 00000000			3047 3048 VRR_K VCVDG, 137, 9, 3	ULONG_MAX	
00002F80				3049+ DS OFD		
00002F80		00002F80		3050+ USING *, R5	base for test data and test routine	
00002F80	00002F9C			3051+T88 DC A(X88)	address of test routine	
00002F84	0058			3052+ DC H' 88'	test number	
00002F86	00			3053+ DC XL1' 00'		
00002F87	89			3054+ DC HL1' 137'	i3	
00002F88	09			3055+ DC HL1' 9'	m4	
00002F89	03			3056+ DC HL1' 3'	cc	
00002F8A	0E			3057+ DC HL1' 14'	cc failed mask	
00002F8B	E5C3E5C4 C7404040			3058+ DC CL8' VCVDG'	instruction name	
00002F94	00000010			3059+ DC A(16)	result length	
00002F98	00002FC0			3060+REA88 DC A(REA88)	result address	
00002F9C				3061+*	INSTRUCTION UNDER TEST ROUTINE	
00002F9C	E710 8F48 0006		00001148	3062+X88 DS OF		
00002FA2	E320 5050 0004		00002FD0	3063+ VL V1, V1FUDGE	pollute V1	
00002FA8	E612 0098 905A			3064+ LG R2, RE88+16	get R2 source	
00002FAE	E710 8F10 000E		00001110	3065+ VCVDG V1, R2, 137, 9	test instruction	
00002FB4	B98D 0020			3066+ VST V1, V1OUTPUT	save	
00002FB8	5020 8EE8		000010E8	3067+ EPSW R2, R0	extract psw	
00002FBC	07FB			3068+ ST R2, CCPSW	to save CC	
00002FC0				3069+ BR R11	return	
00002FC0				3070+REA88 DC OF		
00002FC0	00000000 00000000			3071+ DROP R5		
00002FC0				3072 DC XL16' 00000000000000000000000000000000709551615C'	V1 source	
00002FC8	00000070 9551615C			3073 DC XL08' FFFFFFFFFFFFFF'	R1 result	
00002FD0	FFFFFFFFFF FFFFFFFF			3074		
00002FD0				3075 *-----		
00002FD0				3076 * VCVDG m4= 11 (LB=1, P1=1 , CS=1)		
00002FD0				3077 * i3= 159 (IOM=1, RDC=31)		
00002FD8				3078		
00002FD8		00002FD8		3079 VRR_K VCVDG, 159, 11, 0		
00002FD8	00002FF4			3080+ DS OFD		
00002FD8	0059			3081+ USING *, R5	base for test data and test routine	
00002FDC				3082+T89 DC A(X89)	address of test routine	
00002FDE	00			3083+ DC H' 89'	test number	
00002FDF	9F			3084+ DC XL1' 00'		
00002FE0	OB			3085+ DC HL1' 159'	i3	
00002FE1	00			3086+ DC HL1' 11'	m4	
00002FE2	07			3087+ DC HL1' 0'	cc	
00002FE3	E5C3E5C4 C7404040			3088+ DC HL1' 7'	cc failed mask	
00002FEC	00000010			3089+ DC CL8' VCVDG'	instruction name	
00002FF0	00003018			3090+ DC A(16)	result length	
00002FF0				3091+REA89 DC A(REA89)	result address	
00002FF0				3092+*	INSTRUCTION UNDER TEST ROUTINE	
00002FF4				3093+X89 DS OF		
00002FF4	E710 8F48 0006		00001148	3094+ VL V1, V1FUDGE	pollute V1	
00002FFA	E320 5050 0004		00003028	3095+ LG R2, RE89+16	get R2 source	
00003000	E612 00B9 F05A			3096+ VCVDG V1, R2, 159, 11	test instruction	
00003006	E710 8F10 000E		00001110	3097+ VST V1, V1OUTPUT	save	
0000300C	B98D 0020			3098+ EPSW R2, R0	extract psw	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000030C0	5020 8EE8		000010E8	3153+ 3154+	ST BR	R2, CCPSW R11	to save CC return
000030C4	07FB			3155+RE91	DC	OF	
000030C8				3156+	DROP	R5	
000030C8	00000000 00018446			3157	DC	XL16' 00000000000018446744073709551615F'	V1 source
000030D0	74407370 9551615F			3158	DC	FD' - 1'	
000030D8	FFFFFFF FFFFFFFF			3159			R2 source
000030E0				3160	VRR_K	VCVDG, 159, 11, 0	INT_MAX
000030E0		000030E0		3161+	DS	OFD	
000030E0	000030FC			3162+	USING	* , R5	base for test data and test routine
000030E4	005C			3163+T92	DC	A(X92)	address of test routine
000030E6	00			3164+	DC	H' 92'	test number
000030E7	9F			3165+	DC	XL1' 00'	
000030E8	OB			3166+	DC	HL1' 159'	i3
000030E9	00			3167+	DC	HL1' 11'	m4
000030EA	07			3168+	DC	HL1' 0'	cc
000030EB	E5C3E5C4 C7404040			3169+	DC	HL1' 7'	cc failed mask
000030F4	00000010			3170+	DC	CL8' VCVDG'	instruction name
000030F8	00003120			3171+	DC	A(16)	result length
000030FC				3172+REA92	DC	A(RE92)	result address
000030FC				3173+*			INSTRUCTION UNDER TEST ROUTINE
000030FC				3174+X92	DS	OF	
00003102	E710 8F48 0006	00001148		3175+	VL	V1, V1FUDGE	pollute V1
00003102	E320 5050 0004	00003130		3176+	LG	R2, RE92+16	get R2 source
00003108	E612 00B9 F05A			3177+	VCVDG	V1, R2, 159, 11	test instruction
0000310E	E710 8F10 000E	00001110		3178+	VST	V1, V1OUTPUT	save
00003114	B98D 0020			3179+	EPSW	R2, R0	extract psw
00003118	5020 8EE8	000010E8		3180+	ST	R2, CCPSW	to save CC
0000311C	07FB			3181+	BR	R11	return
00003120				3182+RE92	DC	OF	
00003120				3183+	DROP	R5	
00003120	00000000 00000000			3184	DC	XL16' 000000000000000000000000000000002147483647F'	V1 result
00003128	00000214 7483647F			3185	DC	FD' 2147483647'	R2 source
00003130	00000000 7FFFFFFF			3186			
00003138				3187	VRR_K	VCVDG, 159, 11, 0	INT_MIN
00003138		00003138		3188+	DS	OFD	
00003138	00003154			3189+	USING	* , R5	base for test data and test routine
0000313C	005D			3190+T93	DC	A(X93)	address of test routine
0000313E	00			3191+	DC	H' 93'	test number
0000313F	9F			3192+	DC	XL1' 00'	
00003140	OB			3193+	DC	HL1' 159'	i3
00003141	00			3194+	DC	HL1' 11'	m4
00003142	07			3195+	DC	HL1' 0'	cc
00003143	E5C3E5C4 C7404040			3196+	DC	HL1' 7'	cc failed mask
0000314C	00000010			3197+	DC	CL8' VCVDG'	instruction name
00003150	00003178			3198+	DC	A(16)	result length
00003154				3199+REA93	DC	A(RE93)	result address
00003154				3200+*			INSTRUCTION UNDER TEST ROUTINE
00003154	E710 8F48 0006	00001148		3201+X93	DS	OF	
0000315A	E320 5050 0004	00003188		3202+	VL	V1, V1FUDGE	pollute V1
00003160	E612 00B9 F05A			3203+	LG	R2, RE93+16	get R2 source
00003166	E710 8F10 000E	00001110		3204+	VCVDG	V1, R2, 159, 11	test instruction
0000316C	B98D 0020			3205+	VST	V1, V1OUTPUT	save
0000316C				3206+	EPSW	R2, R0	extract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003170	5020 8EE8		000010E8	3207+ 3208+ 3209+RE93 3210+ 3211	ST BR DC DROP DC	R2, CCPSW R11 OF R5 XL16' 00000000000018446744071562067968F'	to save CC return V1 result
00003174	07FB			3212 3213 *	DC DC	XL8' FFFFFFFF80000000' FD' -2147483648'	R2 source R2 sourc
00003178				3214 3215 3216+	VRR_K DS	VCVDG, 159, 11, 0 OFD	LONG_MAX
00003178				3217+ 3218+T94 3219+	USING DC	* , R5 A(X94) H' 94'	base for test data and test routine address of test routine test number
00003178	00000000 00018446			3220+	DC	XL1' 00'	
00003180	74407156 2067968F			3221+	DC	HL1' 159'	i 3
00003188	FFFFFFFFFF 80000000			3222+	DC	HL1' 11'	m4
00003188				3223+	DC	HL1' 0'	cc
00003190		00003190		3224+	DC	HL1' 7'	cc failed mask
00003190	000031AC			3225+	DC	CL8' VCVDG'	instruction name
00003194	005E			3226+	DC	A(16)	result length
00003196	00			3227+REA94	DC	A(REA94)	result address
00003197	9F			3228+*			INSTRUCTION UNDER TEST ROUTINE
00003198	OB						
00003199	00						
0000319A	07						
0000319B	E5C3E5C4 C7404040						
000031A4	00000010						
000031A8	000031D0						
000031AC							
000031AC	E710 8F48 0006		00001148	3229+X94 3230+	DS VL	OF V1, V1FUDGE	pollute V1
000031B2	E320 5050 0004		000031E0	3231+	LG	R2, RE94+16	get R2 source
000031B8	E612 00B9 F05A			3232+	VCVDG	V1, R2, 159, 11	test instruction
000031BE	E710 8F10 000E		00001110	3233+	VST	V1, V1OUTPUT	save
000031C4	B98D 0020			3234+	EPSW	R2, R0	extract psw
000031C8	5020 8EE8		000010E8	3235+	ST	R2, CCPSW	to save CC
000031CC	07FB			3236+	BR	R11	return
000031D0				3237+REA94	DC	OF	
000031D0	00000000 00009223			3238+	DROP	R5	
000031D8	37203685 4775807F			3239	DC	XL16' 0000000000009223372036854775807F'	V1 source
000031E0	7FFFFFFF FFFFFFFF			3240 3241	DC	XL08' 7FFFFFFFFFFFFFF'	R1 result
000031E0				3242	VRR_K	VCVDG, 159, 11, 0	LONG_MIN
000031E8				3243+	DS	OFD	
000031E8	00003204	000031E8		3244+ 3245+T95	USING DC	* , R5 A(X95)	base for test data and test routine address of test routine test number
000031EC	005F			3246+	DC	H' 95'	
000031EE	00			3247+	DC	XL1' 00'	
000031EF	9F			3248+	DC	HL1' 159'	i 3
000031F0	OB			3249+	DC	HL1' 11'	m4
000031F1	00			3250+	DC	HL1' 0'	cc
000031F2	07			3251+	DC	HL1' 7'	cc failed mask
000031F3	E5C3E5C4 C7404040			3252+	DC	CL8' VCVDG'	instruction name
000031FC	00000010			3253+	DC	A(16)	result length
00003200	00003228			3254+REA95	DC	A(REA95)	result address
00003200				3255+*			INSTRUCTION UNDER TEST ROUTINE
00003204							
00003204	E710 8F48 0006		00001148	3256+X95 3257+	DS VL	OF V1, V1FUDGE	pollute V1
0000320A	E320 5050 0004		00003238	3258+	LG	R2, RE95+16	get R2 source
00003210	E612 00B9 F05A			3259+	VCVDG	V1, R2, 159, 11	test instruction
00003216	E710 8F10 000E		00001110	3260+	VST	V1, V1OUTPUT	save

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
0000321C	B98D 0020			3261+ EPSW R2, R0				
00003220	5020 8EE8		000010E8	3262+ ST R2, CCPSW				
00003224	07FB			3263+ BR R11				
00003228				3264+RE95 DC OF				
00003228				3265+ DROP R5				
00003228	00000000 00009223			3266 DC XL16' 0000000000009223372036854775808F'	V1 source			
00003230	37203685 4775808F			3267 DC XL08' 8000000000000000'		R1 result		
00003238	80000000 00000000			3268				
				3269 VRR_K VCVDG, 159, 11, 0		ULONG_MAX		
00003240				3270+ DS OFD				
00003240	0000325C	00003240		3271+ USING *, R5		base for test data and test routine		
00003240	0060			3272+T96 DC A(X96)		address of test routine		
00003244	00			3273+ DC H'96'		test number		
00003246	9F			3274+ DC XL1' 00'				
00003247	OB			3275+ DC HL1' 159'	i3			
00003248	00			3276+ DC HL1' 11'	m4			
00003249	07			3277+ DC HL1' 0'	cc			
0000324A	E5C3E5C4 C7404040			3278+ DC HL1' 7'	cc failed mask			
0000324B	00000010			3279+ DC CL8' VCVDG'	instruction name			
00003254	00003280			3280+ DC A(16)	result length			
00003258	00000010			3281+REA96 DC A(REA96)	result address			
				3282+*		INSTRUCTION UNDER TEST ROUTINE		
0000325C				3283+X96 DS OF				
0000325C	E710 8F48 0006		00001148	3284+ VL V1, V1FUDGE		pollute V1		
00003262	E320 5050 0004		00003290	3285+ LG R2, RE96+16		get R2 source		
00003268	E612 00B9 F05A			3286+ VCVDG V1, R2, 159, 11		test instruction		
0000326E	E710 8F10 000E		00001110	3287+ VST V1, V1OUTPUT		save		
00003274	B98D 0020			3288+ EPSW R2, R0		extract psw		
00003278	5020 8EE8		000010E8	3289+ ST R2, CCPSW		to save CC		
0000327C	07FB			3290+ BR R11		return		
00003280				3291+REA96 DC OF				
00003280	00000000 00018446			3292+ DROP R5				
00003288	74407370 9551615F			3293 DC XL16' 00000000000018446744073709551615F'	V1 source			
00003290	FFFFFF FFFFFFFF			3294 DC XL08' FFFFFFFFFFFFFF'		R1 result		
				3295				
				3296 * VCVDG m4= 11 (LB=1, P1=1 , CS=1)				
				3297 * i3= 137 (IOM=1, RDC= 9)				
				3298				
				3299 VRR_K VCVDG, 137, 11, 0				
00003298				3300+ DS OFD				
00003298	000032B4	00003298		3301+ USING *, R5		base for test data and test routine		
00003298	0061			3302+T97 DC A(X97)		address of test routine		
0000329C	00			3303+ DC H'97'		test number		
0000329E	89			3304+ DC XL1' 00'				
0000329F	OB			3305+ DC HL1' 137'	i3			
000032A0	00			3306+ DC HL1' 11'	m4			
000032A1	07			3307+ DC HL1' 0'	cc			
000032A2	E5C3E5C4 C7404040			3308+ DC HL1' 7'	cc failed mask			
000032A3	00000010			3309+ DC CL8' VCVDG'	instruction name			
000032AC	000032D8			3310+ DC A(16)	result length			
000032B0	00000010			3311+REA97 DC A(REA97)	result address			
				3312+*		INSTRUCTION UNDER TEST ROUTINE		
000032B4	000032B4	E710 8F48 0006	00001148	3313+X97 DS OF				
				3314+ VL V1, V1FUDGE		pollute V1		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000032BA	E320 5050 0004		000032E8	3315+ 3316+	LG VCVDG	R2, RE97+16 V1, R2, 137, 11	get R2 source test instruction
000032C0	E612 00B8 905A			00001110	3317+ 3318+	VST EPSW	V1, V1OUTPUT R2, R0
000032C6	E710 8F10 000E			000010E8	3319+	ST	extract psw to save CC
000032CC	B98D 0020				3320+ 3321+RE97 3322+	BR DC DROP	return
000032D0	5020 8EE8				3323	DC	XL16' 00000000000000000000000000000000F' V1 result
000032D4	07FB				3324	DC	FD' 0' R2 source
000032D8	00000000 00000000				3325		
000032E0	00000000 0000000F				3326	VRR_K	VCVDG, 137, 11, 0
000032E8	00000000 00000000				3327+	DS	OFD
000032F0	0000330C	000032F0			3328+	USING	* , R5 base for test data and test routine
000032F0	0062				3329+T98	DC	A(X98) address of test routine
000032F4					3330+	DC	H' 98' test number
000032F6	00				3331+	DC	XL1' 00'
000032F7	89				3332+	DC	HL1' 137'
000032F8	OB				3333+	DC	HL1' 11'
000032F9	00				3334+	DC	HL1' 0'
000032FA	07				3335+	DC	HL1' 7'
000032FB	E5C3E5C4 C7404040				3336+	DC	CL8' VCVDG' instruction name
00003304	00000010				3337+	DC	A(16) result length
00003308	00003330				3338+REA98	DC	A(REA98) result address
00003308					3339+*		INSTRUCTION UNDER TEST ROUTINE
0000330C					3340+X98	DS	OF
0000330C	E710 8F48 0006		00001148	3341+	VL	V1, V1FUDGE	pollute V1
00003312	E320 5050 0004		00003340	3342+	LG	R2, RE98+16	get R2 source
00003318	E612 00B8 905A			3343+	VCVDG	V1, R2, 137, 11	test instruction
0000331E	E710 8F10 000E		00001110	3344+	VST	V1, V1OUTPUT	save
00003324	B98D 0020			3345+	EPSW	R2, R0	extract psw
00003328	5020 8EE8		000010E8	3346+	ST	R2, CCPFW	to save CC
0000332C	07FB			3347+	BR	R11	return
00003330	00000000 00000000			3348+REA98	DC	OF	
00003330	00000000 0000001F				3349+	DROP	R5
00003330	00000000 00000001				3350	DC	XL16' 00000000000000000000000000000001F' V1 result
00003338					3351	DC	FD' 1' R2 source
00003340					3352		
00003340					3353	VRR_K	VCVDG, 137, 11, 3 UINT_MAX
00003348		00003348			3354+	DS	OFD
00003348	00003364				3355+	USING	* , R5 base for test data and test routine
00003348					3356+T99	DC	A(X99) address of test routine
0000334C	0063				3357+	DC	H' 99' test number
0000334E	00				3358+	DC	XL1' 00'
0000334F	89				3359+	DC	HL1' 137'
00003350	OB				3360+	DC	HL1' 11'
00003351	03				3361+	DC	HL1' 3'
00003352	OE				3362+	DC	HL1' 14'
00003353	E5C3E5C4 C7404040				3363+	DC	CL8' VCVDG' instruction name
0000335C	00000010				3364+	DC	A(16) result length
00003360	00003388				3365+REA99	DC	A(REA99) result address
00003364					3366+*		INSTRUCTION UNDER TEST ROUTINE
00003364	E710 8F48 0006		00001148	3367+X99	DS	OF	
00003364					3368+	VL	V1, V1FUDGE pollute V1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000336A	E320 5050 0004		00003398	3369+ 3370+	LG VCVGDG	R2, RE99+16 V1, R2, 137, 11	get R2 source test instruction
00003370	E612 00B8 905A		00001110	3371+ 3372+	VST EPSW	V1, V1OUTPUT R2, R0	save extract psw
00003376	E710 8F10 000E		000010E8	3373+	ST	R2, CCPSW	to save CC
0000337C	B98D 0020				BR	R11	return
00003380	5020 8EE8				DC	OF	
00003384	07FB				DROP	R5	
00003388	00000000 00000000			3377	DC	XL16' 000000000000000000000000709551615F'	V1 source
00003390	00000070 9551615F			3378	DC	FD' - 1'	R2 source
00003398	FFFFFF FFFFFFFF			3379			
				3380	VRR_K	VCVDG, 137, 11, 3	INT_MAX
000033A0		000033A0		3381+	DS	OFD	
000033A0	000033BC			3382+	USING	* , R5	base for test data and test routine
000033A0	0064			3383+T100	DC	A(X100)	address of test routine
000033A4				3384+	DC	H' 100'	test number
000033A6	00			3385+	DC	XL1' 00'	
000033A7	89			3386+	DC	HL1' 137'	i3
000033A8	0B			3387+	DC	HL1' 11'	m4
000033A9	03			3388+	DC	HL1' 3'	cc
000033AA	OE			3389+	DC	HL1' 14'	cc failed mask
000033AB	E5C3E5C4 C7404040			3390+	DC	CL8' VCVDG'	instruction name
000033B4	00000010			3391+	DC	A(16)	result length
000033B8	000033E0			3392+REA100	DC	A(RE100)	result address
				3393+*			INSTRUCTION UNDER TEST ROUTINE
000033BC				3394+X100	DS	OF	
000033BC	E710 8F48 0006		00001148	3395+	VL	V1, V1FUDGE	pollute V1
000033C2	E320 5050 0004		000033F0	3396+	LG	R2, RE100+16	get R2 source
000033C8	E612 00B8 905A			3397+	VCVDG	V1, R2, 137, 11	test instruction
000033CE	E710 8F10 000E		00001110	3398+	VST	V1, V1OUTPUT	save
000033D4	B98D 0020			3399+	EPSW	R2, R0	extract psw
000033D8	5020 8EE8		000010E8	3400+	ST	R2, CCPSW	to save CC
000033DC	07FB			3401+	BR	R11	return
000033E0				3402+RE100	DC	OF	
000033E0	00000000 00000000			3403+	DROP	R5	
000033E0				3404	DC	XL16' 000000000000000000000000147483647F'	V1 result
000033E8	00000014 7483647F						
000033F0	00000000 7FFFFFFF			3405	DC	FD' 2147483647'	R2 source
				3406			
				3407	VRR_K	VCVDG, 137, 11, 3	INT_MIN
000033F8		000033F8		3408+	DS	OFD	
000033F8	00003414			3409+	USING	* , R5	base for test data and test routine
000033F8				3410+T101	DC	A(X101)	address of test routine
000033FC	0065			3411+	DC	H' 101'	test number
000033FE	00			3412+	DC	XL1' 00'	
000033FF	89			3413+	DC	HL1' 137'	i3
00003400	0B			3414+	DC	HL1' 11'	m4
00003401	03			3415+	DC	HL1' 3'	cc
00003402	OE			3416+	DC	HL1' 14'	cc failed mask
00003403	E5C3E5C4 C7404040			3417+	DC	CL8' VCVDG'	instruction name
0000340C	00000010			3418+	DC	A(16)	result length
00003410	00003438			3419+REA101	DC	A(RE101)	result address
				3420+*			INSTRUCTION UNDER TEST ROUTINE
00003414				3421+X101	DS	OF	
00003414	E710 8F48 0006		00001148	3422+	VL	V1, V1FUDGE	pollute V1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
0000341A	E320 5050 0004		00003448	3423+ 3424+	LG VCVDG	R2, RE101+16 V1, R2, 137, 11	get R2 source test instruction	
00003420	E612 00B8 905A		00001110	3425+ 3426+	VST EPSW	V1, V10OUTPUT R2, R0	save extract psw	
00003426	E710 8F10 000E		000010E8	3427+	ST	R2, CCPSW	to save CC	
0000342C	B98D 0020							
00003430	5020 8EE8							
00003434	07FB			3428+	BR	R11	return	
00003438				3429+RE101	DC	OF		
00003438				3430+	DROP	R5		
00003438	00000000 00000000			3431	DC	XL16' 000000000000000000000000562067968F'	V1 result	
00003440	00000056 2067968F			3432	DC	XL8' FFFFFFFF80000000'		R2 source
00003448	FFFFFFF 80000000			3433 *	DC	FD' -2147483648'		R2 sourc
				3434				
				3435	VRR_K	VCVDG, 137, 11, 3	LONG_MAX	
00003450				3436+	DS	OFD		
00003450		00003450		3437+	USING	* , R5	base for test data and test routine	
00003450	0000346C			3438+T102	DC	A(X102)	address of test routine	
00003454	0066			3439+	DC	H' 102'	test number	
00003456	00			3440+	DC	XL1' 00'		
00003457	89			3441+	DC	HL1' 137'	i 3	
00003458	0B			3442+	DC	HL1' 11'	m4	
00003459	03			3443+	DC	HL1' 3'	cc	
0000345A	0E			3444+	DC	HL1' 14'	cc failed mask	
0000345B	E5C3E5C4 C7404040			3445+	DC	CL8' VCVDG'	instruction name	
00003464	00000010			3446+	DC	A(16)	result length	
00003468	00003490			3447+REA102	DC	A(RE102)	result address	
				3448+*			INSTRUCTION UNDER TEST ROUTINE	
0000346C				3449+X102	DS	OF		
0000346C	E710 8F48 0006		00001148	3450+	VL	V1, V1FUDGE	pollute V1	
00003472	E320 5050 0004		000034A0	3451+	LG	R2, RE102+16	get R2 source	
00003478	E612 00B8 905A			3452+	VCVDG	V1, R2, 137, 11	test instruction	
0000347E	E710 8F10 000E		00001110	3453+	VST	V1, V10OUTPUT	save	
00003484	B98D 0020			3454+	EPSW	R2, R0	extract psw	
00003488	5020 8EE8		000010E8	3455+	ST	R2, CCPSW	to save CC	
0000348C	07FB			3456+	BR	R11	return	
00003490				3457+RE102	DC	OF		
00003490				3458+	DROP	R5		
00003490	00000000 00000000			3459	DC	XL16' 000000000000000000000000854775807F'	V1 source	
00003498	00000085 4775807F							
000034A0	7FFFFFF FFFFFFF			3460	DC	XL08' 7FFFFFFFFFFFF'	R1 result	
				3461				
				3462	VRR_K	VCVDG, 137, 11, 3	LONG_MIN	
000034A8				3463+	DS	OFD		
000034A8		000034A8		3464+	USING	* , R5	base for test data and test routine	
000034A8	000034C4			3465+T103	DC	A(X103)	address of test routine	
000034AC	0067			3466+	DC	H' 103'	test number	
000034AE	00			3467+	DC	XL1' 00'		
000034AF	89			3468+	DC	HL1' 137'	i 3	
000034B0	0B			3469+	DC	HL1' 11'	m4	
000034B1	03			3470+	DC	HL1' 3'	cc	
000034B2	0E			3471+	DC	HL1' 14'	cc failed mask	
000034B3	E5C3E5C4 C7404040			3472+	DC	CL8' VCVDG'	instruction name	
000034BC	00000010			3473+	DC	A(16)	result length	
000034C0	000034E8			3474+REA103	DC	A(RE103)	result address	
				3475+*			INSTRUCTION UNDER TEST ROUTINE	
000034C4				3476+X103	DS	OF		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000034C4	E710 8F48 0006		00001148	3477+	VL	V1, V1FUDGE	
000034CA	E320 5050 0004		000034F8	3478+	LG	R2, RE103+16	pollute V1 get R2 source
000034D0	E612 00B8 905A			3479+	VCVDG	V1, R2, 137, 11	test instruction
000034D6	E710 8F10 000E		00001110	3480+	VST	V1, V1OUTPUT	save
000034DC	B98D 0020			3481+	EPSW	R2, R0	extract psw
000034E0	5020 8EE8		000010E8	3482+	ST	CCPSW	to save CC
000034E4	07FB			3483+	BR	R11	return
000034E8				3484+RE103	DC	OF	
000034E8				3485+	DROP	R5	
000034E8	00000000 00000000			3486	DC	XL16' 000000000000000000000000854775808F'	V1 source
000034F0	00000085 4775808F						
000034F8	80000000 00000000			3487	DC	XL08' 8000000000000000'	R1 result
				3488			
				3489	VRR_K	VCVDG, 137, 11, 3	ULONG_MAX
00003500				3490+	DS	OFD	
00003500		00003500		3491+	USING	*, R5	base for test data and test routine
00003500	0000351C			3492+T104	DC	A(X104)	address of test routine
00003504	0068			3493+	DC	H' 104'	test number
00003506	00			3494+	DC	XL1' 00'	
00003507	89			3495+	DC	HL1' 137'	i3
00003508	0B			3496+	DC	HL1' 11'	m4
00003509	03			3497+	DC	HL1' 3'	cc
0000350A	0E			3498+	DC	HL1' 14'	cc failed mask
0000350B	E5C3E5C4 C7404040			3499+	DC	CL8' VCVDG'	instruction name
00003514	00000010			3500+	DC	A(16)	result length
00003518	00003540			3501+REA104	DC	A(REA104)	result address
				3502+*			INSTRUCTION UNDER TEST ROUTINE
0000351C				3503+X104	DS	OF	
0000351C	E710 8F48 0006		00001148	3504+	VL	V1, V1FUDGE	pollute V1
00003522	E320 5050 0004		00003550	3505+	LG	R2, RE104+16	get R2 source
00003528	E612 00B8 905A			3506+	VCVDG	V1, R2, 137, 11	test instruction
0000352E	E710 8F10 000E		00001110	3507+	VST	V1, V1OUTPUT	save
00003534	B98D 0020			3508+	EPSW	R2, R0	extract psw
00003538	5020 8EE8		000010E8	3509+	ST	CCPSW	to save CC
0000353C	07FB			3510+	BR	R11	return
00003540				3511+RE104	DC	OF	
00003540				3512+	DROP	R5	
00003540	00000000 00000000			3513	DC	XL16' 000000000000000000000000709551615F'	V1 source
00003548	00000070 9551615F			3514	DC	XL08' FFFFFFFFFFFFFF'	R1 result
00003550	FFFFFFFFFF FFFFFFFF			3515			
00003558	00000000			3516	DC	F' 0'	END OF TABLE
0000355C	00000000			3517	DC	F' 0'	
				3518 *			
				3519 *	table of pointers to individual load test		
00003560				3520 *			
				3521 E6TESTS	DS	OF	
				3522	PTTABLE		
00003560	00001198			3523+TTABLE	DS	OF	
00003560	00001198			3524+	DC	A(T1)	address of test
00003564	000011F0			3525+	DC	A(T2)	address of test
00003568	00001248			3526+	DC	A(T3)	address of test
0000356C	000012A0			3527+	DC	A(T4)	address of test
00003570	000012F8			3528+	DC	A(T5)	address of test
00003574	00001350			3529+	DC	A(T6)	address of test
00003578	000013A8			3530+	DC	A(T7)	address of test

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
0000357C	00001400		3531+	DC A(T8)	address of test
00003580	00001458		3532+	DC A(T9)	address of test
00003584	000014B0		3533+	DC A(T10)	address of test
00003588	00001508		3534+	DC A(T11)	address of test
0000358C	00001560		3535+	DC A(T12)	address of test
00003590	000015B8		3536+	DC A(T13)	address of test
00003594	00001610		3537+	DC A(T14)	address of test
00003598	00001668		3538+	DC A(T15)	address of test
0000359C	000016C0		3539+	DC A(T16)	address of test
000035A0	00001718		3540+	DC A(T17)	address of test
000035A4	00001770		3541+	DC A(T18)	address of test
000035A8	000017C8		3542+	DC A(T19)	address of test
000035AC	00001820		3543+	DC A(T20)	address of test
000035B0	00001878		3544+	DC A(T21)	address of test
000035B4	000018D0		3545+	DC A(T22)	address of test
000035B8	00001928		3546+	DC A(T23)	address of test
000035BC	00001980		3547+	DC A(T24)	address of test
000035C0	000019D8		3548+	DC A(T25)	address of test
000035C4	00001A30		3549+	DC A(T26)	address of test
000035C8	00001A88		3550+	DC A(T27)	address of test
000035CC	00001AE0		3551+	DC A(T28)	address of test
000035D0	00001B38		3552+	DC A(T29)	address of test
000035D4	00001B90		3553+	DC A(T30)	address of test
000035D8	00001BE8		3554+	DC A(T31)	address of test
000035DC	00001C40		3555+	DC A(T32)	address of test
000035E0	00001C98		3556+	DC A(T33)	address of test
000035E4	00001CF0		3557+	DC A(T34)	address of test
000035E8	00001D48		3558+	DC A(T35)	address of test
000035EC	00001DA0		3559+	DC A(T36)	address of test
000035F0	00001DF8		3560+	DC A(T37)	address of test
000035F4	00001E50		3561+	DC A(T38)	address of test
000035F8	00001EA8		3562+	DC A(T39)	address of test
000035FC	00001F00		3563+	DC A(T40)	address of test
00003600	00001F58		3564+	DC A(T41)	address of test
00003604	00001FB0		3565+	DC A(T42)	address of test
00003608	00002008		3566+	DC A(T43)	address of test
0000360C	00002060		3567+	DC A(T44)	address of test
00003610	000020B8		3568+	DC A(T45)	address of test
00003614	00002110		3569+	DC A(T46)	address of test
00003618	00002168		3570+	DC A(T47)	address of test
0000361C	000021C0		3571+	DC A(T48)	address of test
00003620	00002218		3572+	DC A(T49)	address of test
00003624	00002270		3573+	DC A(T50)	address of test
00003628	000022C8		3574+	DC A(T51)	address of test
0000362C	00002320		3575+	DC A(T52)	address of test
00003630	00002378		3576+	DC A(T53)	address of test
00003634	000023D0		3577+	DC A(T54)	address of test
00003638	00002428		3578+	DC A(T55)	address of test
0000363C	00002480		3579+	DC A(T56)	address of test
00003640	000024D8		3580+	DC A(T57)	address of test
00003644	00002530		3581+	DC A(T58)	address of test
00003648	00002588		3582+	DC A(T59)	address of test
0000364C	000025E0		3583+	DC A(T60)	address of test
00003650	00002638		3584+	DC A(T61)	address of test
00003654	00002690		3585+	DC A(T62)	address of test
00003658	000026E8		3586+	DC A(T63)	address of test

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
0000365C	00002740		3587+	DC A(T64)	address of test
00003660	00002798		3588+	DC A(T65)	address of test
00003664	000027F0		3589+	DC A(T66)	address of test
00003668	00002848		3590+	DC A(T67)	address of test
0000366C	000028A0		3591+	DC A(T68)	address of test
00003670	000028F8		3592+	DC A(T69)	address of test
00003674	00002950		3593+	DC A(T70)	address of test
00003678	000029A8		3594+	DC A(T71)	address of test
0000367C	00002A00		3595+	DC A(T72)	address of test
00003680	00002A58		3596+	DC A(T73)	address of test
00003684	00002AB0		3597+	DC A(T74)	address of test
00003688	00002B08		3598+	DC A(T75)	address of test
0000368C	00002B60		3599+	DC A(T76)	address of test
00003690	00002BB8		3600+	DC A(T77)	address of test
00003694	00002C10		3601+	DC A(T78)	address of test
00003698	00002C68		3602+	DC A(T79)	address of test
0000369C	00002CC0		3603+	DC A(T80)	address of test
000036A0	00002D18		3604+	DC A(T81)	address of test
000036A4	00002D70		3605+	DC A(T82)	address of test
000036A8	00002DC8		3606+	DC A(T83)	address of test
000036AC	00002E20		3607+	DC A(T84)	address of test
000036B0	00002E78		3608+	DC A(T85)	address of test
000036B4	00002ED0		3609+	DC A(T86)	address of test
000036B8	00002F28		3610+	DC A(T87)	address of test
000036BC	00002F80		3611+	DC A(T88)	address of test
000036C0	00002FD8		3612+	DC A(T89)	address of test
000036C4	00003030		3613+	DC A(T90)	address of test
000036C8	00003088		3614+	DC A(T91)	address of test
000036CC	000030E0		3615+	DC A(T92)	address of test
000036D0	00003138		3616+	DC A(T93)	address of test
000036D4	00003190		3617+	DC A(T94)	address of test
000036D8	000031E8		3618+	DC A(T95)	address of test
000036DC	00003240		3619+	DC A(T96)	address of test
000036E0	00003298		3620+	DC A(T97)	address of test
000036E4	000032F0		3621+	DC A(T98)	address of test
000036E8	00003348		3622+	DC A(T99)	address of test
000036EC	000033A0		3623+	DC A(T100)	address of test
000036F0	000033F8		3624+	DC A(T101)	address of test
000036F4	00003450		3625+	DC A(T102)	address of test
000036F8	000034A8		3626+	DC A(T103)	address of test
000036FC	00003500		3627+	DC A(T104)	address of test
			3628+*		
00003700	00000000		3629+	DC A(0)	END OF TABLE
00003704	00000000		3630+	DC A(0)	
			3631		
00003708	00000000		3632	DC F' 0'	END OF TABLE
0000370C	00000000		3633	DC F' 0'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				3635 **** Register equates ****
				3636 * Register equates
				3637 **** Register equates ****
	00000000	00000001	3639 R0	EQU 0
	00000001	00000001	3640 R1	EQU 1
	00000002	00000001	3641 R2	EQU 2
	00000003	00000001	3642 R3	EQU 3
	00000004	00000001	3643 R4	EQU 4
	00000005	00000001	3644 R5	EQU 5
	00000006	00000001	3645 R6	EQU 6
	00000007	00000001	3646 R7	EQU 7
	00000008	00000001	3647 R8	EQU 8
	00000009	00000001	3648 R9	EQU 9
	0000000A	00000001	3649 R10	EQU 10
	0000000B	00000001	3650 R11	EQU 11
	0000000C	00000001	3651 R12	EQU 12
	0000000D	00000001	3652 R13	EQU 13
	0000000E	00000001	3653 R14	EQU 14
	0000000F	00000001	3654 R15	EQU 15
				3656 **** Register equates ****
				3657 * Register equates
				3658 **** Register equates ****
	00000000	00000001	3660 V0	EQU 0
	00000001	00000001	3661 V1	EQU 1
	00000002	00000001	3662 V2	EQU 2
	00000003	00000001	3663 V3	EQU 3
	00000004	00000001	3664 V4	EQU 4
	00000005	00000001	3665 V5	EQU 5
	00000006	00000001	3666 V6	EQU 6
	00000007	00000001	3667 V7	EQU 7
	00000008	00000001	3668 V8	EQU 8
	00000009	00000001	3669 V9	EQU 9
	0000000A	00000001	3670 V10	EQU 10
	0000000B	00000001	3671 V11	EQU 11
	0000000C	00000001	3672 V12	EQU 12
	0000000D	00000001	3673 V13	EQU 13
	0000000E	00000001	3674 V14	EQU 14
	0000000F	00000001	3675 V15	EQU 15
	00000010	00000001	3676 V16	EQU 16
	00000011	00000001	3677 V17	EQU 17
	00000012	00000001	3678 V18	EQU 18
	00000013	00000001	3679 V19	EQU 19
	00000014	00000001	3680 V20	EQU 20
	00000015	00000001	3681 V21	EQU 21

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
		00000016	00000001	3682 V22	EQU	22
		00000017	00000001	3683 V23	EQU	23
		00000018	00000001	3684 V24	EQU	24
		00000019	00000001	3685 V25	EQU	25
		0000001A	00000001	3686 V26	EQU	26
		0000001B	00000001	3687 V27	EQU	27
		0000001C	00000001	3688 V28	EQU	28
		0000001D	00000001	3689 V29	EQU	29
		0000001E	00000001	3690 V30	EQU	30
		0000001F	00000001	3691 V31	EQU	31
				3692		
				3693	END	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
RE27	F	00001AC8	4	1383	1373 1377
RE28	F	00001B20	4	1410	1400 1404
RE29	F	00001B78	4	1437	1427 1431
RE3	F	00001288	4	718	708 712
RE30	F	00001BD0	4	1464	1454 1458
RE31	F	00001C28	4	1495	1485 1489
RE32	F	00001C80	4	1522	1512 1516
RE33	F	00001CD8	4	1549	1539 1543
RE34	F	00001D30	4	1576	1566 1570
RE35	F	00001D88	4	1603	1593 1597
RE36	F	00001DE0	4	1633	1623 1627
RE37	F	00001E38	4	1660	1650 1654
RE38	F	00001E90	4	1687	1677 1681
RE39	F	00001EE8	4	1714	1704 1708
RE4	F	000012E0	4	745	735 739
RE40	F	00001F40	4	1741	1731 1735
RE41	F	00001F98	4	1783	1773 1777
RE42	F	00001FF0	4	1810	1800 1804
RE43	F	00002048	4	1837	1827 1831
RE44	F	000020A0	4	1864	1854 1858
RE45	F	000020F8	4	1891	1881 1885
RE46	F	00002150	4	1918	1908 1912
RE47	F	000021A8	4	1945	1935 1939
RE48	F	00002200	4	1972	1962 1966
RE49	F	00002258	4	2002	1992 1996
RE5	F	00001338	4	772	762 766
RE50	F	000022B0	4	2029	2019 2023
RE51	F	00002308	4	2056	2046 2050
RE52	F	00002360	4	2083	2073 2077
RE53	F	000023B8	4	2110	2100 2104
RE54	F	00002410	4	2137	2127 2131
RE55	F	00002468	4	2164	2154 2158
RE56	F	000024C0	4	2191	2181 2185
RE57	F	00002518	4	2222	2212 2216
RE58	F	00002570	4	2249	2239 2243
RE59	F	000025C8	4	2276	2266 2270
RE6	F	00001390	4	802	792 796
RE60	F	00002620	4	2303	2293 2297
RE61	F	00002678	4	2330	2320 2324
RE62	F	000026D0	4	2357	2347 2351
RE63	F	00002728	4	2384	2374 2378
RE64	F	00002780	4	2411	2401 2405
RE65	F	000027D8	4	2441	2431 2435
RE66	F	00002830	4	2468	2458 2462
RE67	F	00002888	4	2495	2485 2489
RE68	F	000028E0	4	2522	2512 2516
RE69	F	00002938	4	2549	2539 2543
RE7	F	000013E8	4	829	819 823
RE70	F	00002990	4	2576	2566 2570
RE71	F	000029E8	4	2603	2593 2597
RE72	F	00002A40	4	2630	2620 2624
RE73	F	00002A98	4	2661	2651 2655
RE74	F	00002AF0	4	2688	2678 2682
RE75	F	00002B48	4	2715	2705 2709
RE76	F	00002BA0	4	2742	2732 2736
RE77	F	00002BF8	4	2769	2759 2763

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
RE78	F	00002C50	4	2797	2787 2791
RE79	F	00002CA8	4	2824	2814 2818
RE8	F	00001440	4	856	846 850
RE80	F	00002D00	4	2851	2841 2845
RE81	F	00002D58	4	2881	2871 2875
RE82	F	00002DB0	4	2908	2898 2902
RE83	F	00002E08	4	2935	2925 2929
RE84	F	00002E60	4	2962	2952 2956
RE85	F	00002EB8	4	2989	2979 2983
RE86	F	00002F10	4	3016	3006 3010
RE87	F	00002F68	4	3043	3033 3037
RE88	F	00002FC0	4	3070	3060 3064
RE89	F	00003018	4	3101	3091 3095
RE9	F	00001498	4	883	873 877
RE90	F	00003070	4	3128	3118 3122
RE91	F	000030C8	4	3155	3145 3149
RE92	F	00003120	4	3182	3172 3176
RE93	F	00003178	4	3209	3199 3203
RE94	F	000031D0	4	3237	3227 3231
RE95	F	00003228	4	3264	3254 3258
RE96	F	00003280	4	3291	3281 3285
RE97	F	000032D8	4	3321	3311 3315
RE98	F	00003330	4	3348	3338 3342
RE99	F	00003388	4	3375	3365 3369
REA1	A	000011B0	4	654	
REA10	A	000014C8	4	900	
REA100	A	000033B8	4	3392	
REA101	A	00003410	4	3419	
REA102	A	00003468	4	3447	
REA103	A	000034C0	4	3474	
REA104	A	00003518	4	3501	
REA11	A	00001520	4	931	
REA12	A	00001578	4	958	
REA13	A	000015D0	4	985	
REA14	A	00001628	4	1012	
REA15	A	00001680	4	1039	
REA16	A	000016D8	4	1069	
REA17	A	00001730	4	1096	
REA18	A	00001788	4	1123	
REA19	A	000017E0	4	1150	
REA2	A	00001208	4	681	
REA20	A	00001838	4	1177	
REA21	A	00001890	4	1208	
REA22	A	000018E8	4	1235	
REA23	A	00001940	4	1262	
REA24	A	00001998	4	1289	
REA25	A	000019F0	4	1316	
REA26	A	00001A48	4	1346	
REA27	A	00001AA0	4	1373	
REA28	A	00001AF8	4	1400	
REA29	A	00001B50	4	1427	
REA3	A	00001260	4	708	
REA30	A	00001BA8	4	1454	
REA31	A	00001C00	4	1485	
REA32	A	00001C58	4	1512	
REA33	A	00001CB0	4	1539	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
REA34	A	00001D08	4	1566	
REA35	A	00001D60	4	1593	
REA36	A	00001DB8	4	1623	
REA37	A	00001E10	4	1650	
REA38	A	00001E68	4	1677	
REA39	A	00001EC0	4	1704	
REA4	A	000012B8	4	735	
REA40	A	00001F18	4	1731	
REA41	A	00001F70	4	1773	
REA42	A	00001FC8	4	1800	
REA43	A	00002020	4	1827	
REA44	A	00002078	4	1854	
REA45	A	000020D0	4	1881	
REA46	A	00002128	4	1908	
REA47	A	00002180	4	1935	
REA48	A	000021D8	4	1962	
REA49	A	00002230	4	1992	
REA5	A	00001310	4	762	
REA50	A	00002288	4	2019	
REA51	A	000022E0	4	2046	
REA52	A	00002338	4	2073	
REA53	A	00002390	4	2100	
REA54	A	000023E8	4	2127	
REA55	A	00002440	4	2154	
REA56	A	00002498	4	2181	
REA57	A	000024F0	4	2212	
REA58	A	00002548	4	2239	
REA59	A	000025A0	4	2266	
REA6	A	00001368	4	792	
REA60	A	000025F8	4	2293	
REA61	A	00002650	4	2320	
REA62	A	000026A8	4	2347	
REA63	A	00002700	4	2374	
REA64	A	00002758	4	2401	
REA65	A	000027B0	4	2431	
REA66	A	00002808	4	2458	
REA67	A	00002860	4	2485	
REA68	A	000028B8	4	2512	
REA69	A	00002910	4	2539	
REA7	A	000013C0	4	819	
REA70	A	00002968	4	2566	
REA71	A	000029C0	4	2593	
REA72	A	00002A18	4	2620	
REA73	A	00002A70	4	2651	
REA74	A	00002AC8	4	2678	
REA75	A	00002B20	4	2705	
REA76	A	00002B78	4	2732	
REA77	A	00002BD0	4	2759	
REA78	A	00002C28	4	2787	
REA79	A	00002C80	4	2814	
REA8	A	00001418	4	846	
REA80	A	00002CD8	4	2841	
REA81	A	00002D30	4	2871	
REA82	A	00002D88	4	2898	
REA83	A	00002DE0	4	2925	
REA84	A	00002E38	4	2952	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
REA85	A	00002E90	4	2979	
REA86	A	00002EE8	4	3006	
REA87	A	00002F40	4	3033	
REA88	A	00002F98	4	3060	
REA89	A	00002FF0	4	3091	
REA9	A	00001470	4	873	
REA90	A	00003048	4	3118	
REA91	A	000030A0	4	3145	
REA92	A	000030F8	4	3172	
REA93	A	00003150	4	3199	
REA94	A	000031A8	4	3227	
REA95	A	00003200	4	3254	
REA96	A	00003258	4	3281	
REA97	A	000032B0	4	3311	
REA98	A	00003308	4	3338	
REA99	A	00003360	4	3365	
READDR	A	00000018	4	526	223
REG2LOW	U	000000DD	1	430	
REG2PATT	U	AABBCCDD	1	429	
RELEN	A	00000014	4	525	
RPTDWSAV	D	00000458	8	353	342 344
RPTERROR	I	00000430	4	337	275 309
RPTSAVE	F	00000450	4	350	337 347
RPTSVR5	F	00000454	4	351	338 346
SKL0001	U	00000054	1	178	194
SKT0001	C	0000022A	26	175	178 195
SVOLDPSW	U	00000140	0	113	
T1	A	00001198	4	645	3524
T10	A	000014B0	4	891	3533
T100	A	000033A0	4	3383	3623
T101	A	000033F8	4	3410	3624
T102	A	00003450	4	3438	3625
T103	A	000034A8	4	3465	3626
T104	A	00003500	4	3492	3627
T11	A	00001508	4	922	3534
T12	A	00001560	4	949	3535
T13	A	000015B8	4	976	3536
T14	A	00001610	4	1003	3537
T15	A	00001668	4	1030	3538
T16	A	000016C0	4	1060	3539
T17	A	00001718	4	1087	3540
T18	A	00001770	4	1114	3541
T19	A	000017C8	4	1141	3542
T2	A	000011F0	4	672	3525
T20	A	00001820	4	1168	3543
T21	A	00001878	4	1199	3544
T22	A	000018D0	4	1226	3545
T23	A	00001928	4	1253	3546
T24	A	00001980	4	1280	3547
T25	A	000019D8	4	1307	3548
T26	A	00001A30	4	1337	3549
T27	A	00001A88	4	1364	3550
T28	A	00001AE0	4	1391	3551
T29	A	00001B38	4	1418	3552
T3	A	00001248	4	699	3526
T30	A	00001B90	4	1445	3553

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
T31	A	00001BE8	4	1476	3554
T32	A	00001C40	4	1503	3555
T33	A	00001C98	4	1530	3556
T34	A	00001CF0	4	1557	3557
T35	A	00001D48	4	1584	3558
T36	A	00001DAO	4	1614	3559
T37	A	00001DF8	4	1641	3560
T38	A	00001E50	4	1668	3561
T39	A	00001EA8	4	1695	3562
T4	A	000012A0	4	726	3527
T40	A	00001F00	4	1722	3563
T41	A	00001F58	4	1764	3564
T42	A	00001FB0	4	1791	3565
T43	A	00002008	4	1818	3566
T44	A	00002060	4	1845	3567
T45	A	000020B8	4	1872	3568
T46	A	00002110	4	1899	3569
T47	A	00002168	4	1926	3570
T48	A	000021C0	4	1953	3571
T49	A	00002218	4	1983	3572
T5	A	000012F8	4	753	3528
T50	A	00002270	4	2010	3573
T51	A	000022C8	4	2037	3574
T52	A	00002320	4	2064	3575
T53	A	00002378	4	2091	3576
T54	A	000023D0	4	2118	3577
T55	A	00002428	4	2145	3578
T56	A	00002480	4	2172	3579
T57	A	000024D8	4	2203	3580
T58	A	00002530	4	2230	3581
T59	A	00002588	4	2257	3582
T6	A	00001350	4	783	3529
T60	A	000025E0	4	2284	3583
T61	A	00002638	4	2311	3584
T62	A	00002690	4	2338	3585
T63	A	000026E8	4	2365	3586
T64	A	00002740	4	2392	3587
T65	A	00002798	4	2422	3588
T66	A	000027F0	4	2449	3589
T67	A	00002848	4	2476	3590
T68	A	000028A0	4	2503	3591
T69	A	000028F8	4	2530	3592
T7	A	000013A8	4	810	3530
T70	A	00002950	4	2557	3593
T71	A	000029A8	4	2584	3594
T72	A	00002A00	4	2611	3595
T73	A	00002A58	4	2642	3596
T74	A	00002AB0	4	2669	3597
T75	A	00002B08	4	2696	3598
T76	A	00002B60	4	2723	3599
T77	A	00002BB8	4	2750	3600
T78	A	00002C10	4	2778	3601
T79	A	00002C68	4	2805	3602
T8	A	00001400	4	837	3531
T80	A	00002CC0	4	2832	3603
T81	A	00002D18	4	2862	3604

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
T82	A	00002D70	4	2889	3605
T83	A	00002DC8	4	2916	3606
T84	A	00002E20	4	2943	3607
T85	A	00002E78	4	2970	3608
T86	A	00002ED0	4	2997	3609
T87	A	00002F28	4	3024	3610
T88	A	00002F80	4	3051	3611
T89	A	00002FD8	4	3082	3612
T9	A	00001458	4	864	3532
T90	A	00003030	4	3109	3613
T91	A	00003088	4	3136	3614
T92	A	000030E0	4	3163	3615
T93	A	00003138	4	3190	3616
T94	A	00003190	4	3218	3617
T95	A	000031E8	4	3245	3618
T96	A	00003240	4	3272	3619
T97	A	00003298	4	3302	3620
T98	A	000032F0	4	3329	3621
T99	A	00003348	4	3356	3622
TESTCC	I	00000316	4	230	220
TESTING	F	00001004	4	441	
TESTREST	U	000002FE	1	222	240
TNUM	H	00000004	2	516	251 285
TSUB	A	00000000	4	515	215
TTABLE	F	00003560	4	3523	
V0	U	00000000	1	3660	
V1	U	00000001	1	3661	657 659 660 684 686 687 711 713 714 738 740 741 765 767 768 795 797 798 822 824 825 849 851 852 876 878 879 903 905 906 934 936 937 961 963 964 988 990 991
				1015 1017 1018 1042 1044 1045 1072 1074 1075 1099 1101 1102 1126	
				1128 1129 1153 1155 1156 1180 1182 1183 1211 1213 1214 1238 1240	
				1241 1265 1267 1268 1292 1294 1295 1319 1321 1322 1349 1351 1352	
				1376 1378 1379 1403 1405 1406 1430 1432 1433 1457 1459 1460 1488	
				1490 1491 1515 1517 1518 1542 1544 1545 1569 1571 1572 1596 1598	
				1599 1626 1628 1629 1653 1655 1656 1680 1682 1683 1707 1709 1710	
				1734 1736 1737 1776 1778 1779 1803 1805 1806 1830 1832 1833 1857	
				1859 1860 1884 1886 1887 1911 1913 1914 1938 1940 1941 1965 1967	
				1968 1995 1997 1998 2022 2024 2025 2049 2051 2052 2076 2078 2079	
				2103 2105 2106 2130 2132 2133 2157 2159 2160 2184 2186 2187 2215	
				2217 2218 2242 2244 2245 2269 2271 2272 2296 2298 2299 2323 2325	
				2326 2350 2352 2353 2377 2379 2380 2404 2406 2407 2434 2436 2437	
				2461 2463 2464 2488 2490 2491 2515 2517 2518 2542 2544 2545 2569	
				2571 2572 2596 2598 2599 2623 2625 2626 2654 2656 2657 2681 2683	
				2684 2708 2710 2711 2735 2737 2738 2762 2764 2765 2790 2792 2793	
				2817 2819 2820 2844 2846 2847 2874 2876 2877 2901 2903 2904 2928	
				2930 2931 2955 2957 2958 2982 2984 2985 3009 3011 3012 3036 3038	
				3039 3063 3065 3066 3094 3096 3097 3121 3123 3124 3148 3150 3151	
				3175 3177 3178 3202 3204 3205 3230 3232 3233 3257 3259 3260 3284	
				3286 3287 3314 3316 3317 3341 3343 3344 3368 3370 3371 3395 3397	
				3398 3422 3424 3425 3450 3452 3453 3477 3479 3480 3504 3506 3507	
V10	U	0000000A	1	3670	
V11	U	0000000B	1	3671	
V12	U	0000000C	1	3672	
V13	U	0000000D	1	3673	
V14	U	0000000E	1	3674	
V15	U	0000000F	1	3675	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
V16	U	00000010	1	3676	
V17	U	00000011	1	3677	
V18	U	00000012	1	3678	
V19	U	00000013	1	3679	
V1FUDGE	X	00001148	16	503	657 684 711 738 765 795 822 849 876 903 934 961 988 1015 1042 1072 1099 1126 1153 1180 1211 1238 1265 1292 1319 1349 1376 1403 1430 1457 1488 1515 1542 1569 1596 1626 1653 1680 1707 1734 1776 1803 1830 1857 1884 1911 1938 1965 1995 2022 2049 2076 2103 2130 2157 2184 2215 2242 2269 2296 2323 2350 2377 2404 2434 2461 2488 2515 2542 2569 2596 2623 2654 2681 2708 2735 2762 2790 2817 2844 2874 2901 2928 2955 2982 3009 3036 3063 3094 3121 3148 3175 3202 3230 3257 3284 3314 3341 3368 3395 3422 3450 3477 3504
V1FUDGEB	X	00001158	16	504	
V1INPUT	C	00001168	16	505	
V1OUTPUT	X	00001110	16	499	224 660 687 714 741 768 798 825 852 879 906 937 964 991 1018 1045 1075 1102 1129 1156 1183 1214 1241 1268 1295 1322 1352 1379 1406 1433 1460 1491 1518 1545 1572 1599 1629 1656 1683 1710 1737 1779 1806 1833 1860 1887 1914 1941 1968 1998 2025 2052 2079 2106 2133 2160 2187 2218 2245 2272 2299 2326 2353 2380 2407 2437 2464 2491 2518 2545 2572 2599 2626 2657 2684 2711 2738 2765 2793 2820 2847 2877 2904 2931 2958 2985 3012 3039 3066 3097 3124 3151 3178 3205 3233 3260 3287 3317 3344 3371 3398 3425 3453 3480 3507
V2	U	00000002	1	3662	
V20	U	00000014	1	3680	
V21	U	00000015	1	3681	
V22	U	00000016	1	3682	
V23	U	00000017	1	3683	
V24	U	00000018	1	3684	
V25	U	00000019	1	3685	
V26	U	0000001A	1	3686	
V27	U	0000001B	1	3687	
V28	U	0000001C	1	3688	
V29	U	0000001D	1	3689	
V3	U	00000003	1	3663	
V30	U	0000001E	1	3690	
V31	U	0000001F	1	3691	
V4	U	00000004	1	3664	
V5	U	00000005	1	3665	
V6	U	00000006	1	3666	
V7	U	00000007	1	3667	
V8	U	00000008	1	3668	
V9	U	00000009	1	3669	
X0001	U	000002B0	1	184 172 185	
X1	F	000011B4	4	656 645	
X10	F	000014CC	4	902 891	
X100	F	000033BC	4	3394 3383	
X101	F	00003414	4	3421 3410	
X102	F	0000346C	4	3449 3438	
X103	F	000034C4	4	3476 3465	
X104	F	0000351C	4	3503 3492	
X11	F	00001524	4	933 922	
X12	F	0000157C	4	960 949	
X13	F	000015D4	4	987 976	
X14	F	0000162C	4	1014 1003	
X15	F	00001684	4	1041 1030	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
X16	F	000016DC	4	1071	1060
X17	F	00001734	4	1098	1087
X18	F	0000178C	4	1125	1114
X19	F	000017E4	4	1152	1141
X2	F	0000120C	4	683	672
X20	F	0000183C	4	1179	1168
X21	F	00001894	4	1210	1199
X22	F	000018EC	4	1237	1226
X23	F	00001944	4	1264	1253
X24	F	0000199C	4	1291	1280
X25	F	000019F4	4	1318	1307
X26	F	00001A4C	4	1348	1337
X27	F	00001AA4	4	1375	1364
X28	F	00001AFC	4	1402	1391
X29	F	00001B54	4	1429	1418
X3	F	00001264	4	710	699
X30	F	00001BAC	4	1456	1445
X31	F	00001C04	4	1487	1476
X32	F	00001C5C	4	1514	1503
X33	F	00001CB4	4	1541	1530
X34	F	00001DOC	4	1568	1557
X35	F	00001D64	4	1595	1584
X36	F	00001DBC	4	1625	1614
X37	F	00001E14	4	1652	1641
X38	F	00001E6C	4	1679	1668
X39	F	00001EC4	4	1706	1695
X4	F	000012BC	4	737	726
X40	F	00001F1C	4	1733	1722
X41	F	00001F74	4	1775	1764
X42	F	00001FCC	4	1802	1791
X43	F	00002024	4	1829	1818
X44	F	0000207C	4	1856	1845
X45	F	000020D4	4	1883	1872
X46	F	0000212C	4	1910	1899
X47	F	00002184	4	1937	1926
X48	F	000021DC	4	1964	1953
X49	F	00002234	4	1994	1983
X5	F	00001314	4	764	753
X50	F	0000228C	4	2021	2010
X51	F	000022E4	4	2048	2037
X52	F	0000233C	4	2075	2064
X53	F	00002394	4	2102	2091
X54	F	000023EC	4	2129	2118
X55	F	00002444	4	2156	2145
X56	F	0000249C	4	2183	2172
X57	F	000024F4	4	2214	2203
X58	F	0000254C	4	2241	2230
X59	F	000025A4	4	2268	2257
X6	F	0000136C	4	794	783
X60	F	000025FC	4	2295	2284
X61	F	00002654	4	2322	2311
X62	F	000026AC	4	2349	2338
X63	F	00002704	4	2376	2365
X64	F	0000275C	4	2403	2392
X65	F	000027B4	4	2433	2422
X66	F	0000280C	4	2460	2449

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
X67	F	00002864	4	2487	2476
X68	F	000028BC	4	2514	2503
X69	F	00002914	4	2541	2530
X7	F	000013C4	4	821	810
X70	F	0000296C	4	2568	2557
X71	F	000029C4	4	2595	2584
X72	F	00002A1C	4	2622	2611
X73	F	00002A74	4	2653	2642
X74	F	00002ACC	4	2680	2669
X75	F	00002B24	4	2707	2696
X76	F	00002B7C	4	2734	2723
X77	F	00002BD4	4	2761	2750
X78	F	00002C2C	4	2789	2778
X79	F	00002C84	4	2816	2805
X8	F	0000141C	4	848	837
X80	F	00002CDC	4	2843	2832
X81	F	00002D34	4	2873	2862
X82	F	00002D8C	4	2900	2889
X83	F	00002DE4	4	2927	2916
X84	F	00002E3C	4	2954	2943
X85	F	00002E94	4	2981	2970
X86	F	00002EEC	4	3008	2997
X87	F	00002F44	4	3035	3024
X88	F	00002F9C	4	3062	3051
X89	F	00002FF4	4	3093	3082
X9	F	00001474	4	875	864
X90	F	0000304C	4	3120	3109
X91	F	000030A4	4	3147	3136
X92	F	000030FC	4	3174	3163
X93	F	00003154	4	3201	3190
X94	F	000031AC	4	3229	3218
X95	F	00003204	4	3256	3245
X96	F	0000325C	4	3283	3272
X97	F	000032B4	4	3313	3302
X98	F	0000330C	4	3340	3329
X99	F	00003364	4	3367	3356
XC0001	U	000002D8	1	198	190
ZVE6TST	J	00000000	14096	110	113 115 119 123 439 111
=A(E6TESTS)	A	00000558	4	415	204
=AL2(L' MSGMSG)	R	00000566	2	419	365
=F' 1'	F	0000055C	4	416	239 315
=F' 2'	F	00000554	4	414	189
=H' 0'	H	00000564	2	418	360
=XL4' 3'	X	00000560	4	417	246

MACRO DEFN REFERENCES

FCHECK	62	171
PTTABLE	594	3522
VRR_K	540	642 669 696 723 750 780 807 834 861 888 919 946 973 1000 1027 1057 1084 1111 1138 1165 1196 1223 1250 1277 1304 1334 1361 1388 1415 1442 1473 1500 1527 1554 1581 1611 1638 1665 1692 1719 1761 1788 1815 1842 1869 1896 1923 1950 1980 2007 2034 2061 2088 2115 2142 2169 2200 2227 2254 2281 2308 2335 2362 2389 2419 2446 2473 2500 2527 2554 2581 2608 2639 2666 2693 2720 2747 2775 2802 2829 2859 2886 2913 2940 2967 2994 3021 3048 3079 3106 3133 3160 3187 3215 3242 3269 3299 3326 3353 3380 3407 3435 3462 3489

DESC	SYMBOL	SIZE	POS	ADDR
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Entry: 0

Image	IMAGE	14096	0000-370F	0000-370F
Region		14096	0000-370F	0000-370F
CSECT	ZVE6TST	14096	0000-370F	0000-370F

STMT	FILE NAME
1	/home/tn529/sharedvfp/tests/zvector-e6-13-converttodecimal.asm

** NO ERRORS FOUND **